

EA02-025

FORD 10/27/03

APPENDIX N

BOOK 18 OF 61

PART 4 OF 4

9900226 "C" HEXPORT, CAVITY, BLACK RESIDUE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 14:12:31 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Bessel (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2F / 2F

Y Axis: % Transmittance

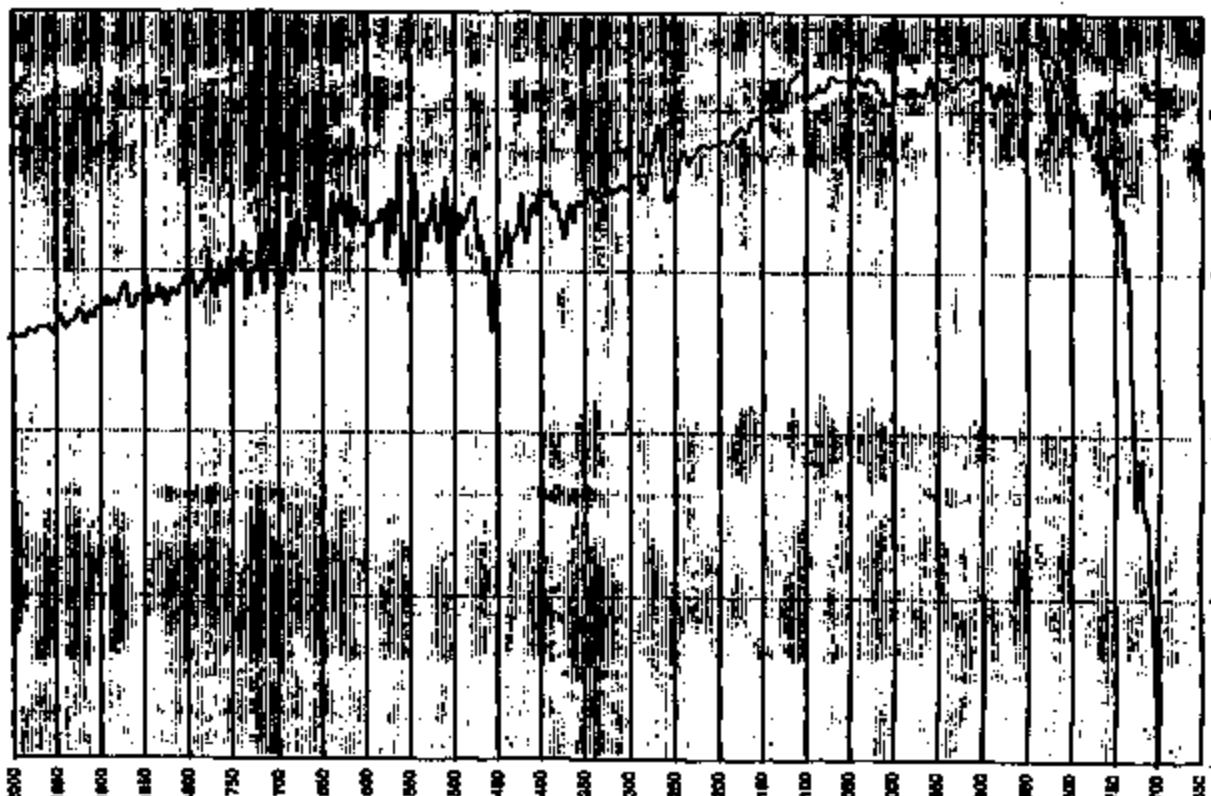
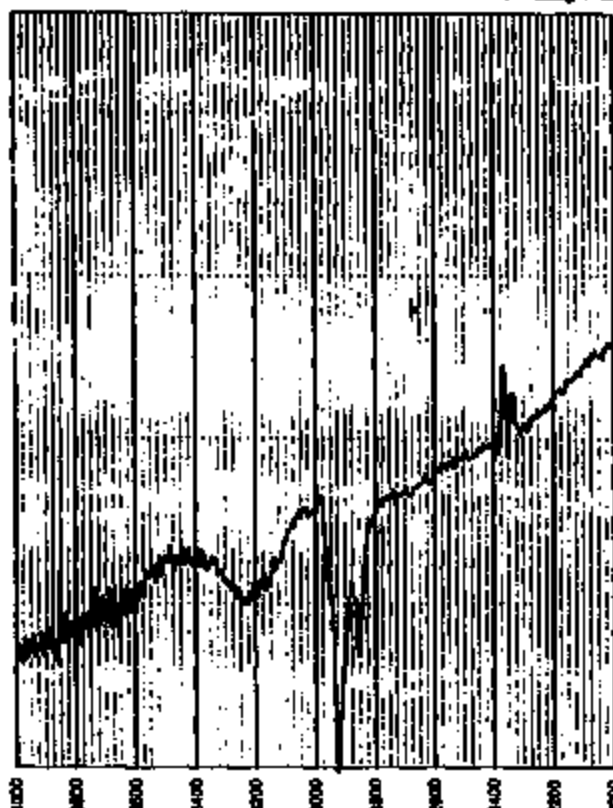
X Axis: Wavenumber

Engineer:

Comment:

Interpretation:

hydrocarbon (possibly mineral oil) + trace silicone



8713 2777

9900226 "C" HEXPORT, CAVITY, BROWN RESIDUE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 14:15:58 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 2H / 2R

Engineer: MCH

APOD: Norton-Bear (medium)

Detector: MCT[15]

Y Axis: % Transmittance

X Axis: Wavenumber

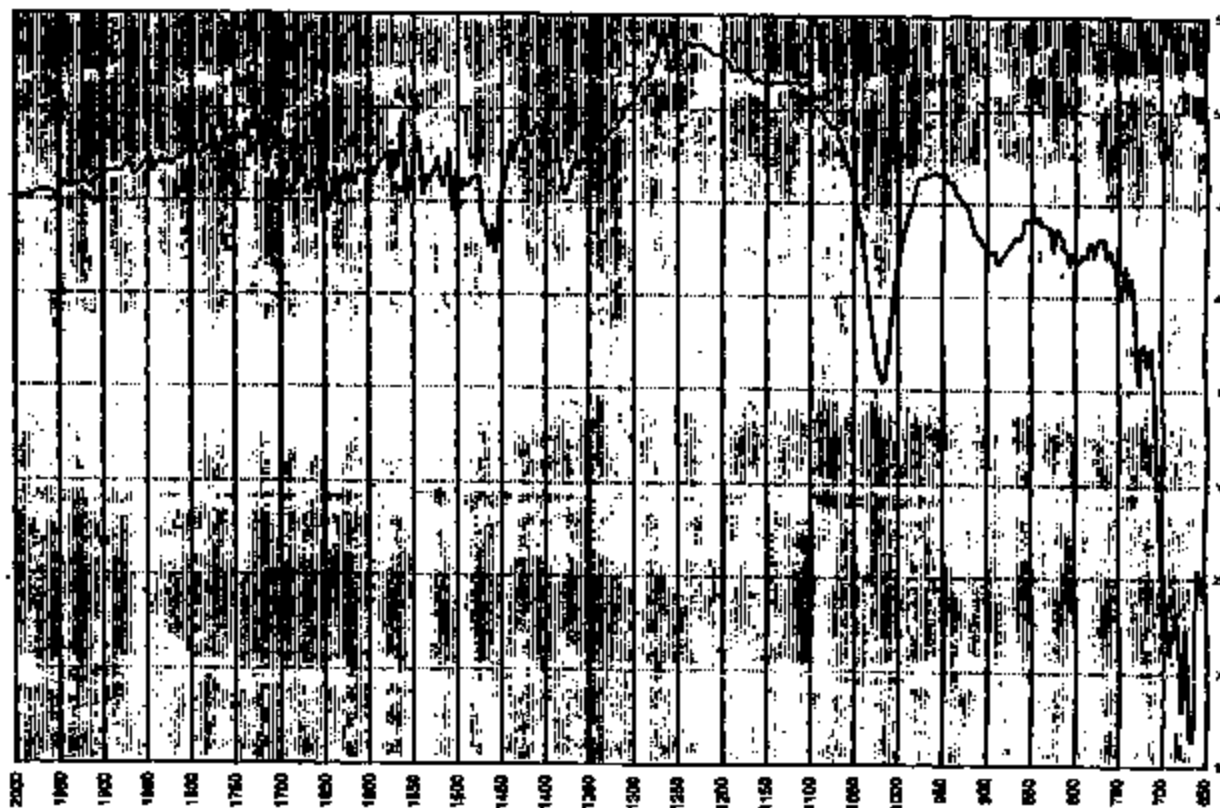
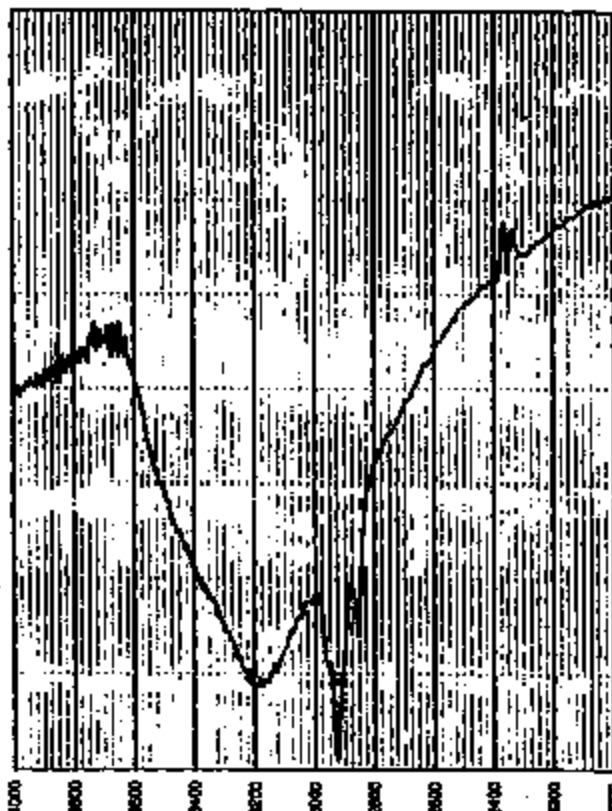
Engineer:

mk

Client:

Interpretation:

inorganics, plus trace hydrocarbon - possibly mol.



3713 2778

9900226 "C" CUP, INTERIOR

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 14:35:07 1999

Engineer: MCH

Scans: 128 / 256

AFOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

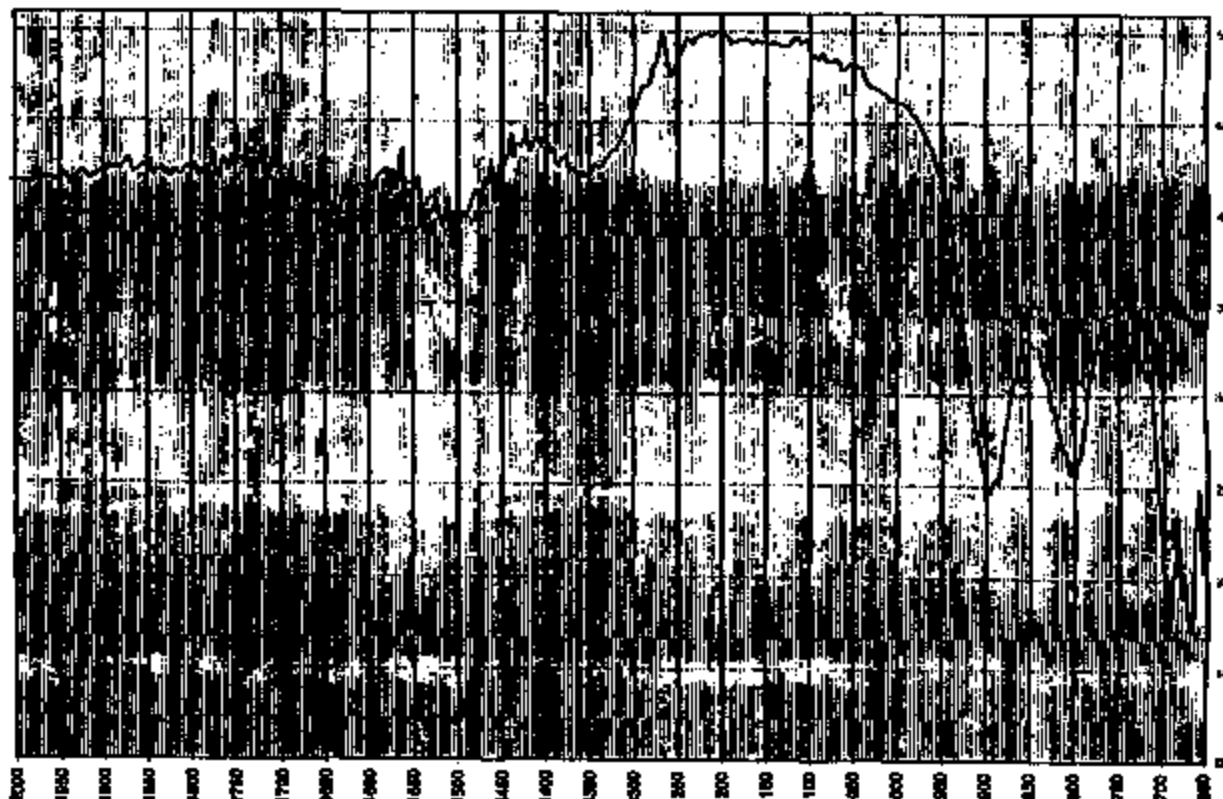
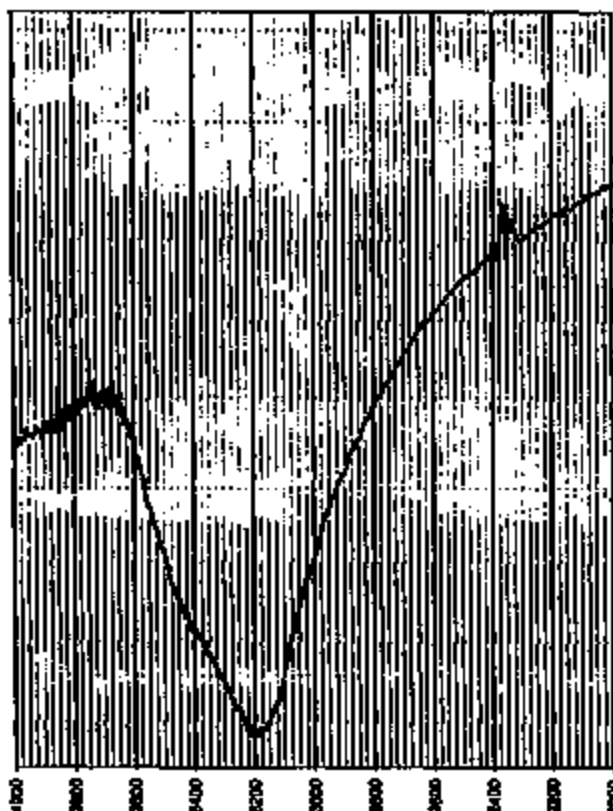
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: mjl

Concave:

Interpretation: inorganic - probably including yellow iron oxide + trace silicone



3713 2779

9900226 "C" CUP, SWITCH SIDE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 14:41:52 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Baer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

Y Axis: % Transmittance

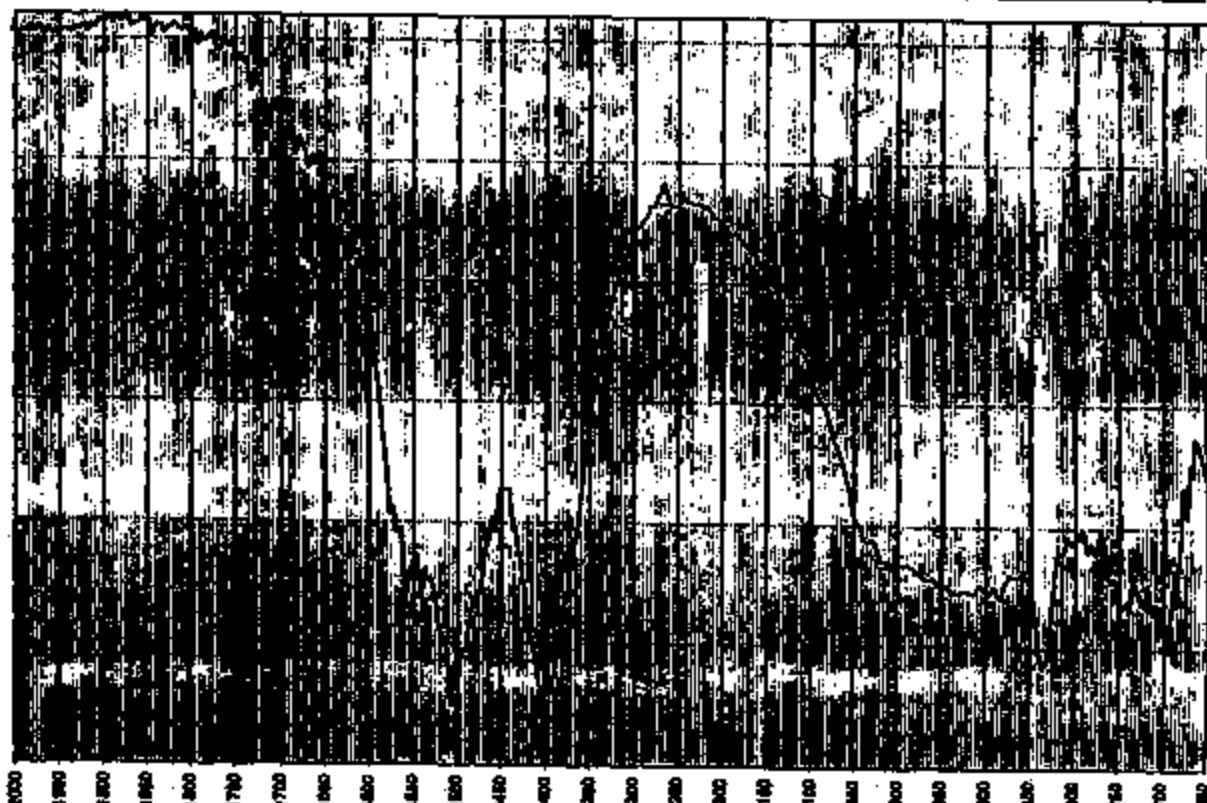
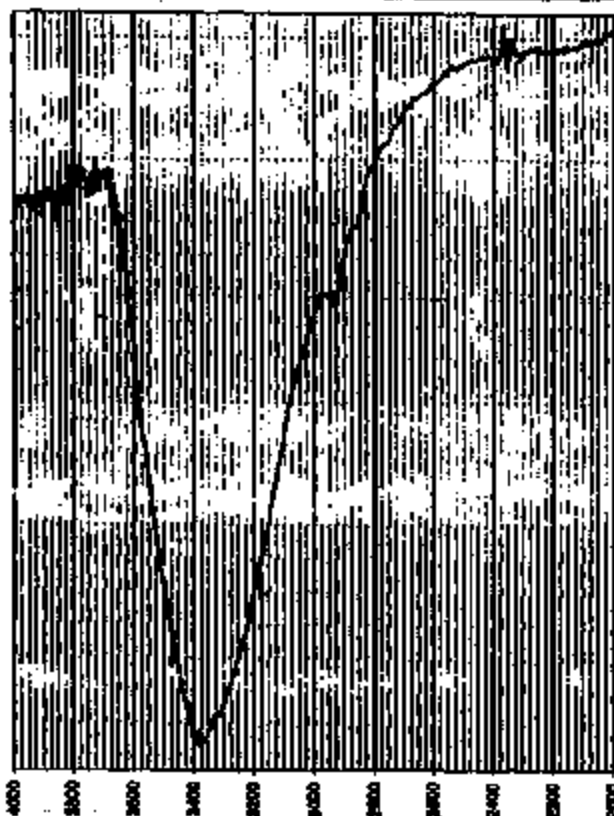
X Axis: Wavenumber

Engineer: *MCH*

Comment:

Interpretation:

metallic surface with organic residue, possibly from the switch mechanism.



3713 2780

9900226 "C", WASHER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 08:32:37 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Baeer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

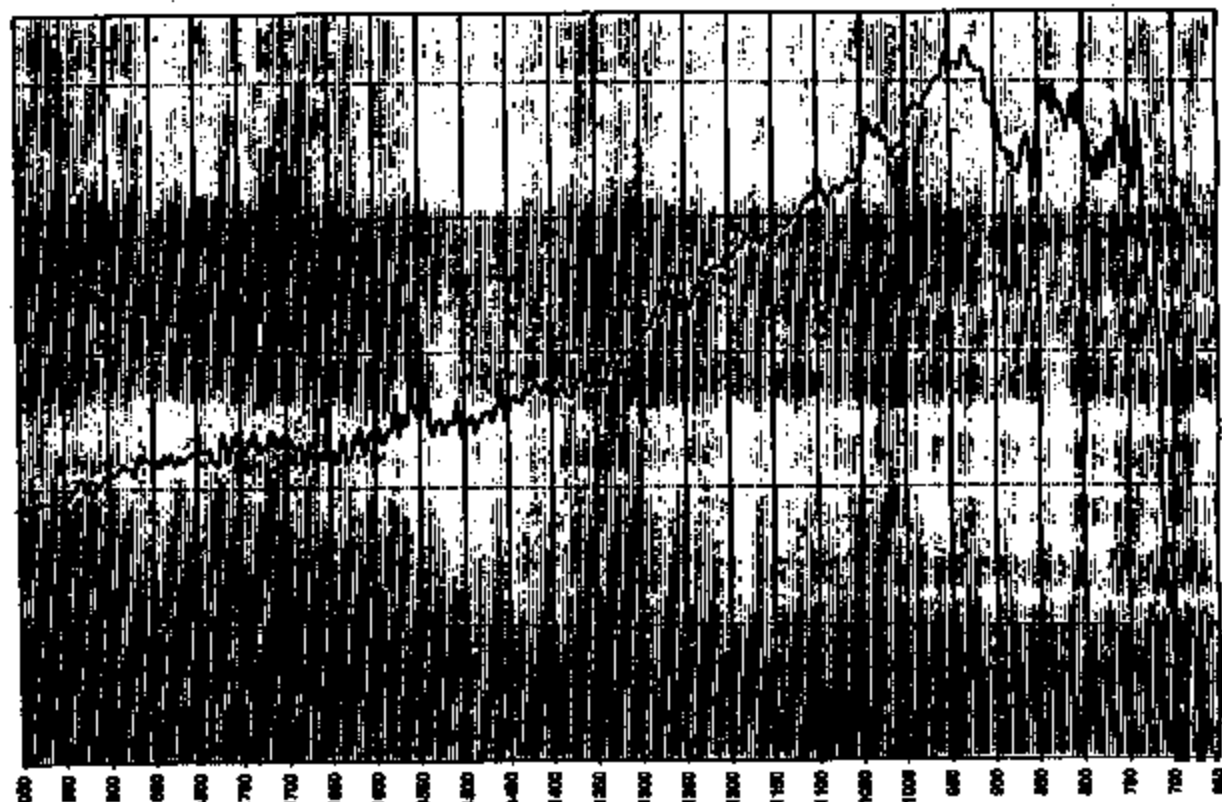
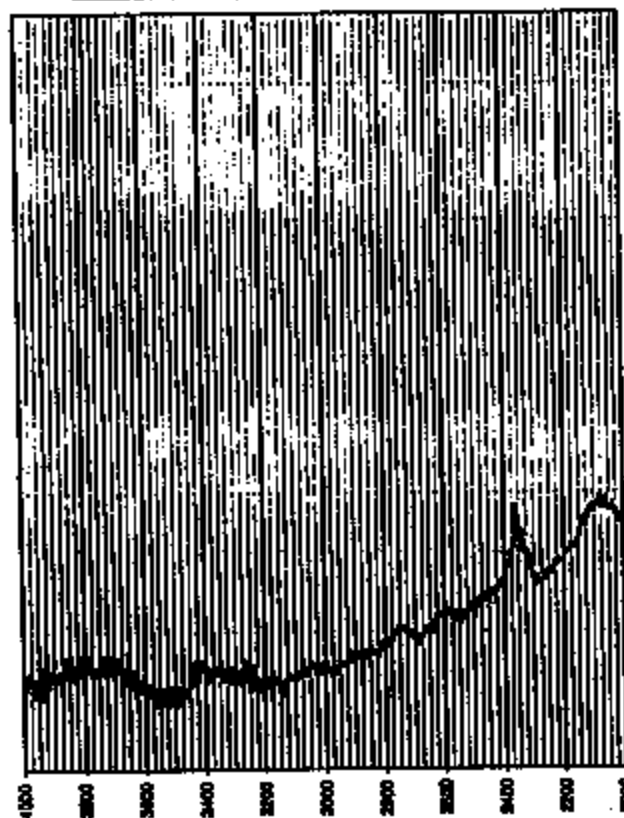
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *MCH*

Contact:

evidence of isodurics



3713 2781

9900226 "C", CONVERTER

Specification:
Supplier:
Preparation method: AS RECEIVED
IR Technique: MICROSCOPE

Wed Feb 10 08:36:35 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

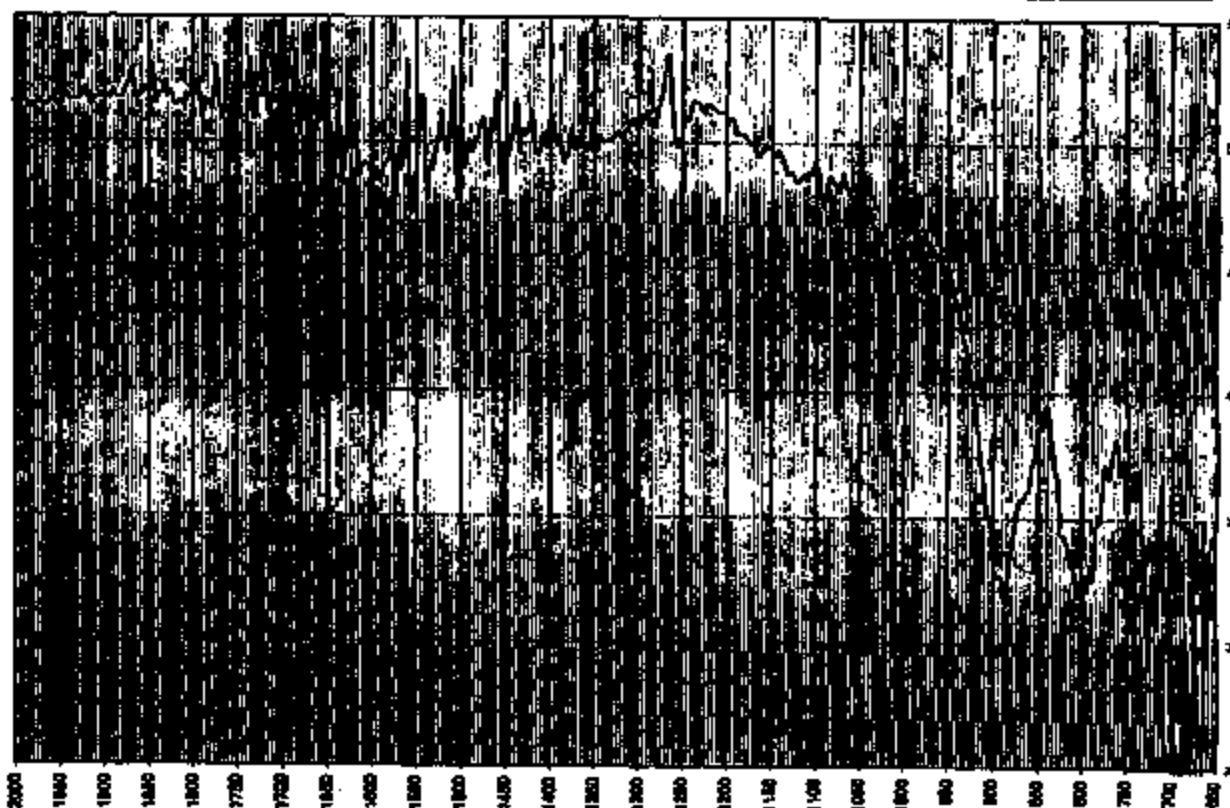
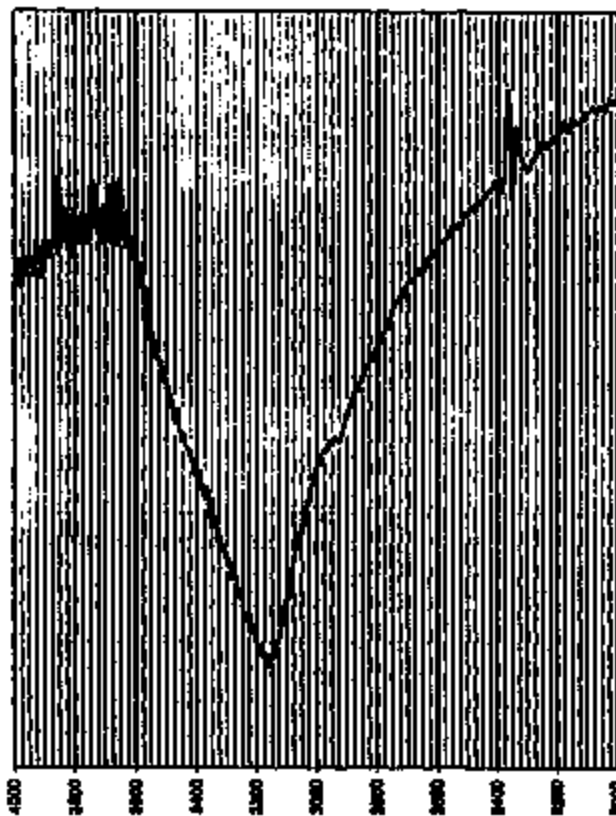
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *mj*

Interpretation:

Insulator, probably including yellow van oxide & trace silicone



3719 2782

9900226 "C", DISC

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Wed Feb 10 08:50:54 1999

Engineer: MCH

Scan: 128 / 256

APOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[16]

Gain: 4 / 4

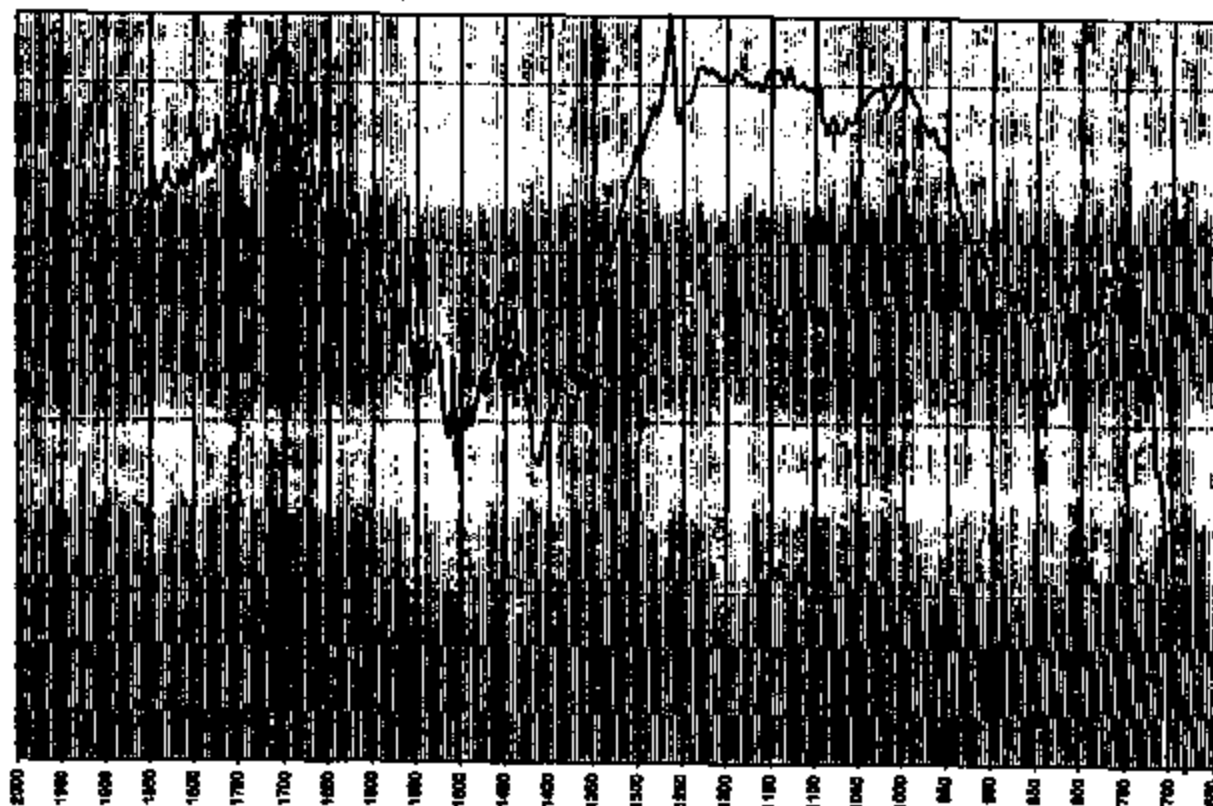
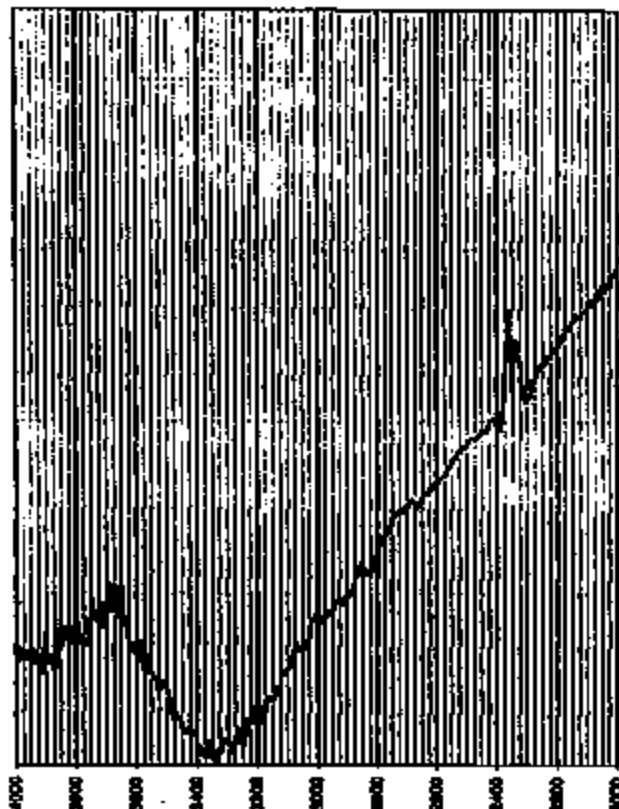
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *mt*

Interpretation:

new spec & compare to previous spec file



3713 2783

9900226 "D", HEXPORT, FITTING END

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 13:52:24 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Bear (medium)

Detector: MCT[16]

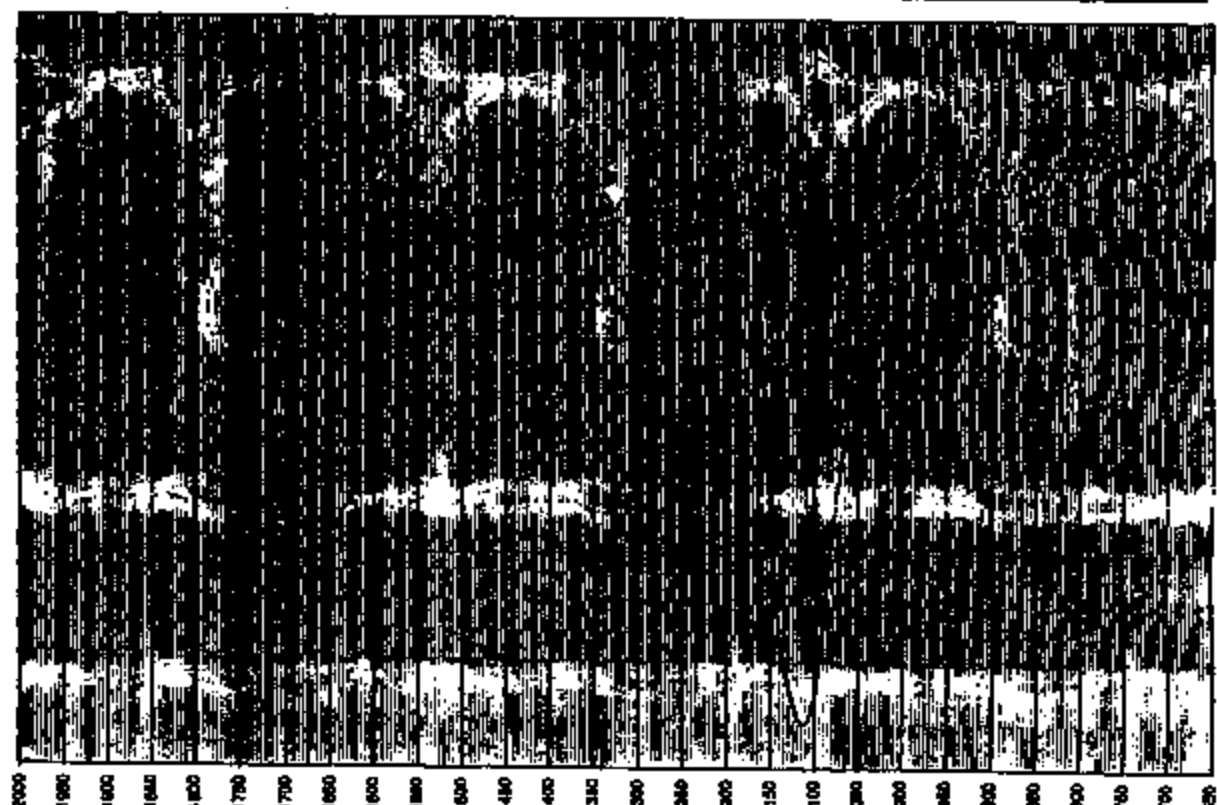
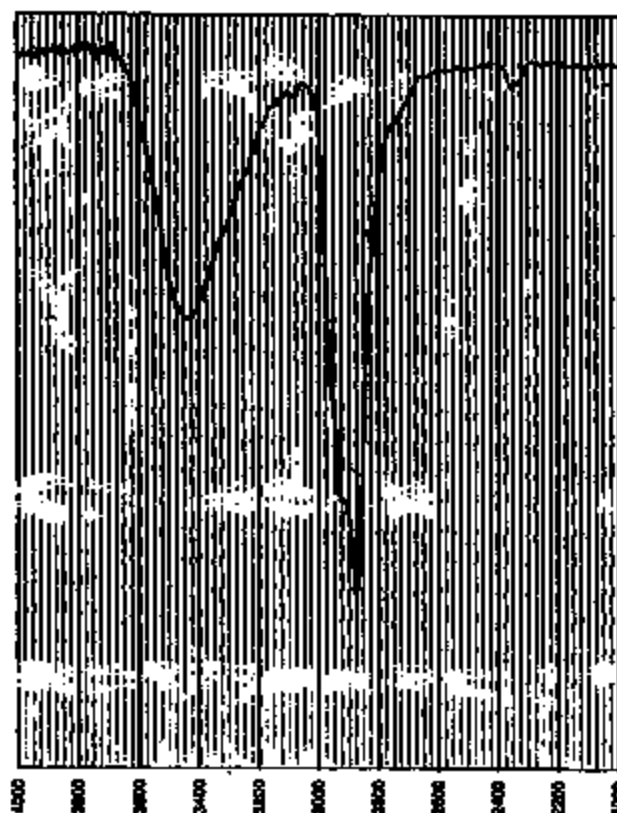
Y Axis: % Transmittance X Axis: Wavenumber

Engineer: *mg*

Center:

Interpretation:

glycol based material (probably brake fluid) - metal seal (probably on outside)



9900226 "D", HEXPORT, CAVITY

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 13:47:09 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

X Axis: Wavenumber

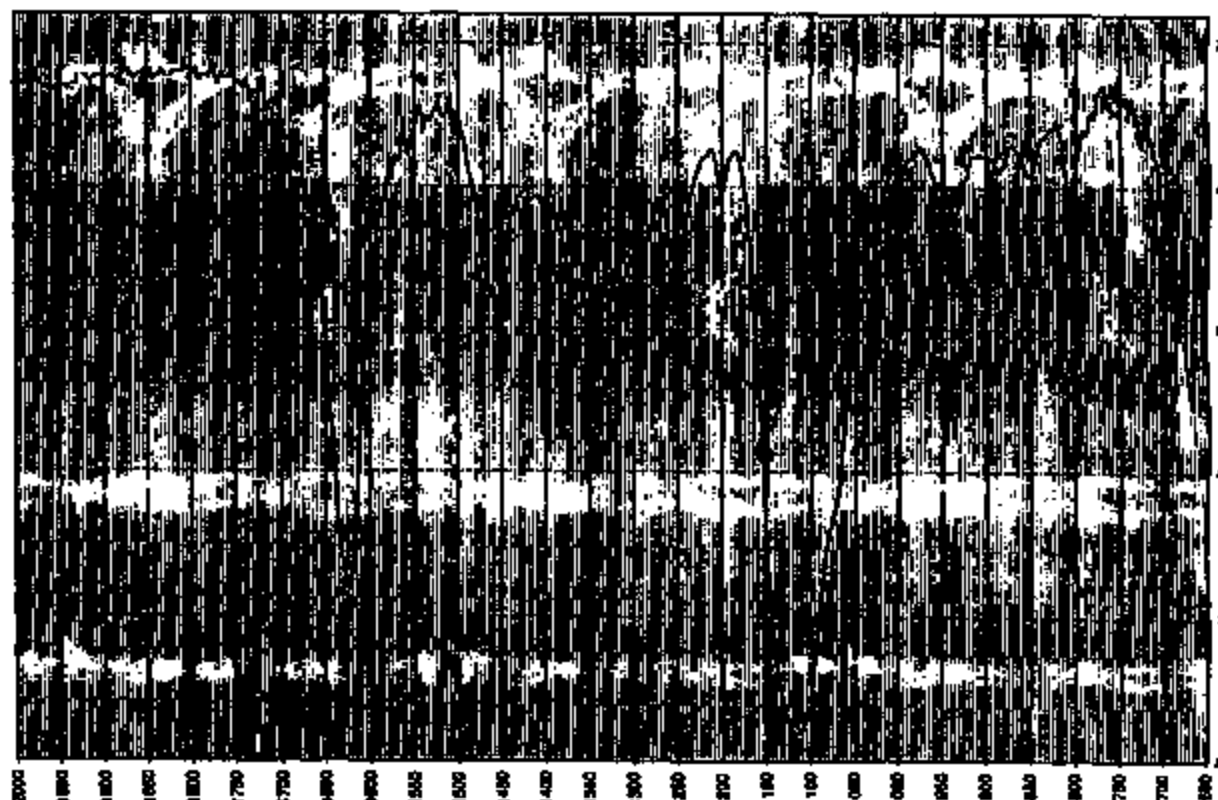
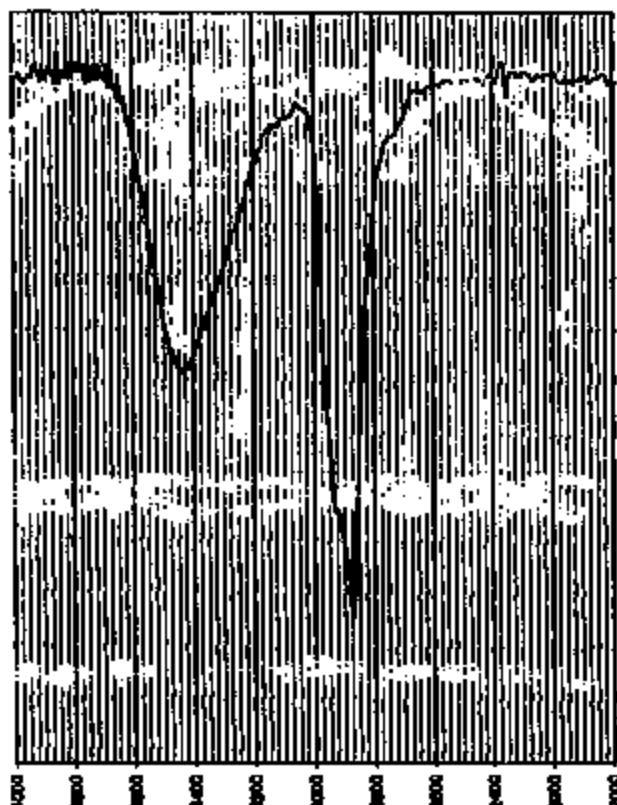
Engineer:

my

Comment:

Interpretation:

*glycol based material (possibly Bunker fluid) - maybe 92/8 (probably not a pure)
Eqbm (pH) + ms (pH)*



3713 2785

9900226 "D" SEAL 1, LIQUID WITH BLACK

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 09:03:25 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[16]

Gain: 2R / 2R

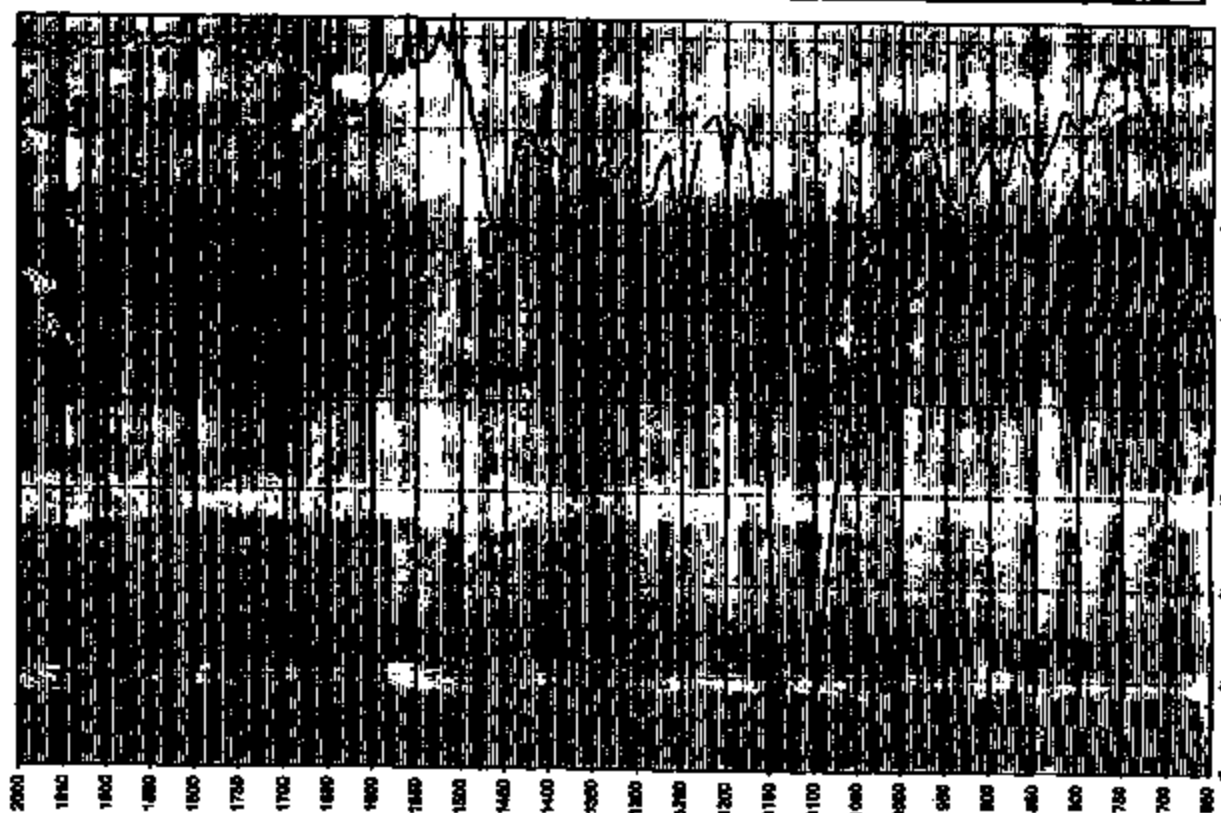
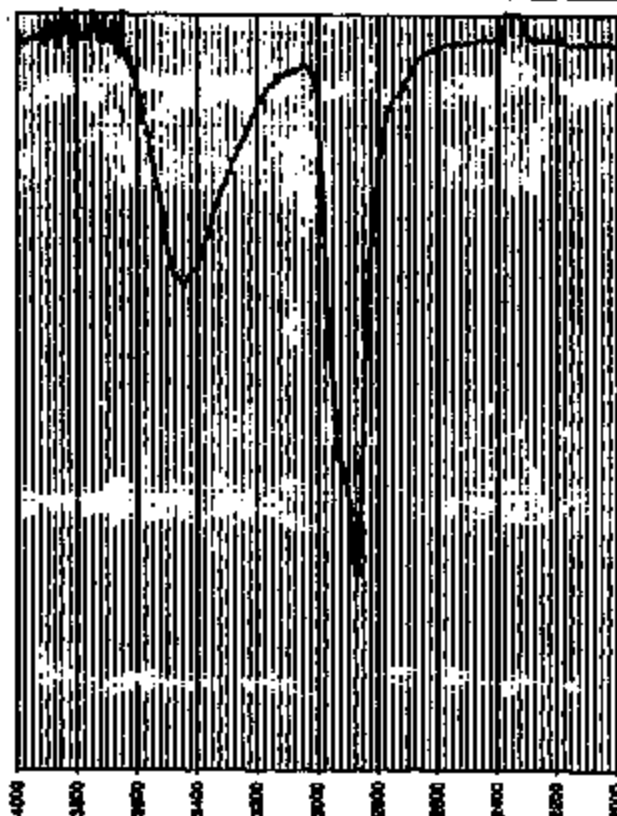
Y Axis: % Transmittance X Axis: Wavenumber

Engineer:

WV

Operator:

glan [PDF]



9713 2786

9900226 "D" SEAL 2, RESIDUE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 09:43:34 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

Y Axis: % Transmittance

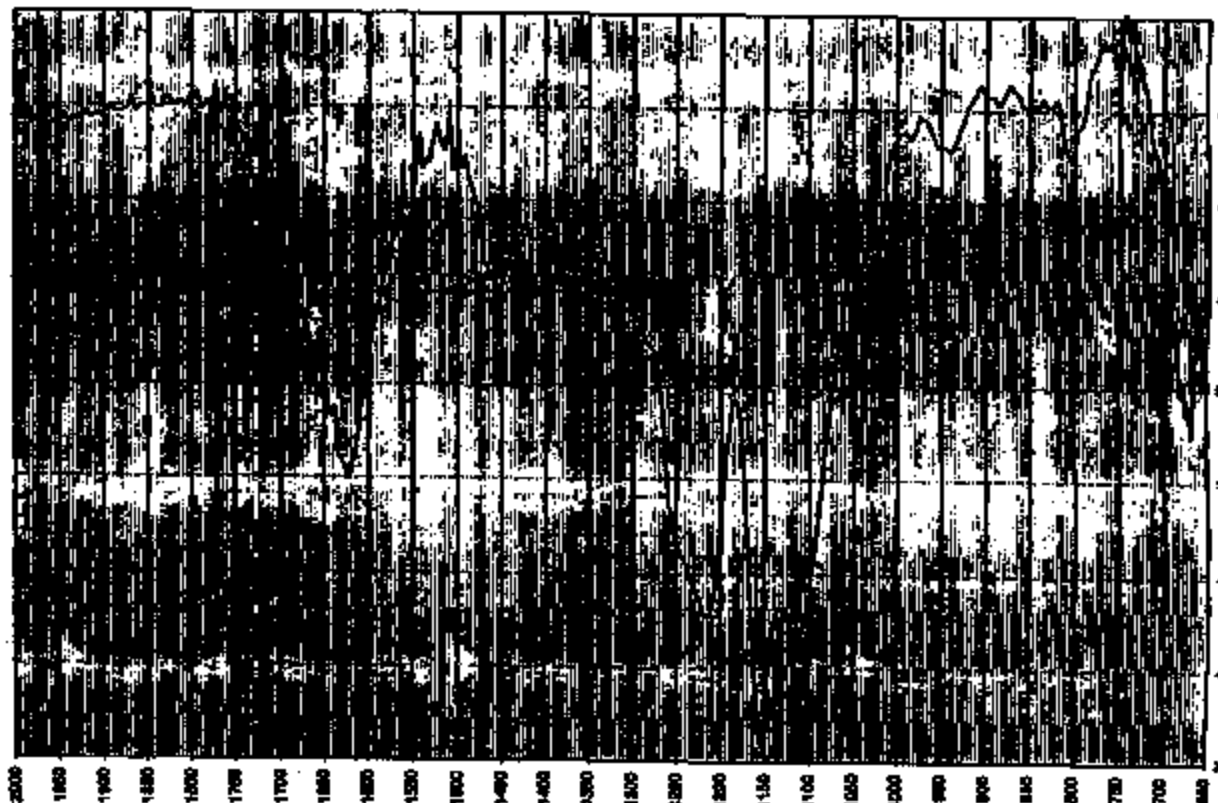
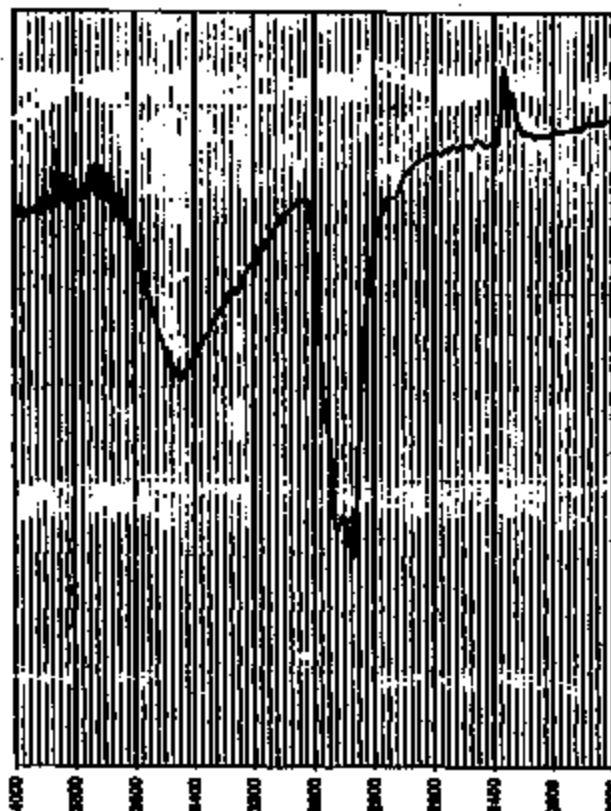
X Axis: Wavenumber

Comment:

Conc:

Interpretation:

m.s. (p.v) → glen + AFM/PEP



8713 2787

9900226 "D" SEAL2

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 09:38:54 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

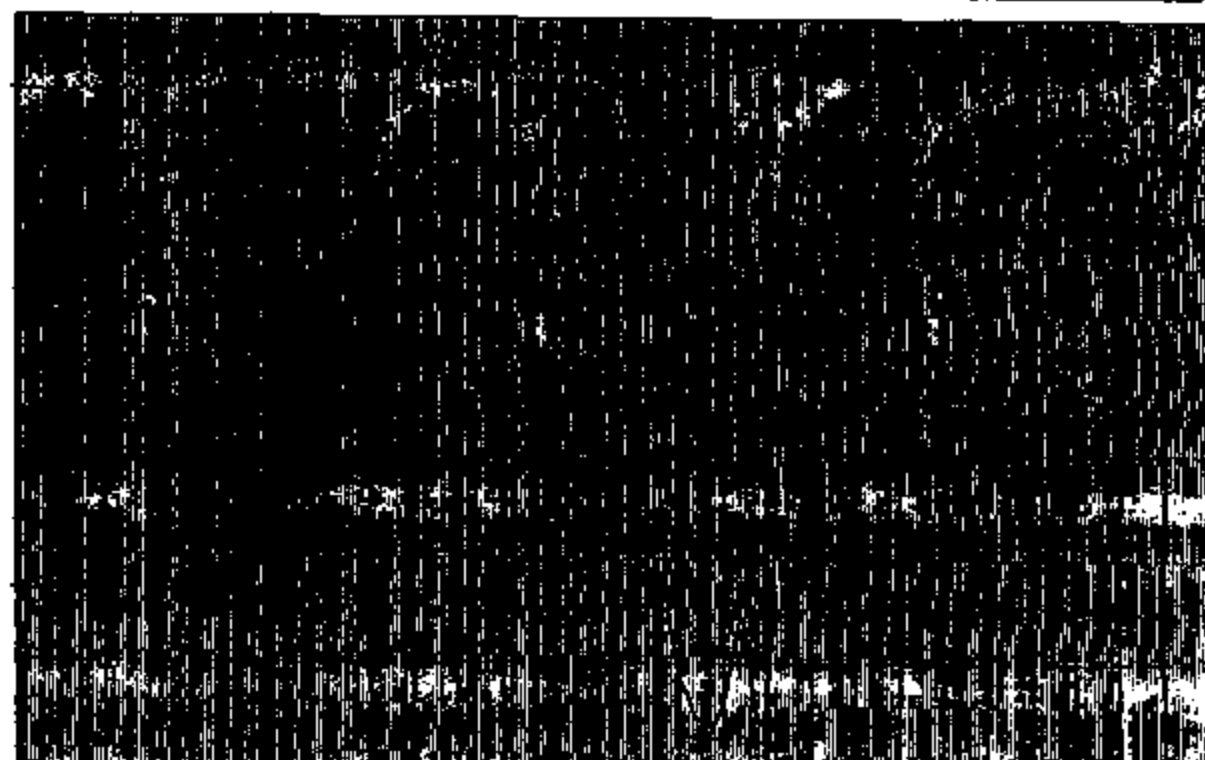
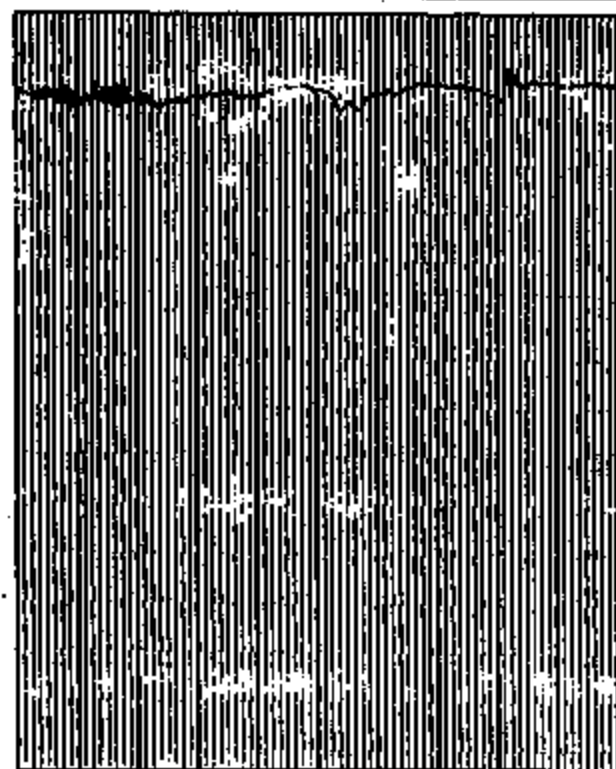
Gain: 2A / 2A

Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Operator:



3713 2789

9900226 "D" SEAL 3,FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

m.s. (p.o) 456m

Mon Feb 08 09:14:04 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

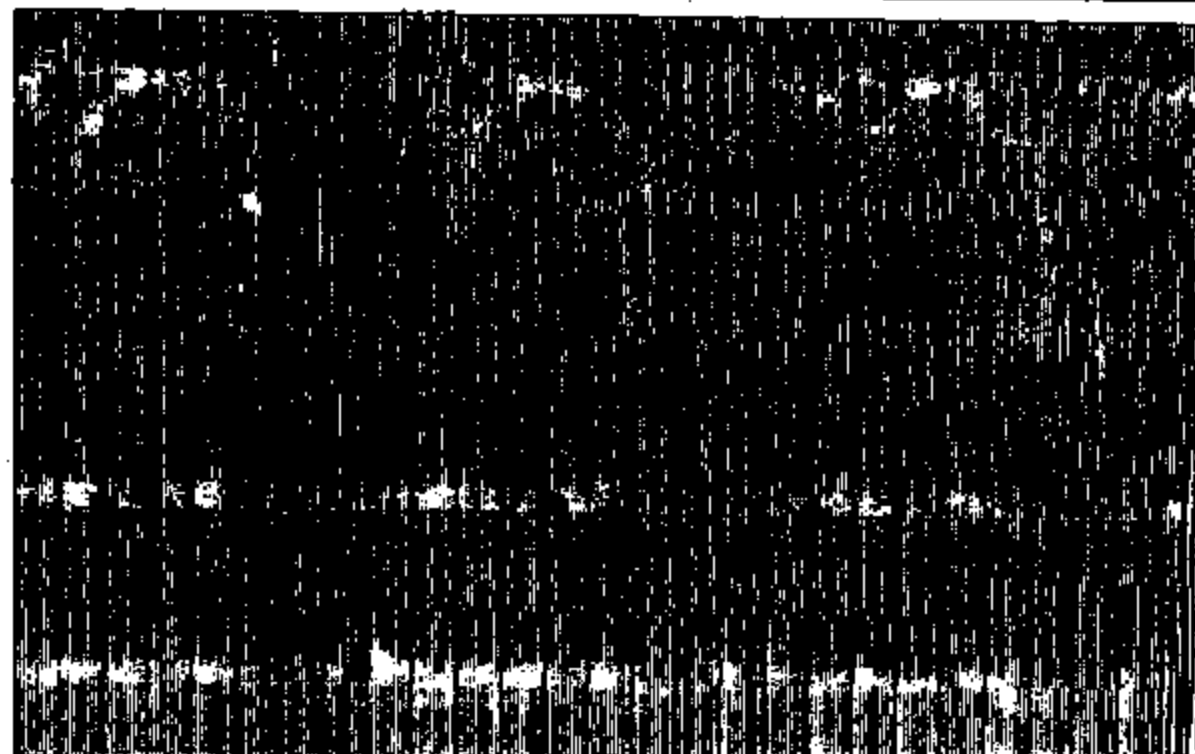
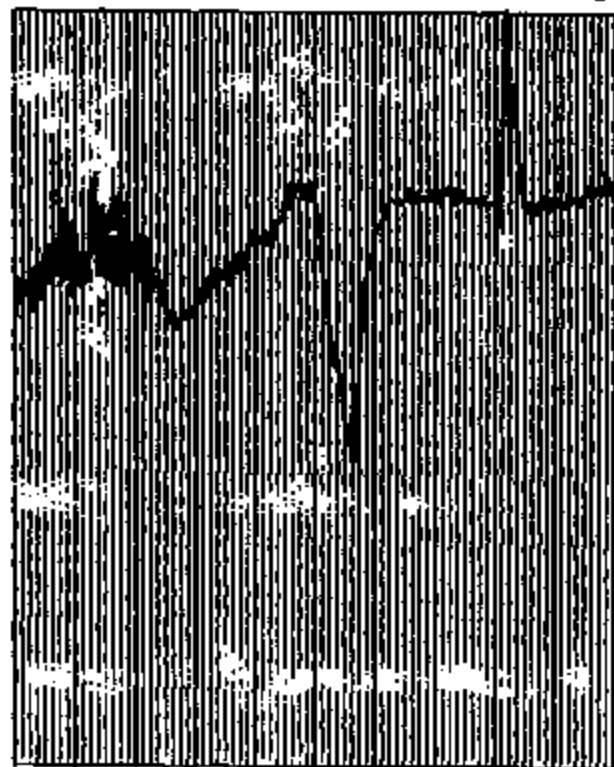
Detector: MCT[16]

Gain: 2H / 2R

Y Axis: % Transmittance X Axis: Wavenumber

Engineer:

Colour:



3713 2789

9900226 "D" SEAL 3, BROWN/BLACK RESIDUE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 08:11:05 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[16]

Gain: 2R / 2R

Y Axis: % Transmittance

X Axis: Wavenumbers

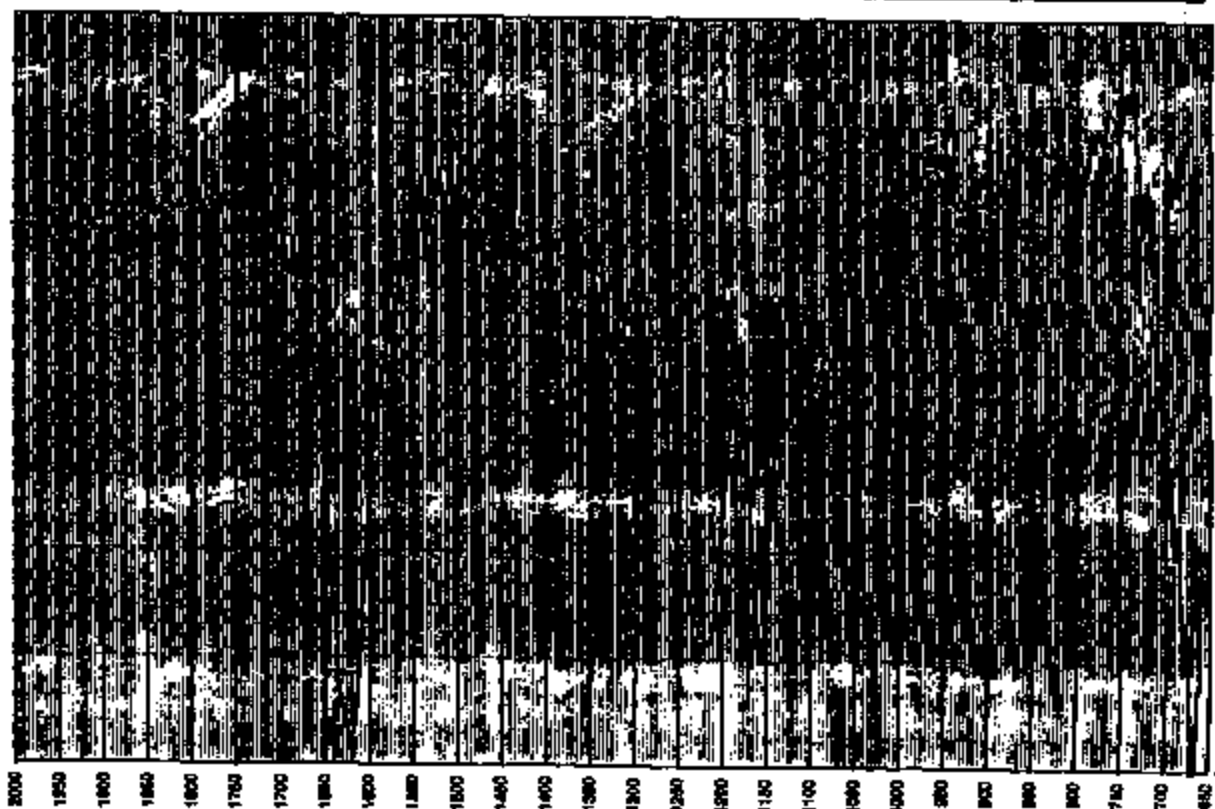
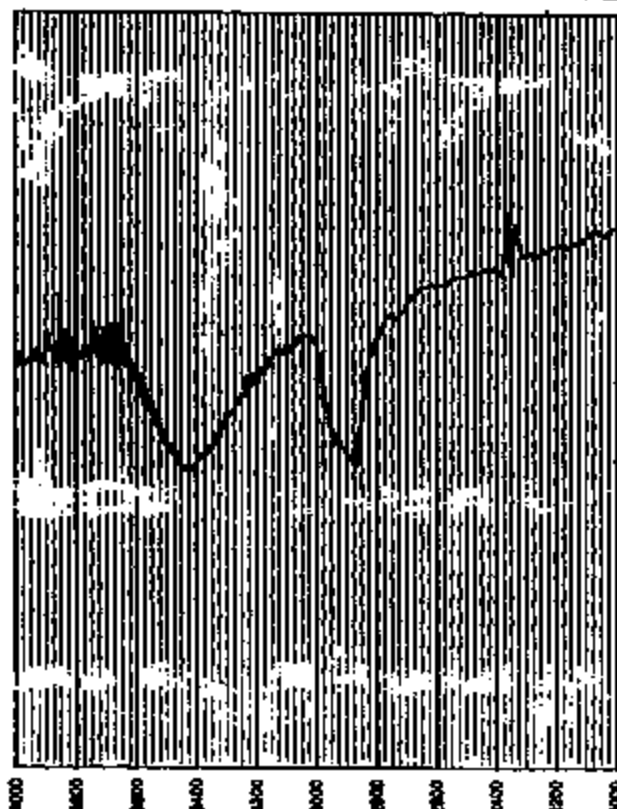
Engineer:

MJ

Comment:

Interpretation:

m.s.g.o) + M2 L11n FUP



3718 2790

9900226 "D", WASHER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 14:43:03 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Beer (medium)

Detector: MCT[15]

Y Axis: % Transmittance

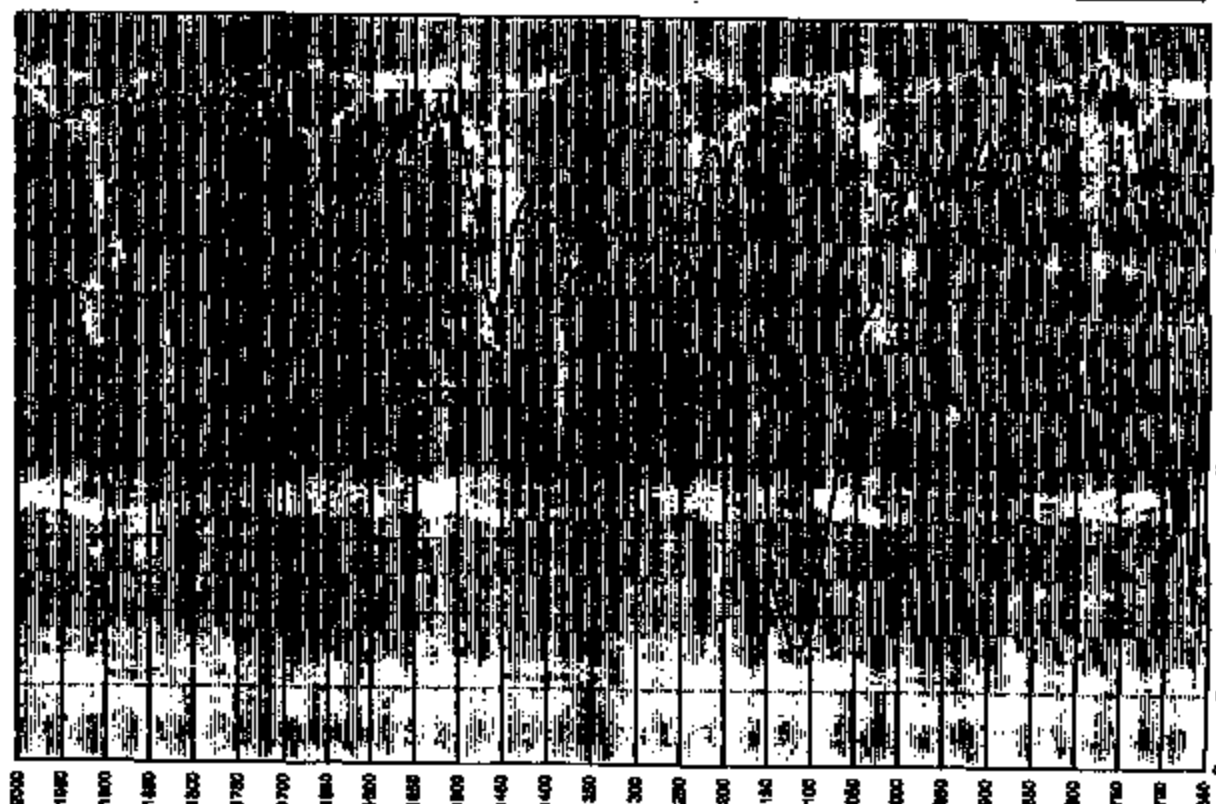
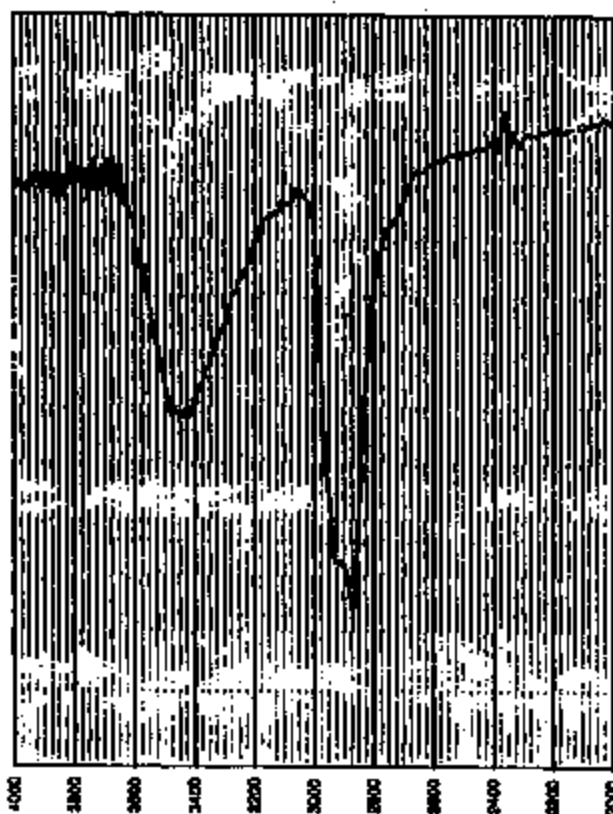
X Axis: Wavenumber (cm⁻¹)

Engineer: *ML*

Client:

Interpretation:

glass (ref) + ms (po)



8713 2791

9900226 "D", CONVERTER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

ess - gum (150)

Fri Feb 05 14:47:18 1999

Scan: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MOH

APOD: Norton-Beer (medium)

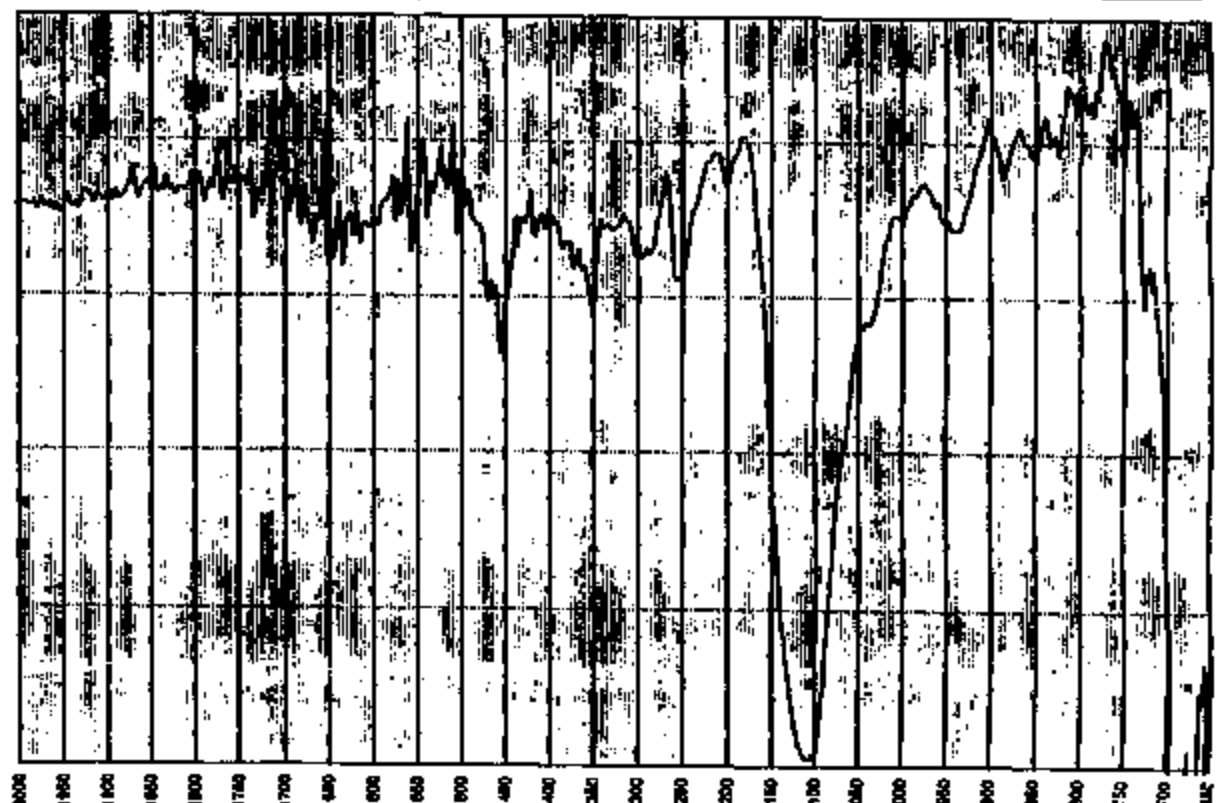
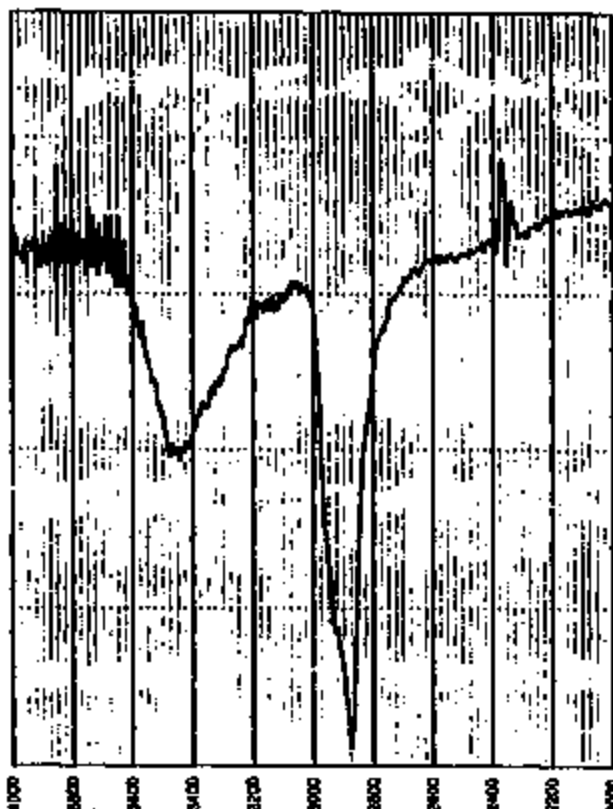
Detector: MCT[16]

Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Operator:



3718 2792

9900226 "D", SPACER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Fri Feb 05 14:57:36 1999

Scan: 126 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Beer (medium)

Detector: MCT[15]

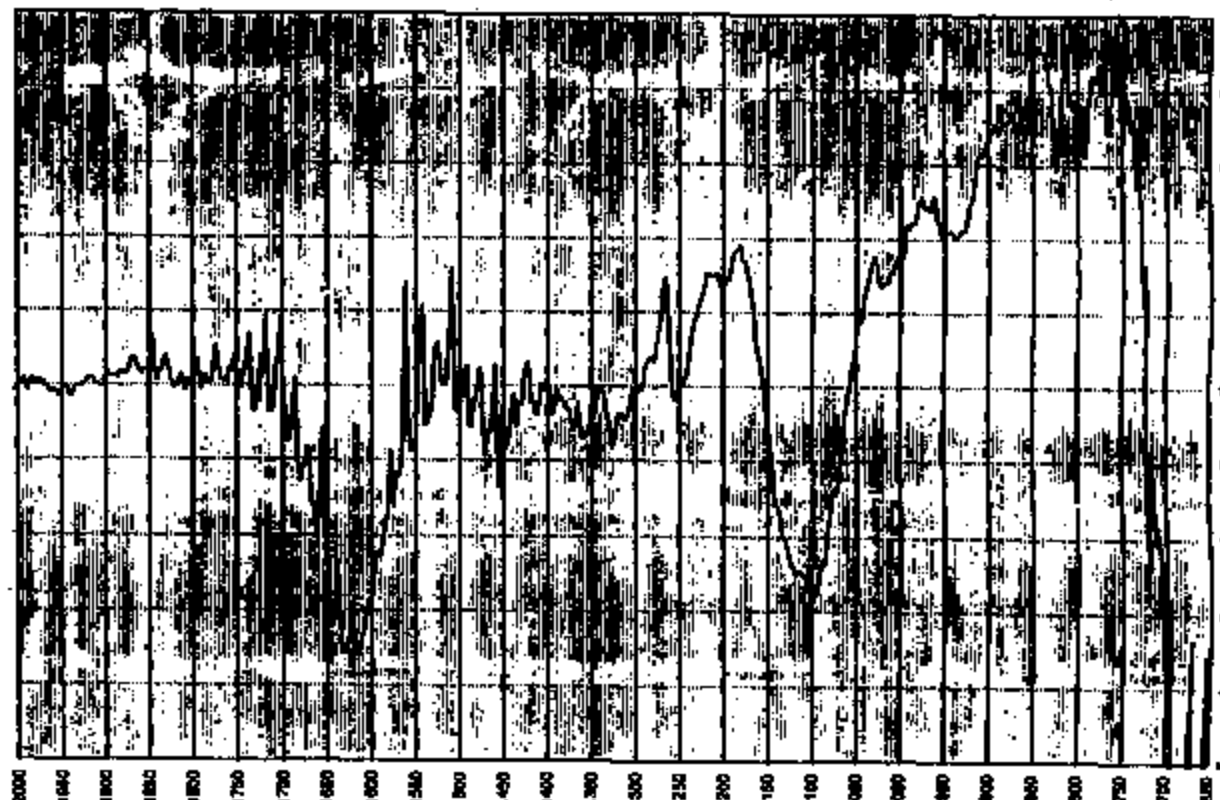
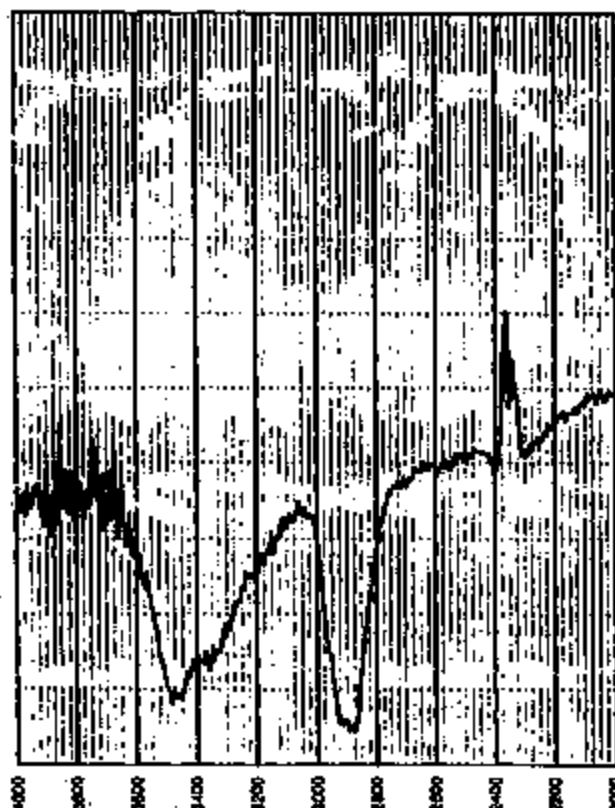
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Comment:

MS (rubt) gbm



3713 2793

9900226 "D", DISC

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 06 14:54:18 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Beer (medium)

Detector: MCT[15]

Y Axis: % Transmittance

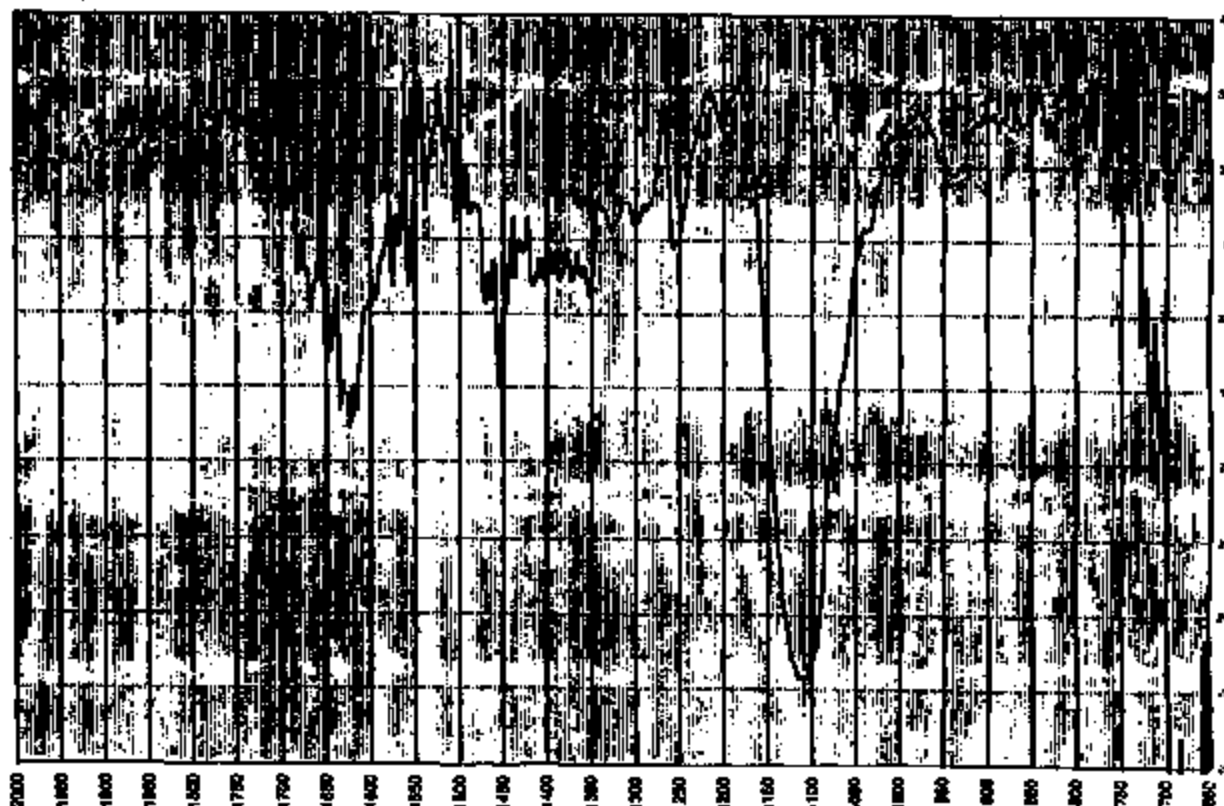
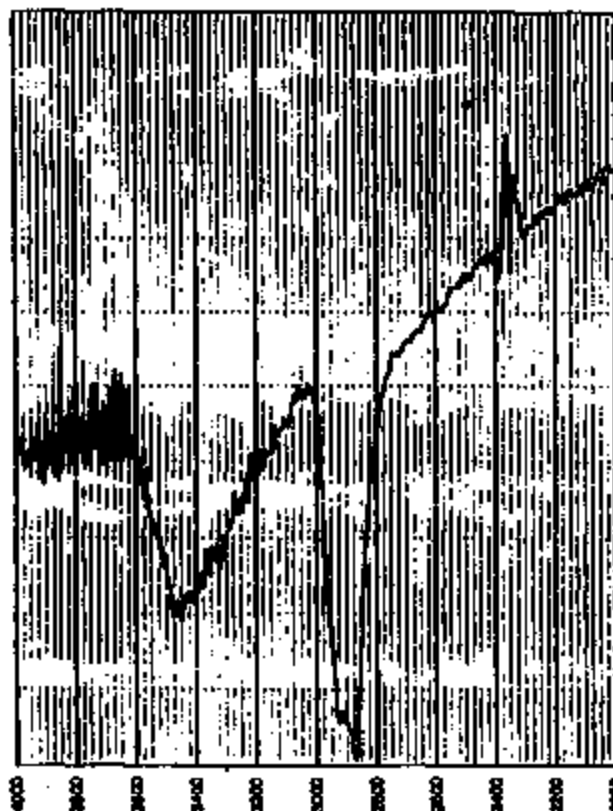
X Axis: Wavenumber

Engineer:

MCH

Center:

Interpretation: $\text{H}_2\text{O}(\text{v.o.})$ + SiH_4



3713 2794

9900226 "D", CUP, INTERIOR

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 14:07:58 1989

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCM

APOD: Norton-Beer (medium)

Detector: MCT[15]

Y Axis: % Transmittance

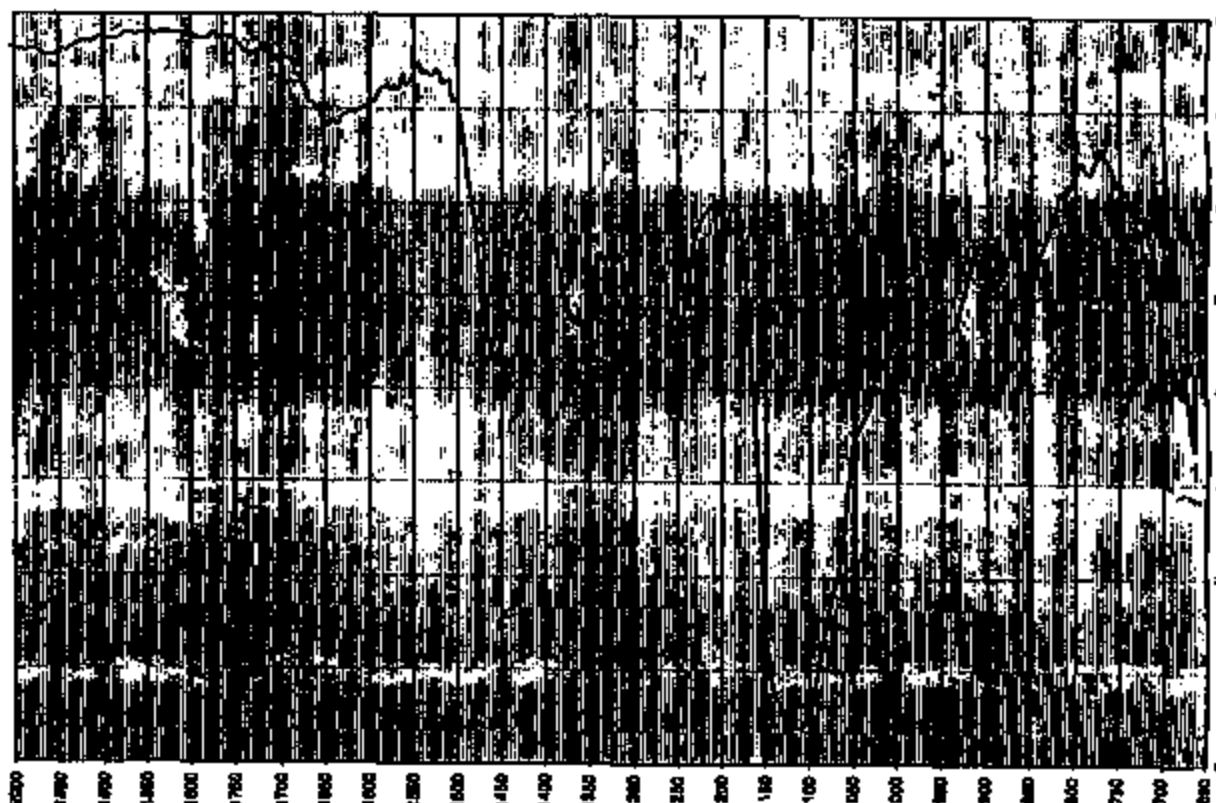
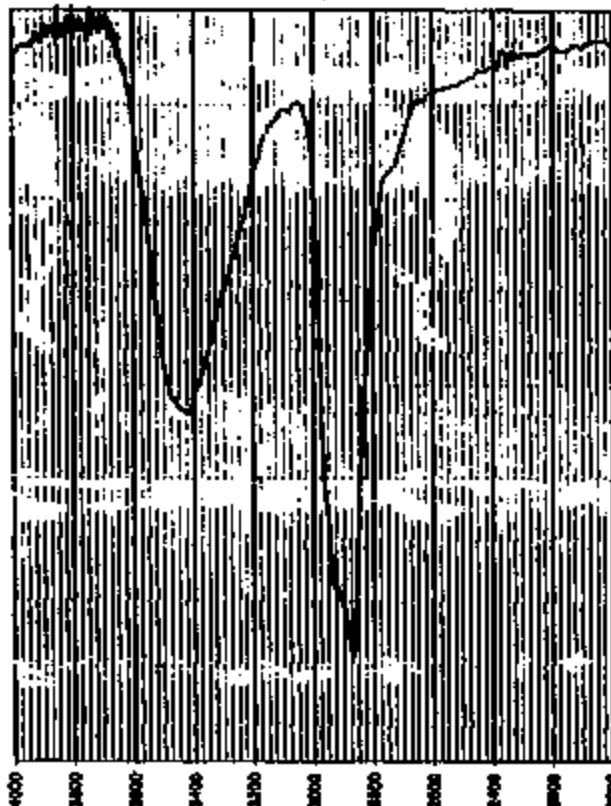
X Axis: Wavenumber

Engineer: *MCM*

Comment:

Interpretation:

ghm (pBF)



3713 2795

9900226 "D", CUP, SWITCH SIDE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 14:19:20 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Beer (medium)

Detector: MCT[15]

Y Axis: % Transmittance

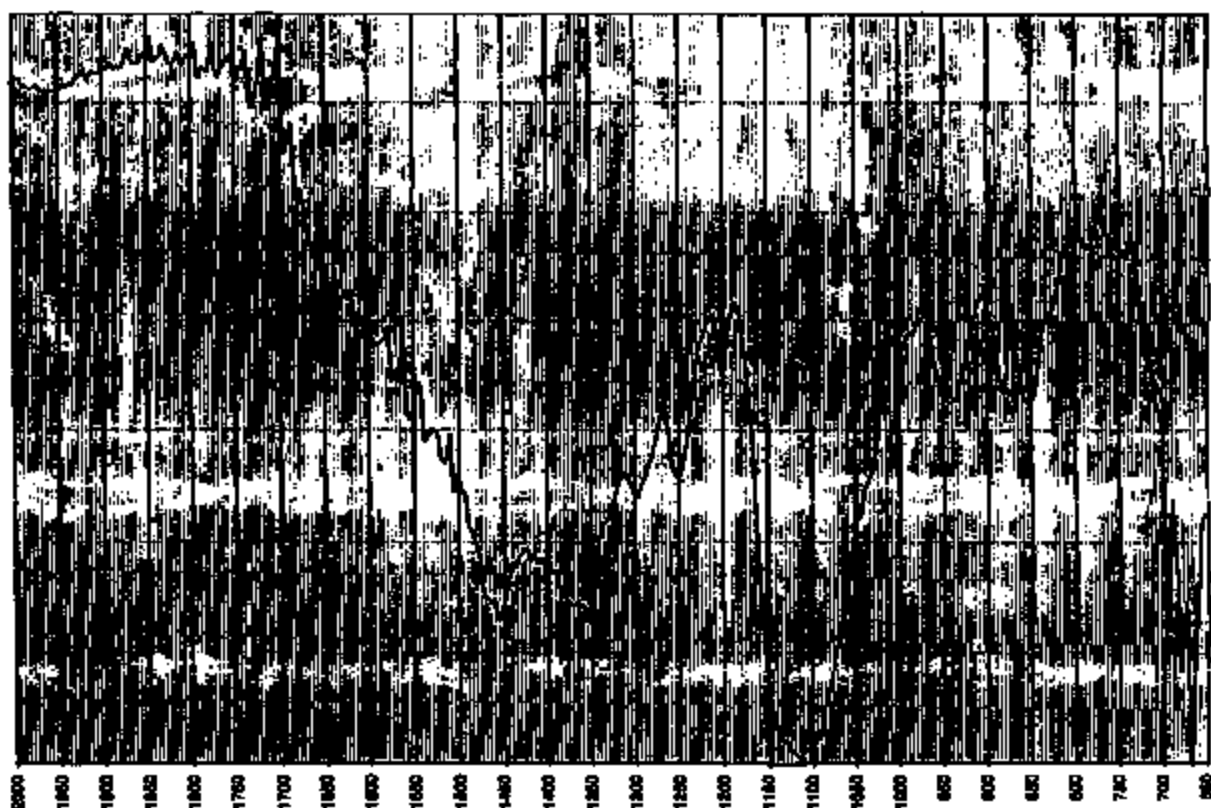
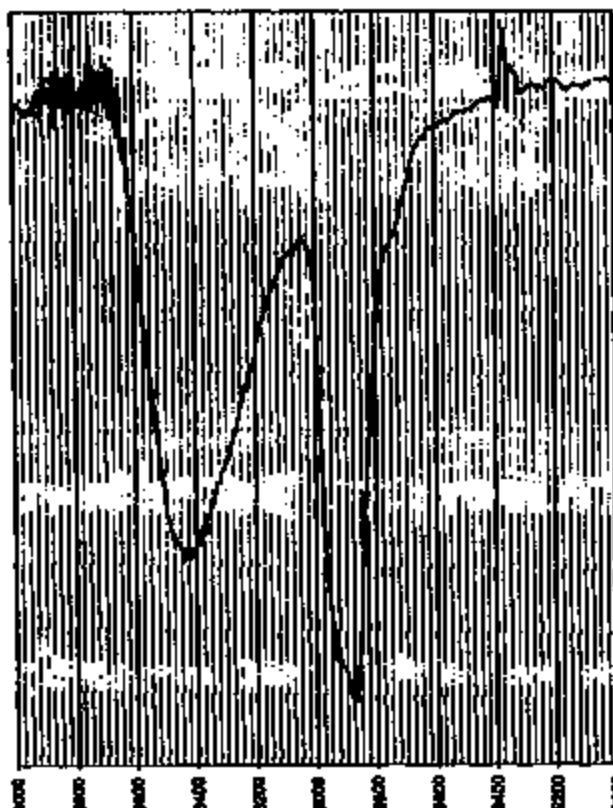
X Axis: Wavenumber

Engineer: *MCH*

Concur:

Interpretation:

glm (68r) + other hydrocarbon



3713 2796

9900226 "D", CONTACT

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 14:26:43 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Beer (medium)

Detector: MCT[15]

Y Axis: % Transmittance

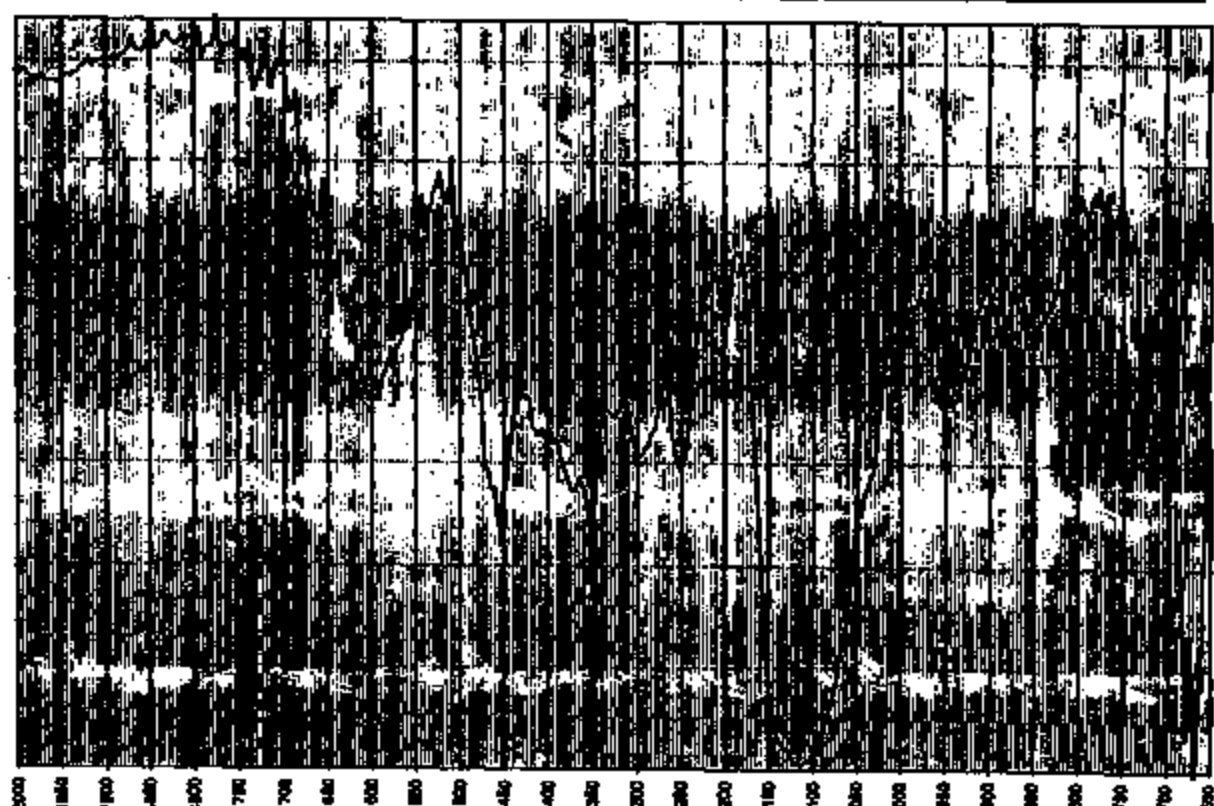
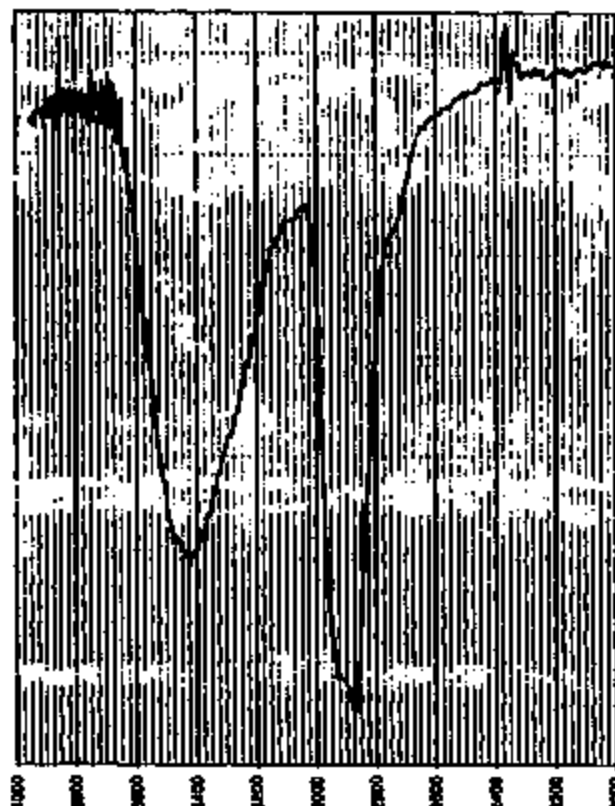
X Axis: Wavenumber

Engineer: MCH

Comment:

Interpretation:

ms + ybm (K₂Cr₂O₇)



3713 2797

9900226 "D", BASE, CONNECTOR CAVITY

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

ess. 86m (BP)

Fri Feb 05 14:29:48 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

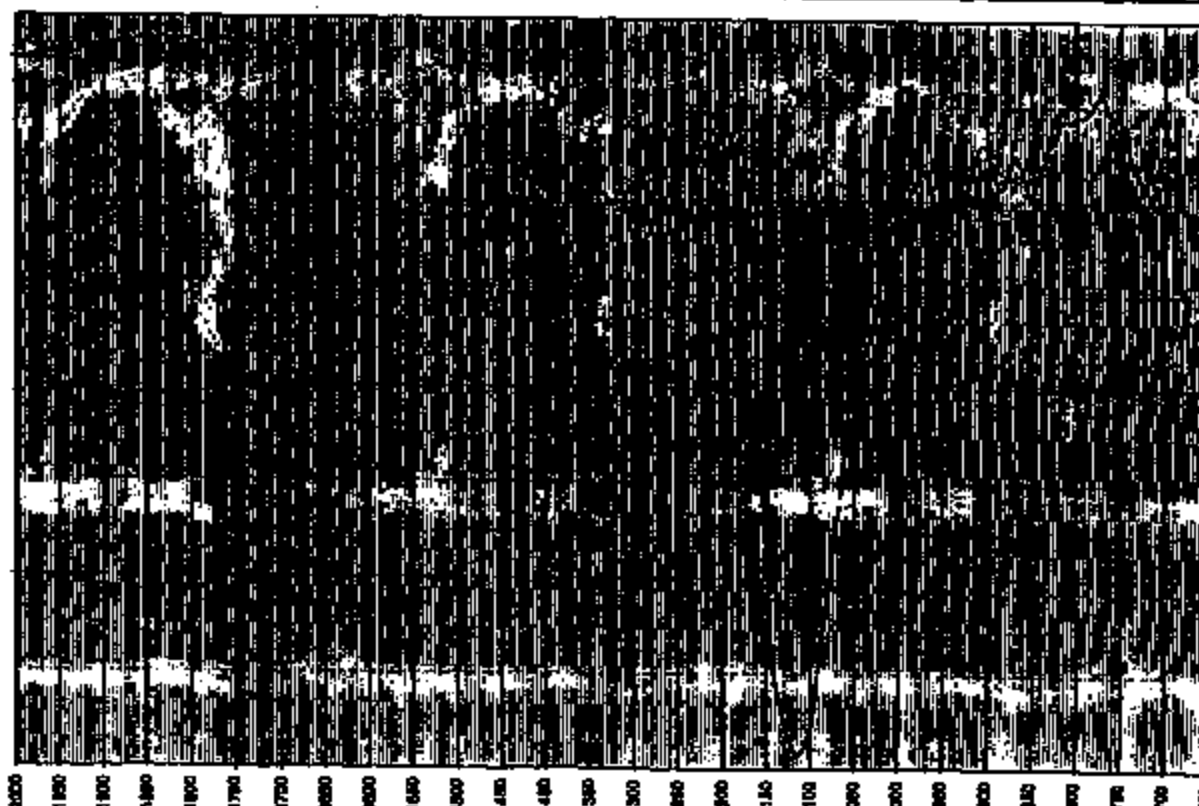
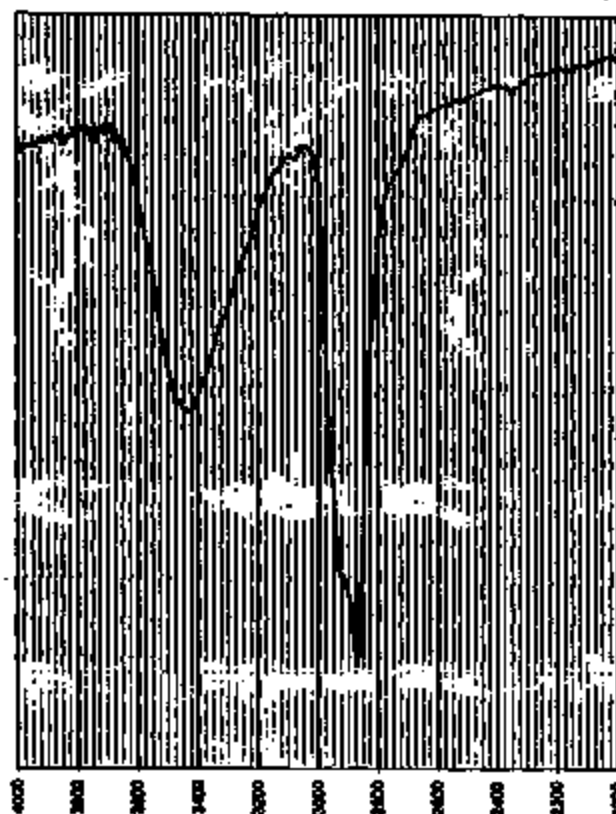
Engineer: MCH

APOD: Norton-Bear (medium)

Detector: MCT[15]

Y Axis: % Transmittance

X Axis: Wavenumber



3713 2796

9900226 "F" HEXPORT, FITTING END

Specification:
Supplier:
Preparation method: AS RECEIVED
IR Technique: MICROSCOPE

Wed Feb 10 09:17:23 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

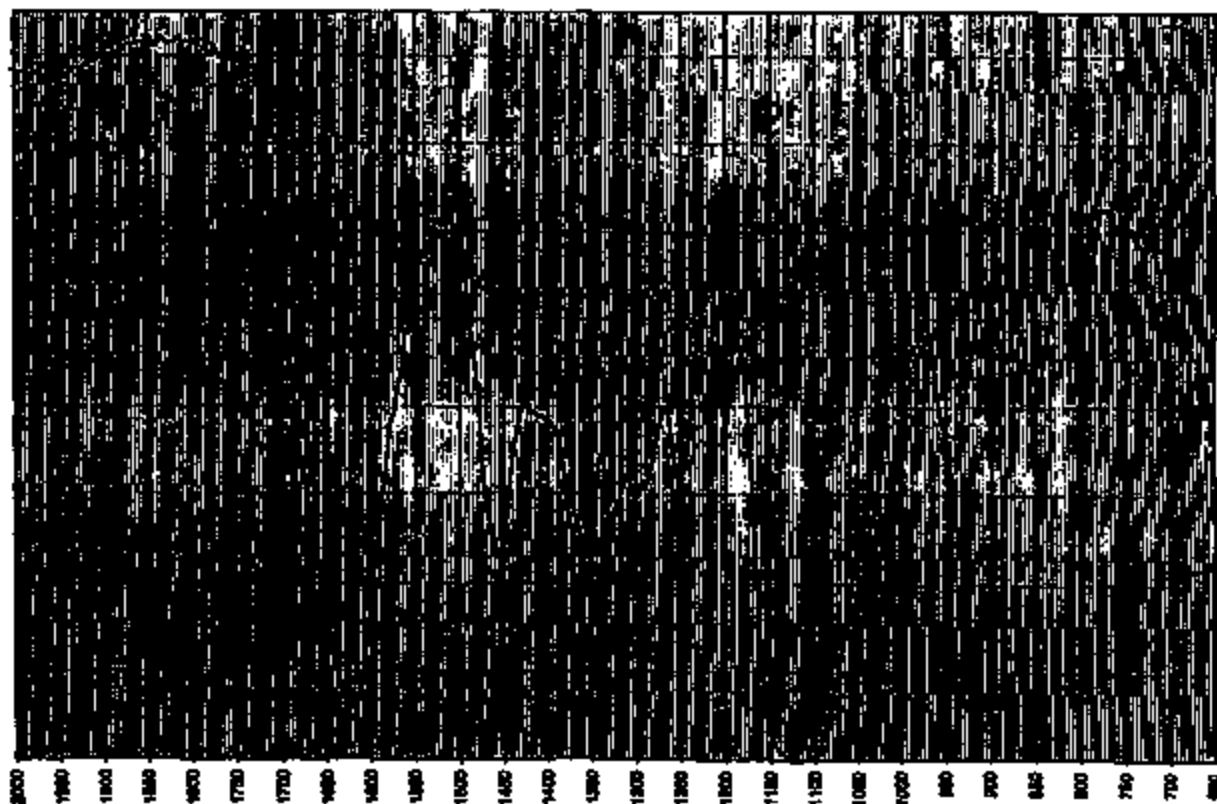
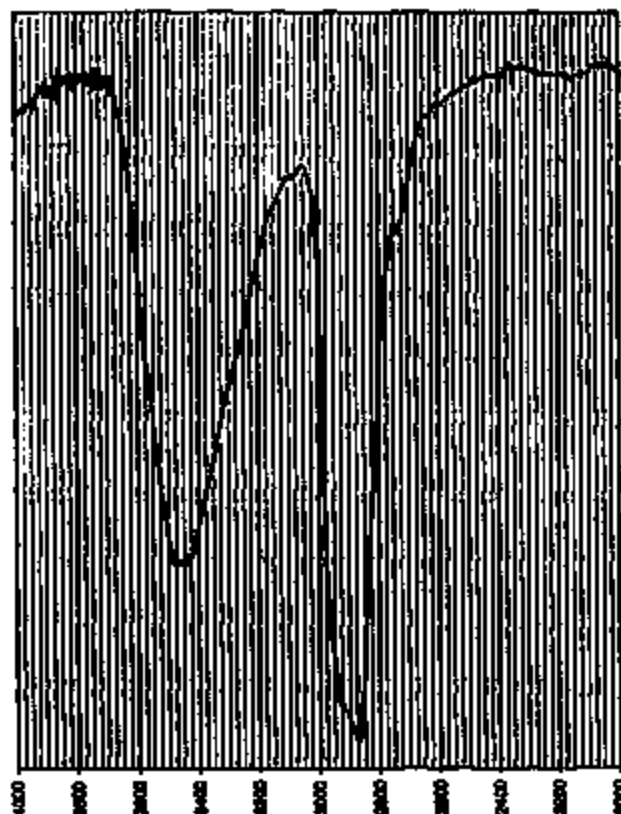
X Axis: Wavenumber

Engineer: *ML*

Comment:

Interpretation:

MS (p.u) & h₂ (p.p.f)



3713 2799

9900226 "F" HEXPORT, CAVITY

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 09:12:20 1998

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

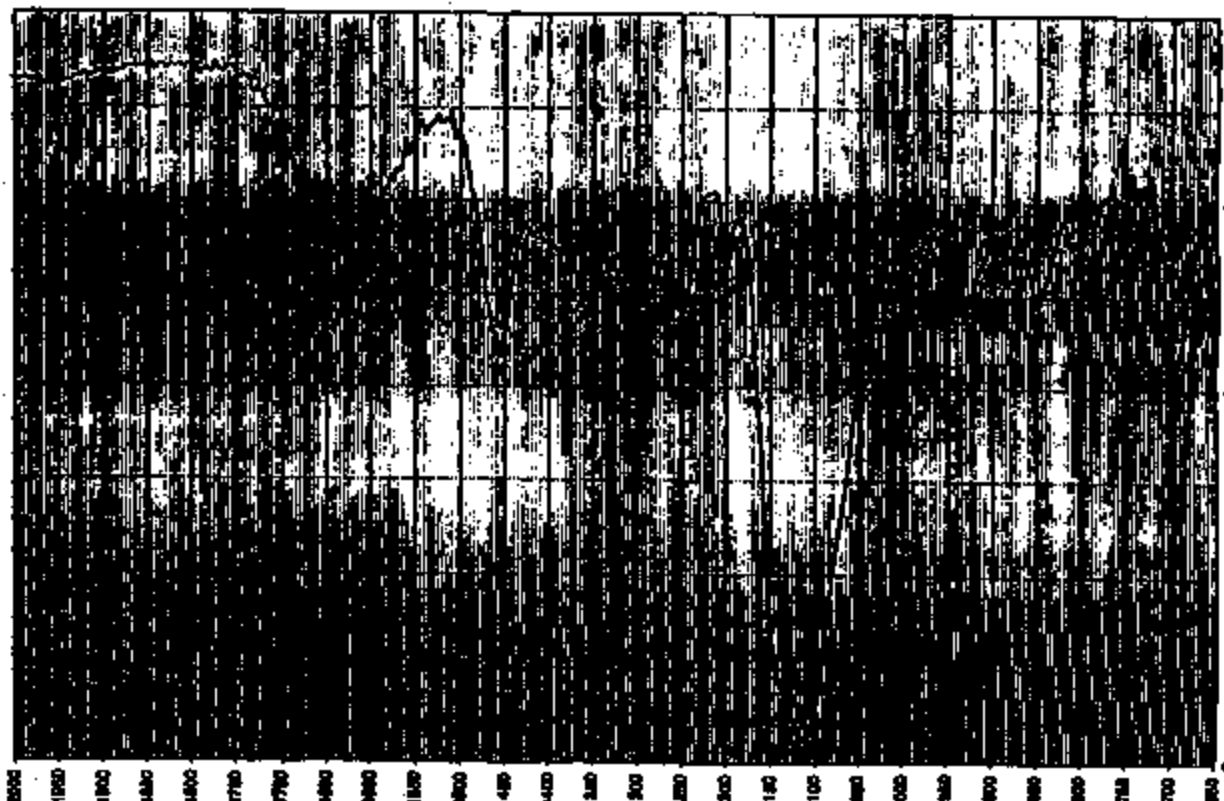
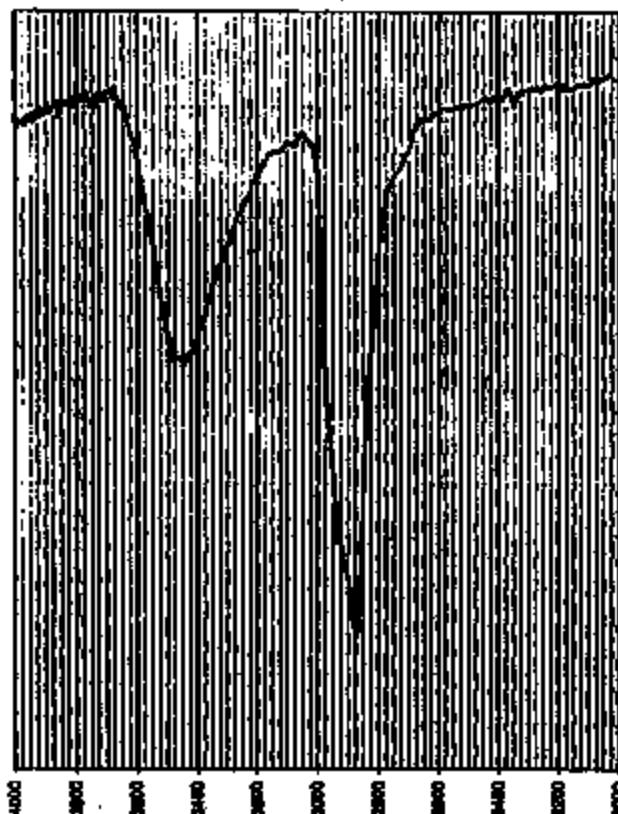
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *MCH*

Comment:

gl m (r R) + m (r)



3713 2800

9900226 "F" SEAL 1, FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 13:40:14 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

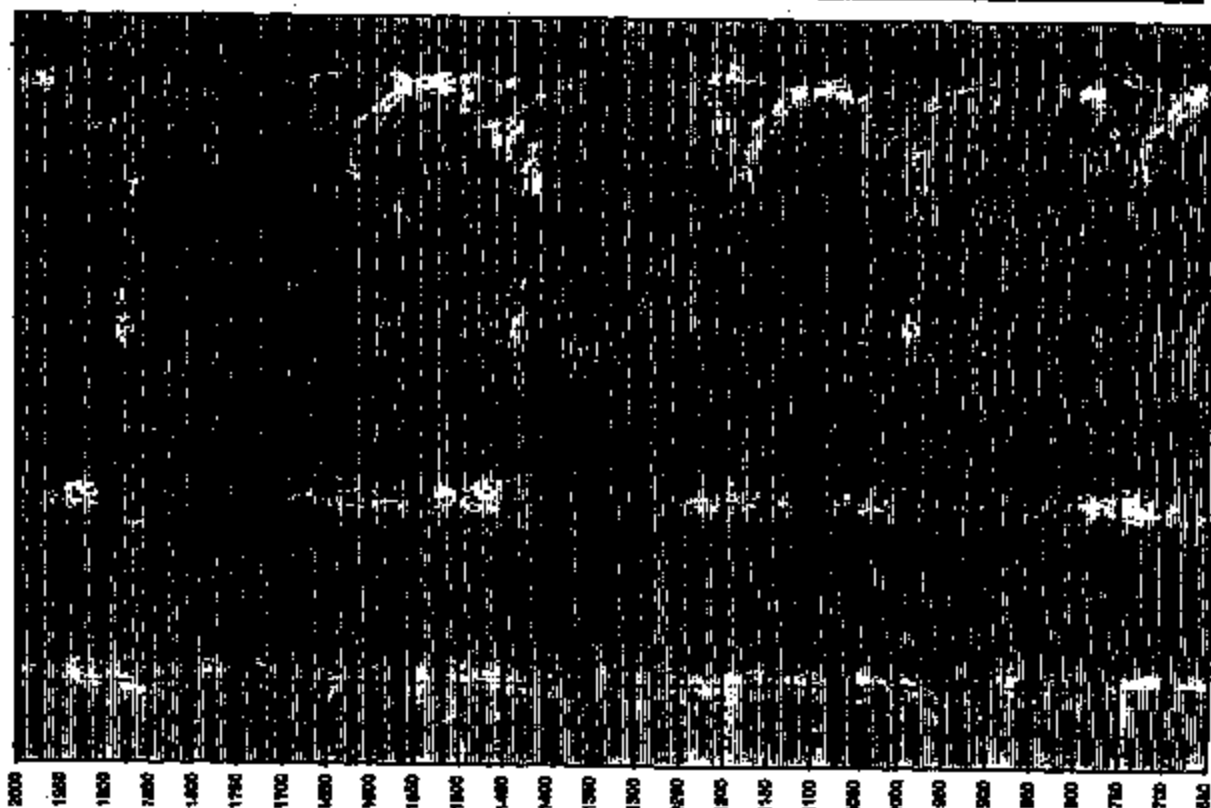
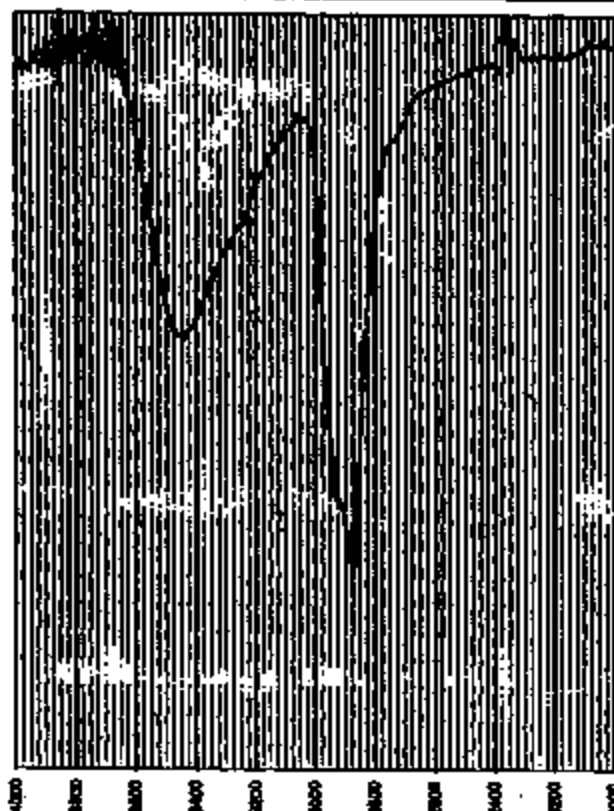
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *MCH*

Circle:

1200 (p.o.) & 560 (p.o.)



9900226 "F" SEAL 2, FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Mon Feb 08 13:47:00 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

Y Axis: % Transmittance

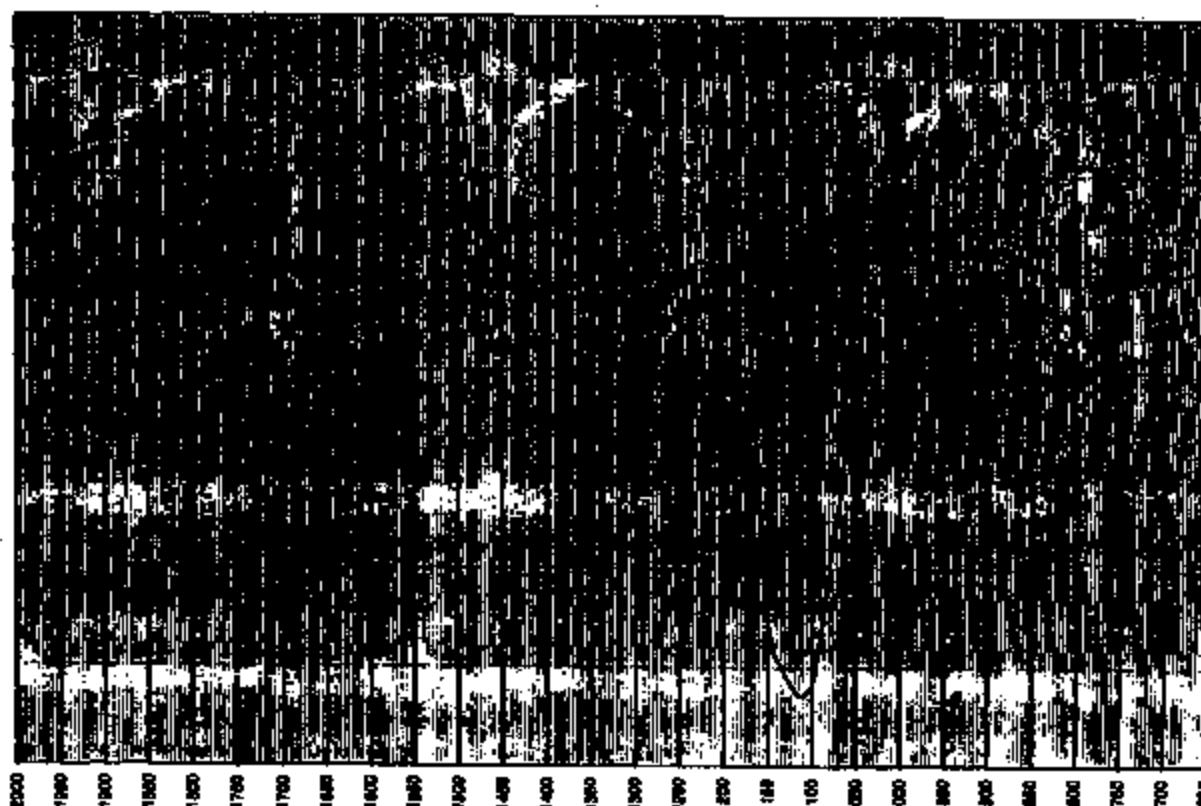
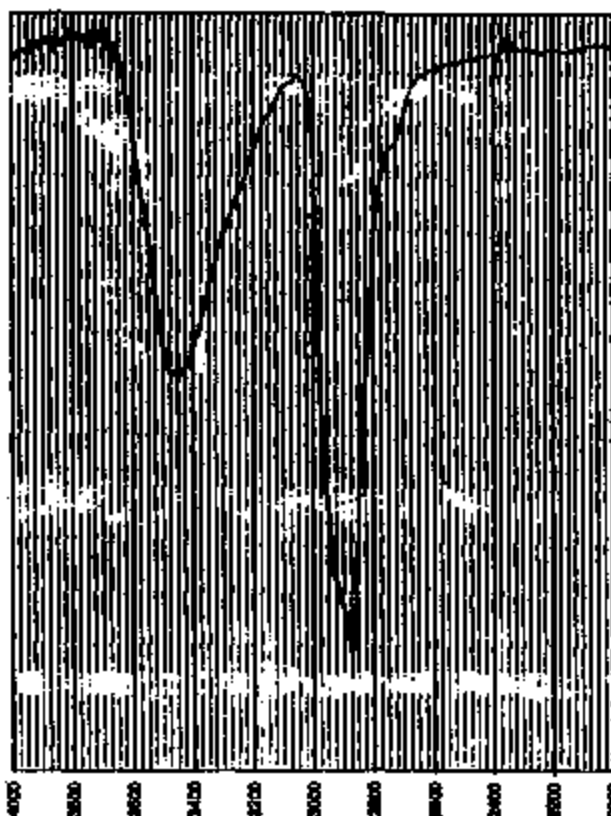
X Axis: Wavenumber

Engineer: *M/r*

Owner:

Interpretation:

see gbm (p 5F)



9713 2802

9900226 "F" SEAL 3, RESIDUE

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

John Walker

Mon Feb 08 13:51:50 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

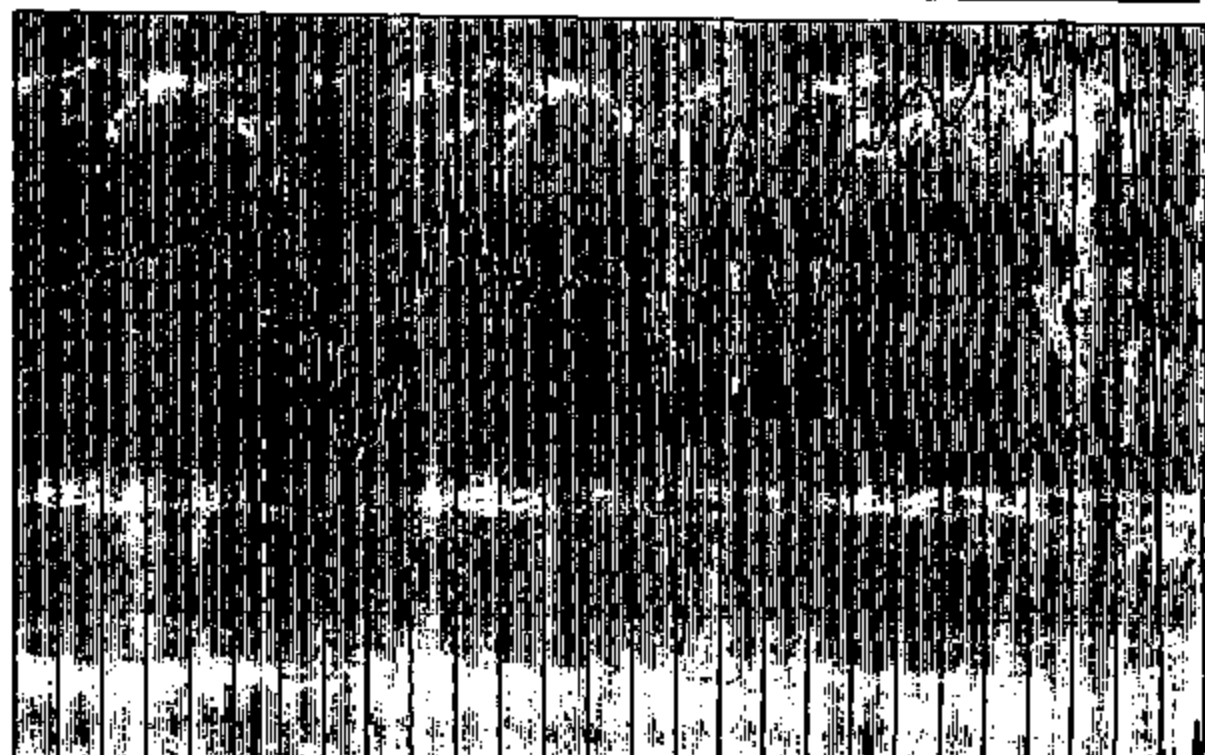
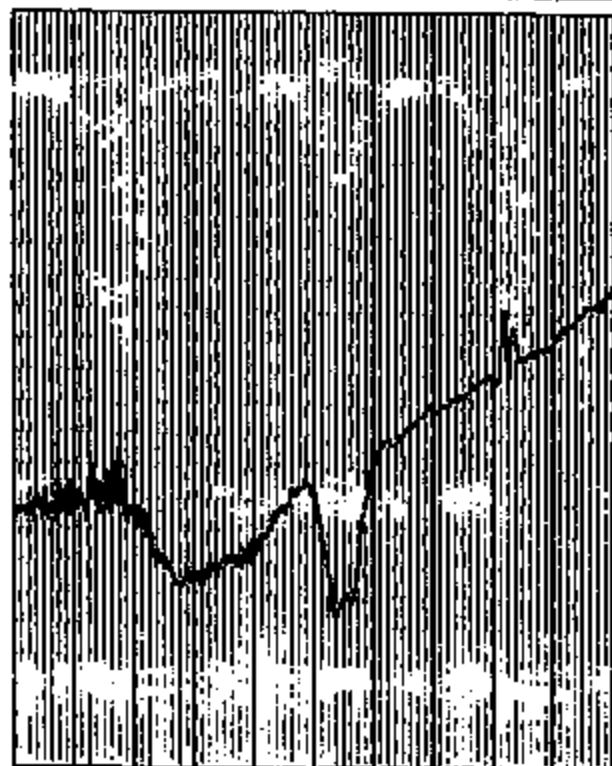
Gain: 2R / 2R

Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Comment:



3713 2808

9900226 "F" WASHER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 09:39:52 1989

Engineer: MCH

Scan: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

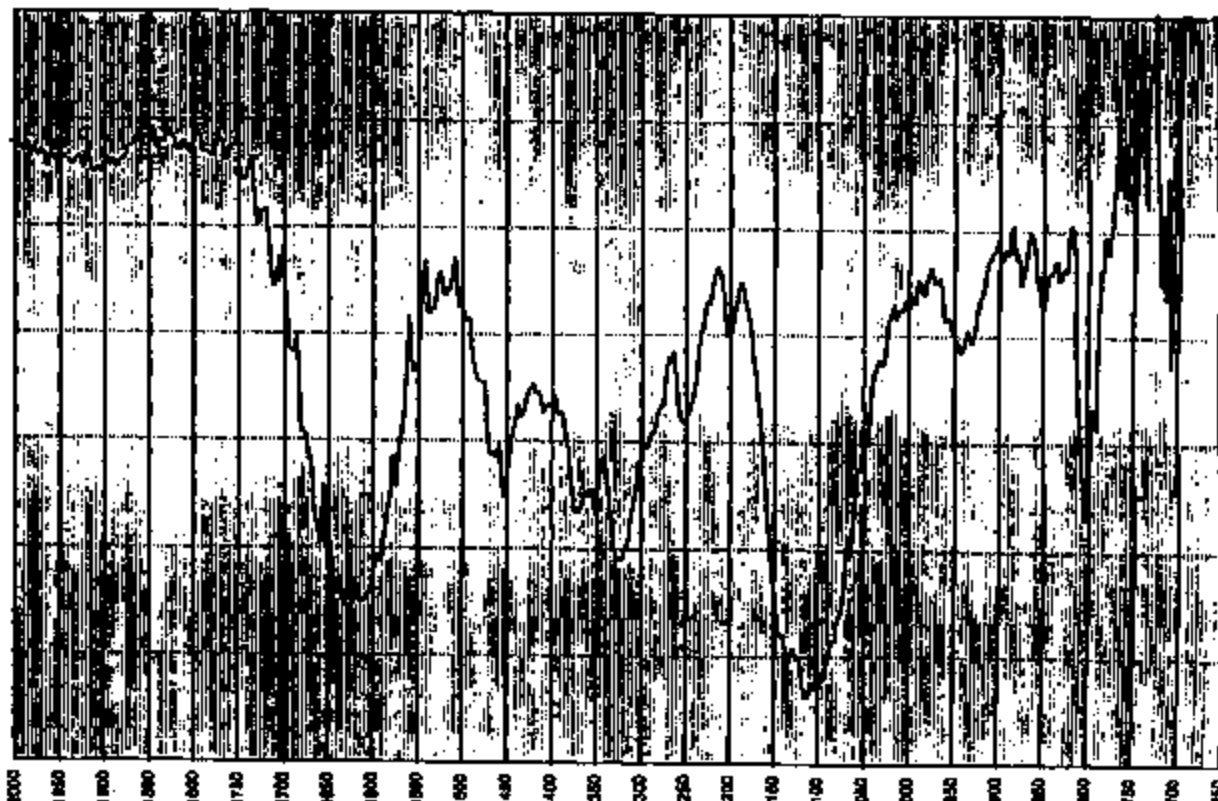
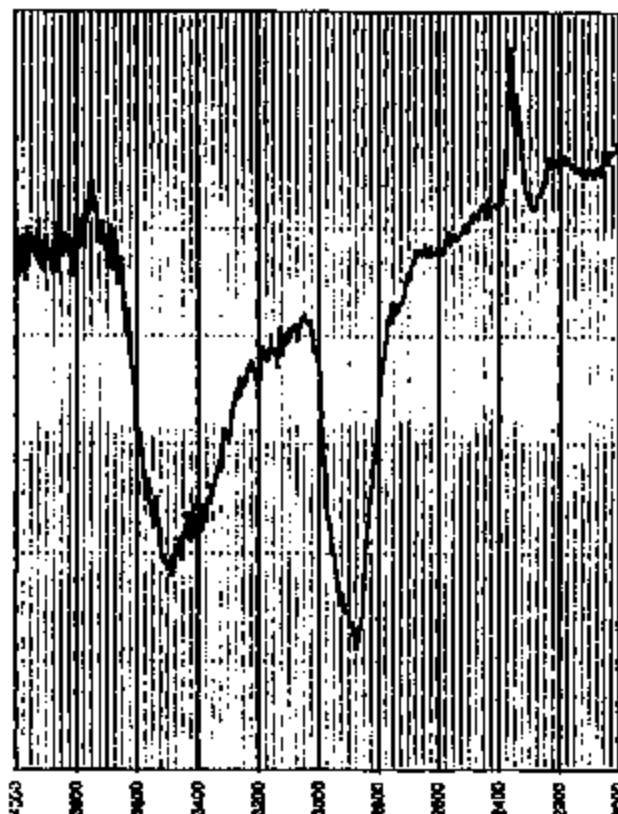
X Axis: Wavenumber

Engineer:

MCH

Comment:

3600 (pk) + 1700 (pk)



9900226 "F" CONVERTER

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Wed Feb 10 09:43:16 1999

Engineer: MCH

Scan: 126 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

X Axis: Wavenumber

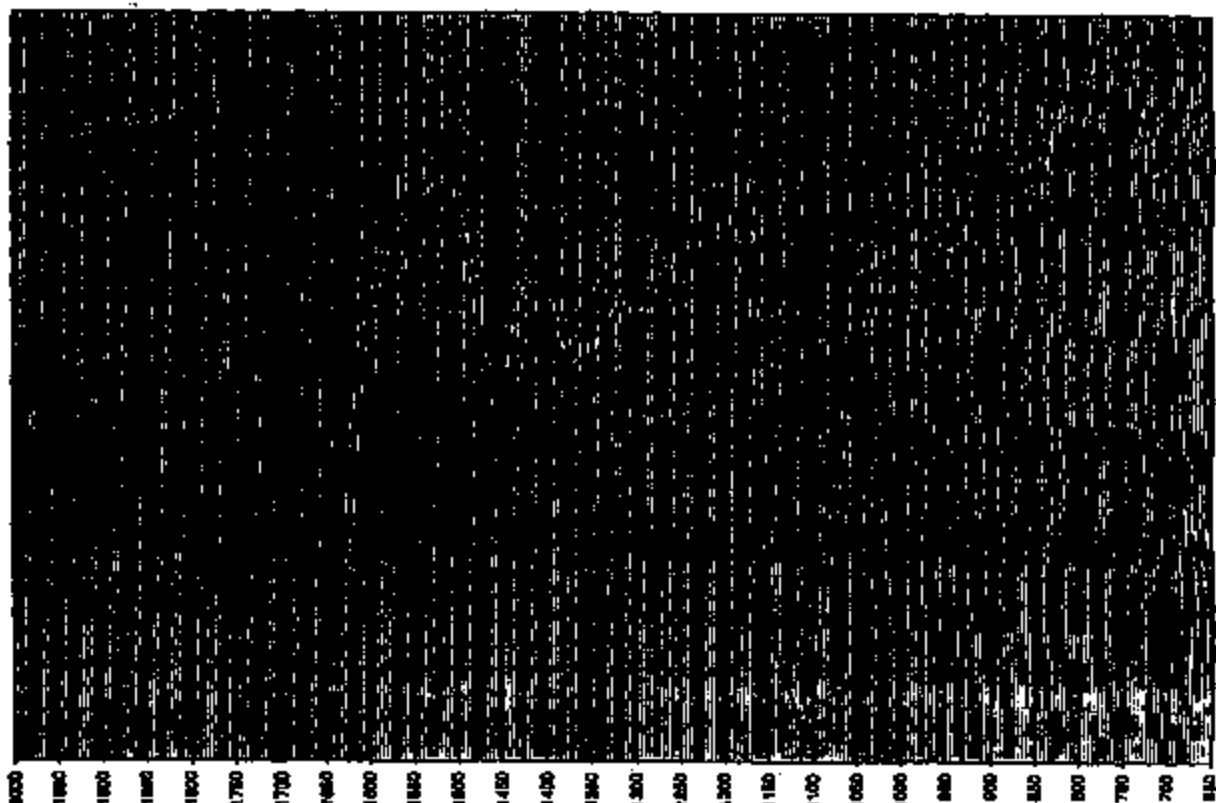
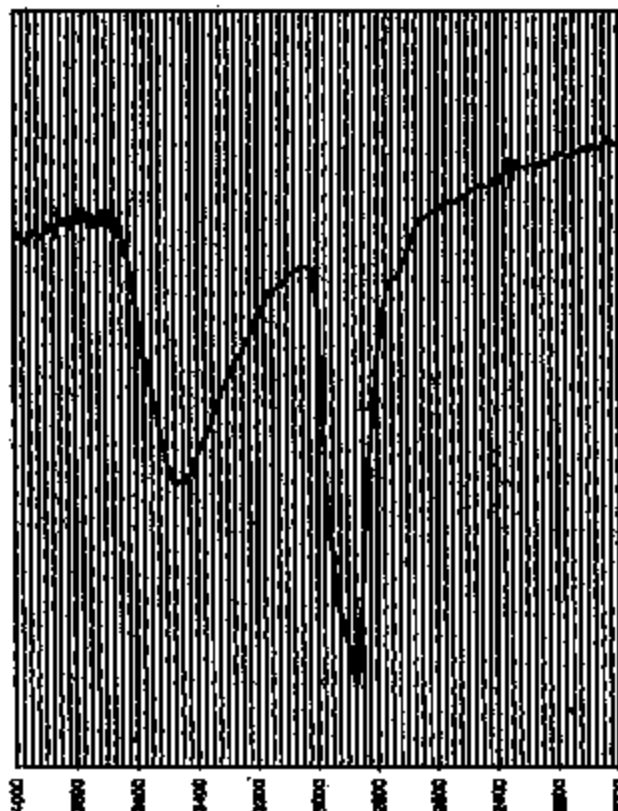
Engineer:

mk

Owner:

Interpretation:

ghm(BF) ✓ ms(p.o)



3713 2606

9900226 "F" SPACER

Specification:
Supplier:
Preparation method: AS RECEIVED
IR Technique: MICROSCOPE

Wed Feb 10 09:54:52 1998

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Baer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

X Axis: Wavenumber

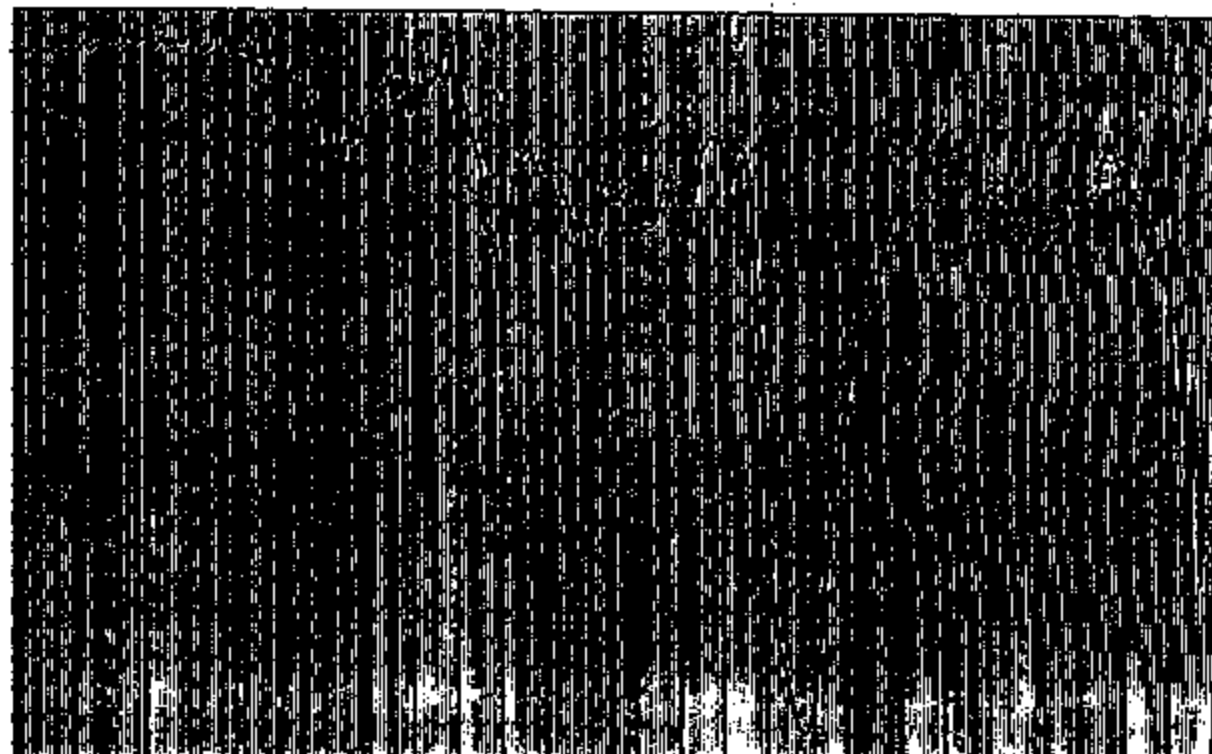
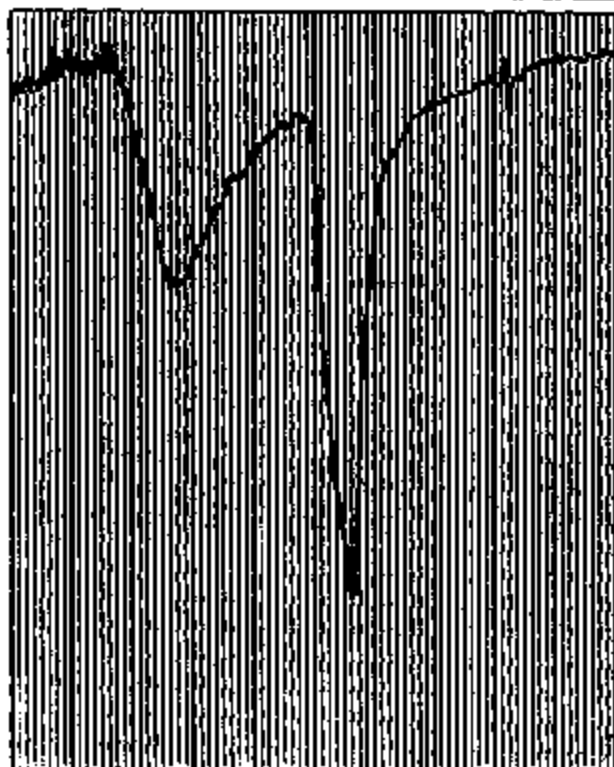
Engineer:

cm

Center:

Interpretation:

ess 86m (18C)



9713 2806

9900226 "F" DISC

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Wed Feb 10 09:58:19 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Saier (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

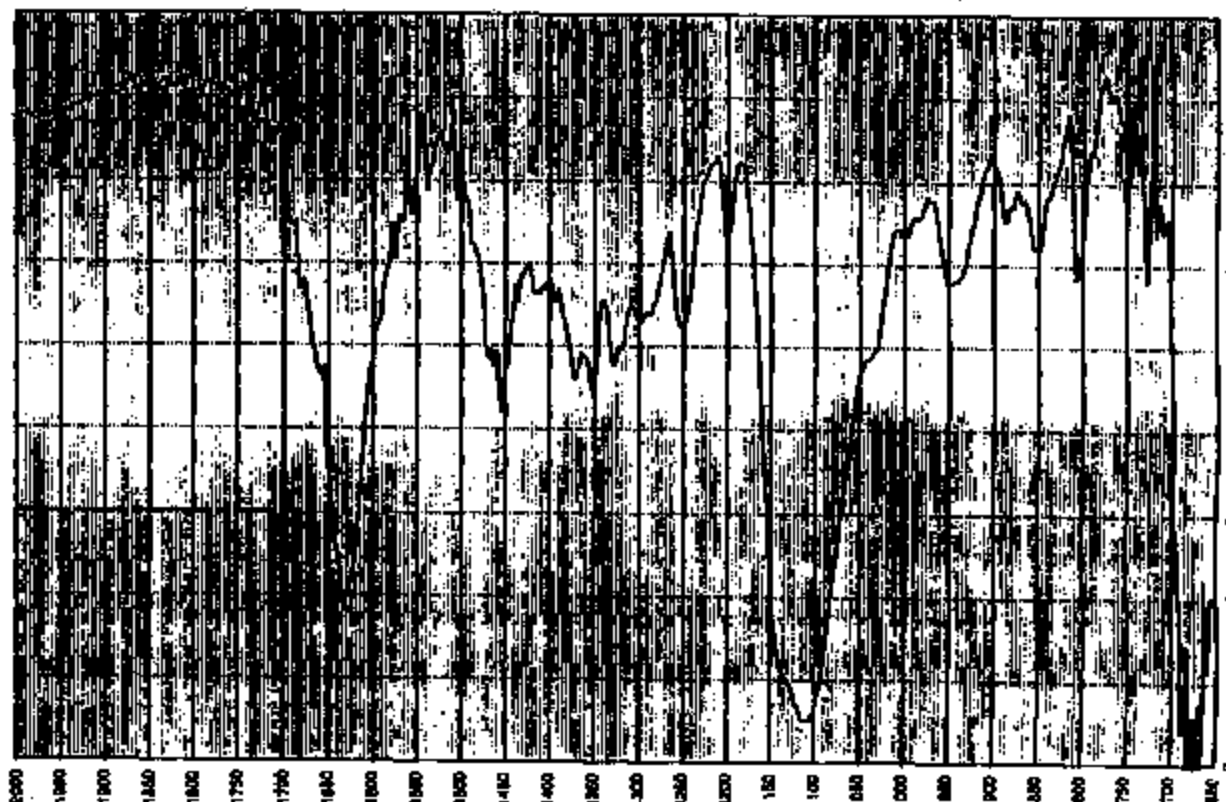
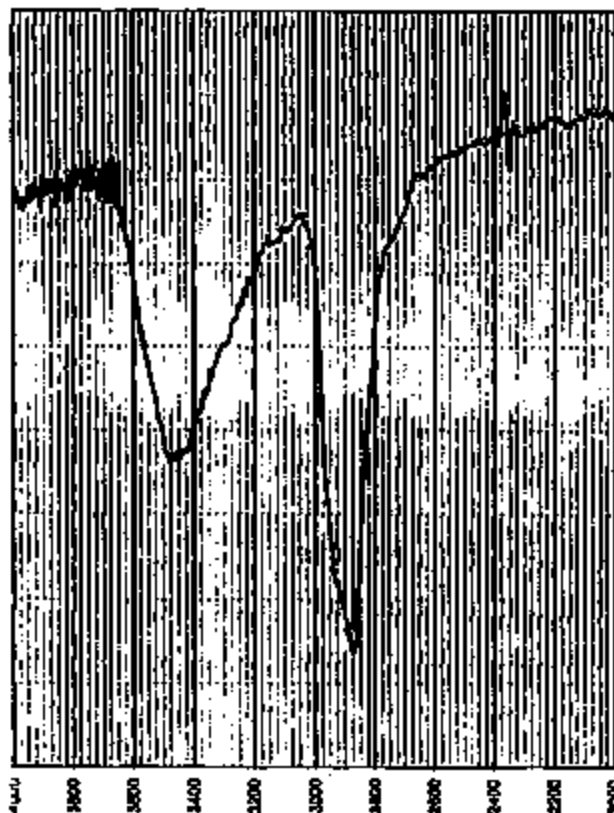
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer: *mjb*

Interpretation:

m.s(pu) - 8bm (r^{Bo})



3713 2807

9900226 "F" CUP, INTERIOR

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Wed Feb 10 09:38:45 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

X Axis: Wavenumber

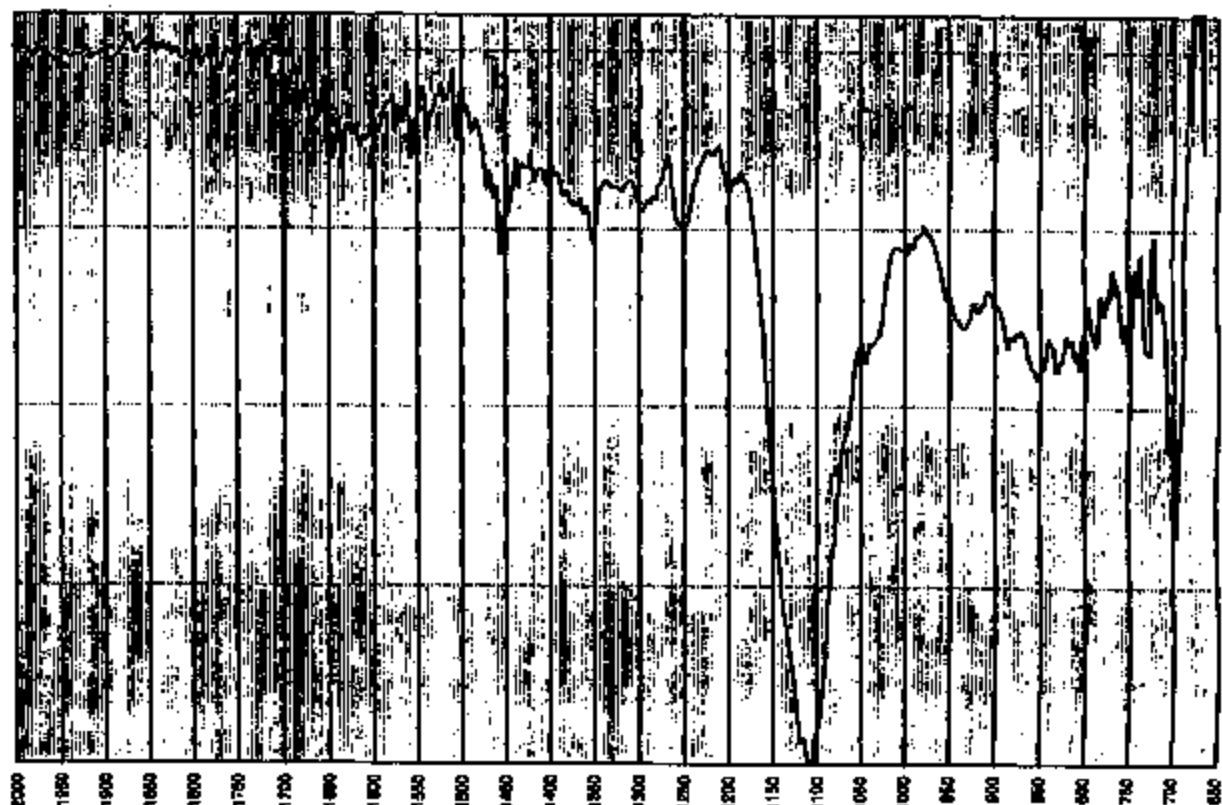
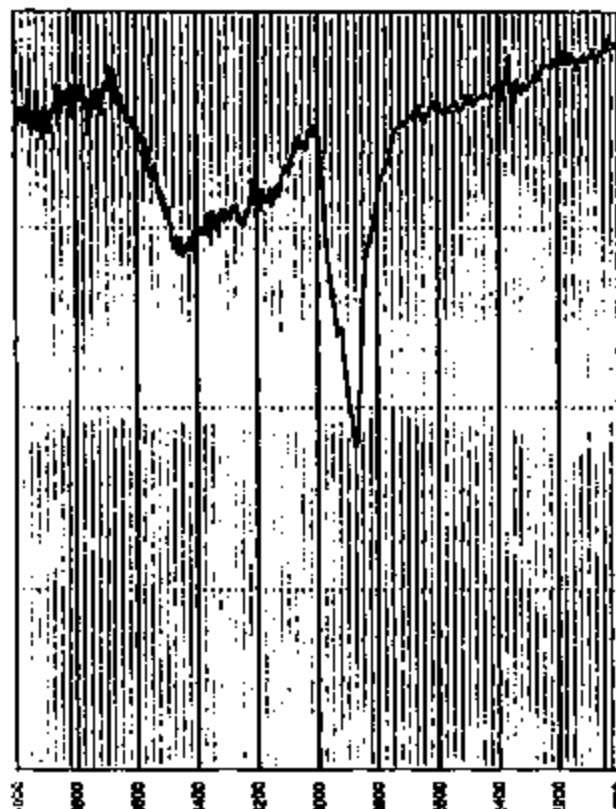
Engineer:

MCH

Comment:

Interpretation:

ess sbm(pkf)



3713 2808

9900226 "F" CUP, SWITCH SIDE, BLACK

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 09:20:29 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

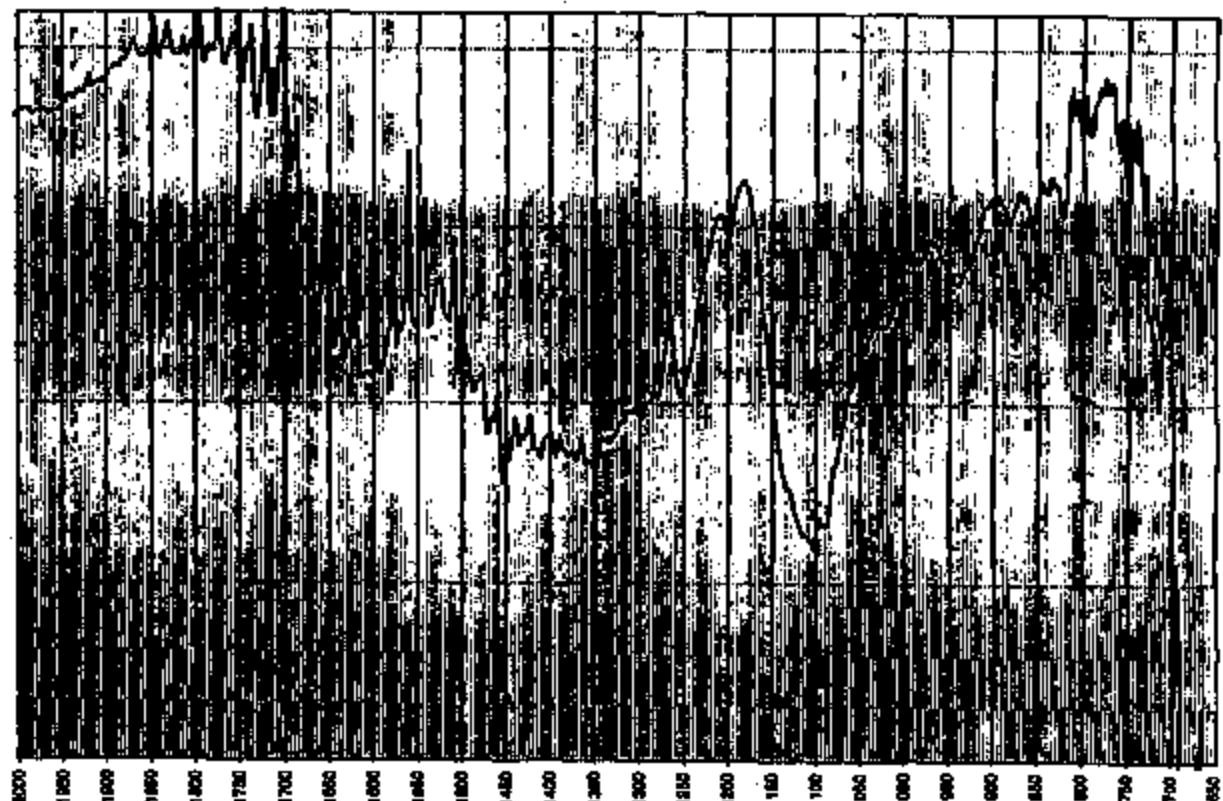
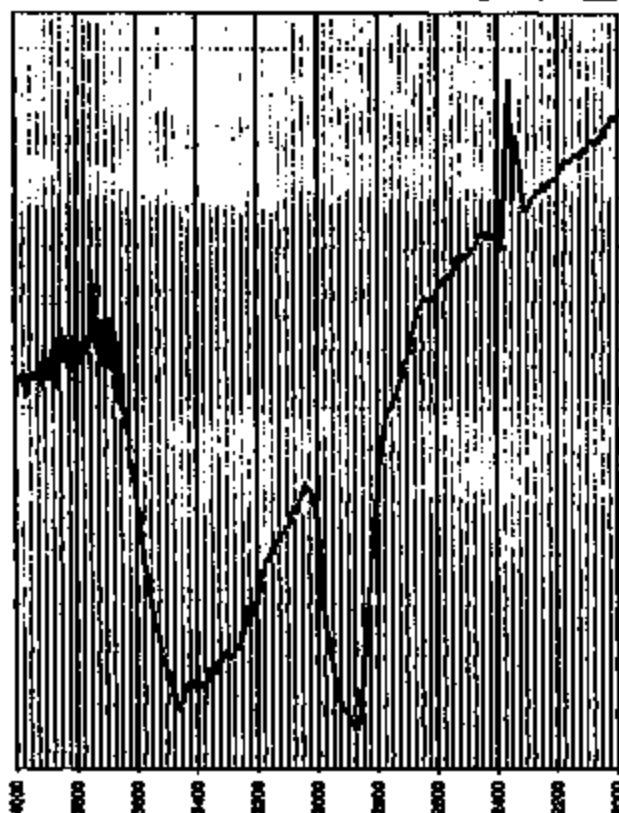
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Comment:

given - other



3713 2809

9900226 "F" CONTACT

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 10:03:24 1999

Engineer: MCH

Scan: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

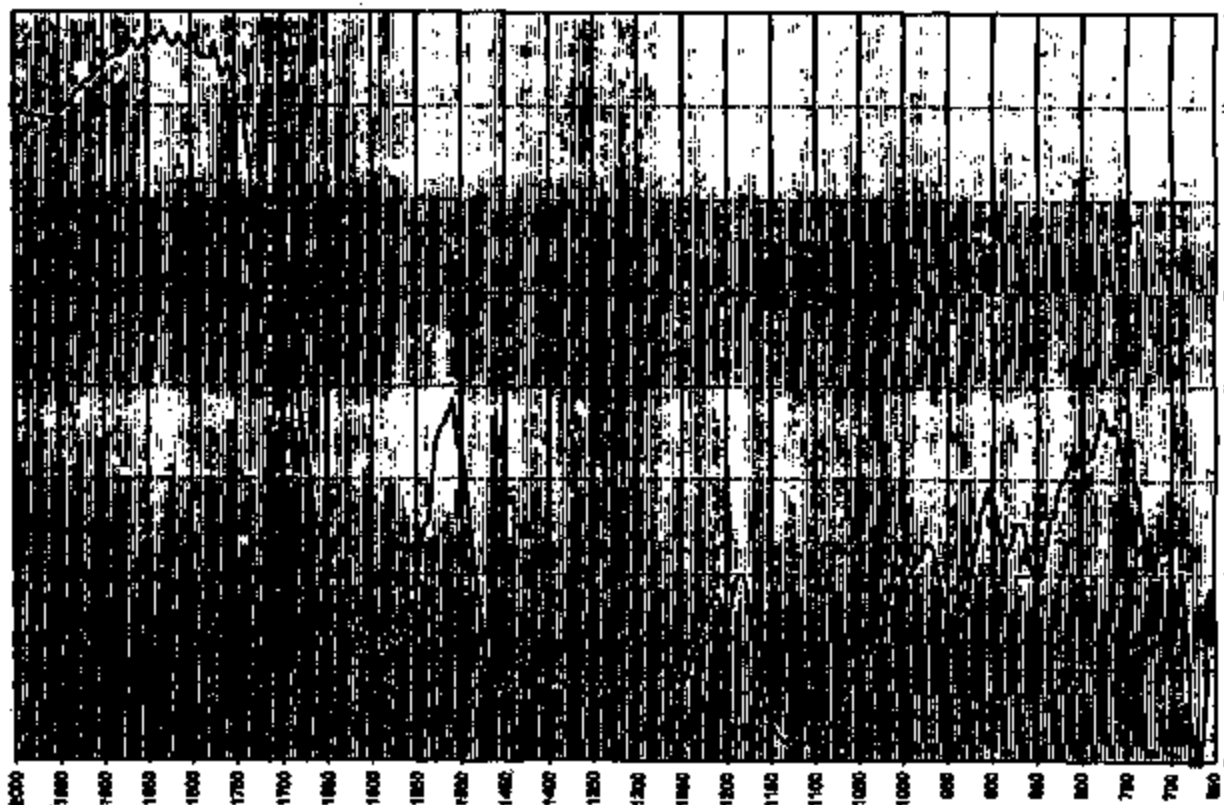
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Cancel:

3600 (possible) 1600 possible, metal self



3713 2610

9900226 "F" BASE, CONNECTER CAVITY

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Wed Feb 10 10:06:19 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Beer (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 4 / 4

Y Axis: % Transmittance

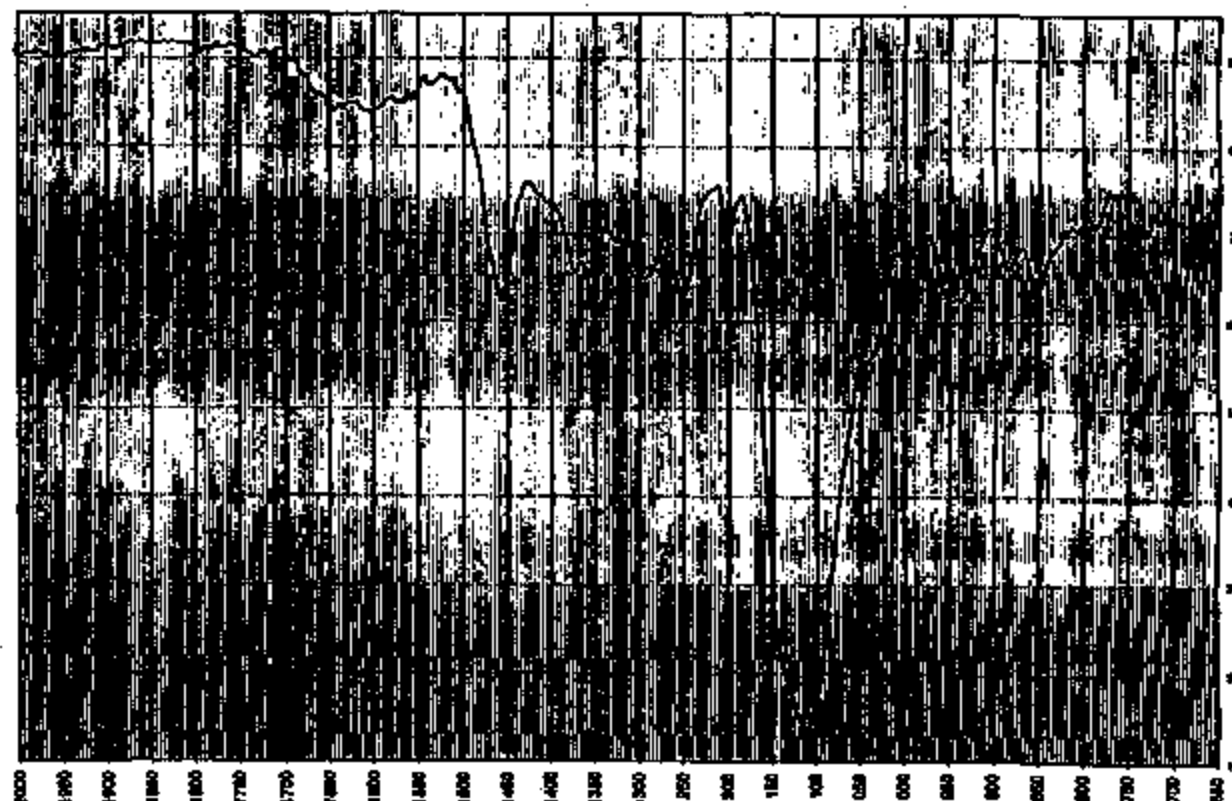
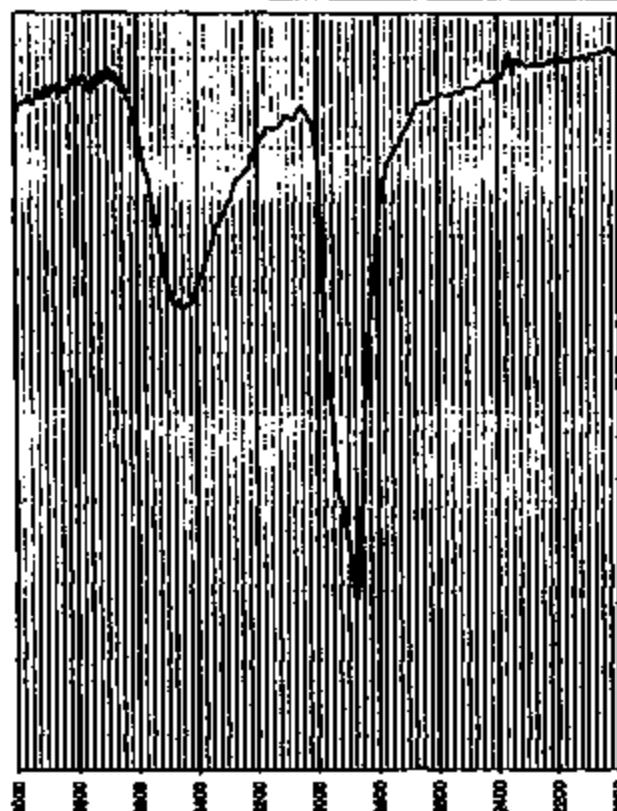
X Axis: Wavenumber

Engineer:

M

Comment:

CS₂ 50um (pBF)



3713 2811

9300220 11 REPORT, FITTING END

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Fri Feb 05 15:11:26 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Bear (medium)

Detector: MCT[15]

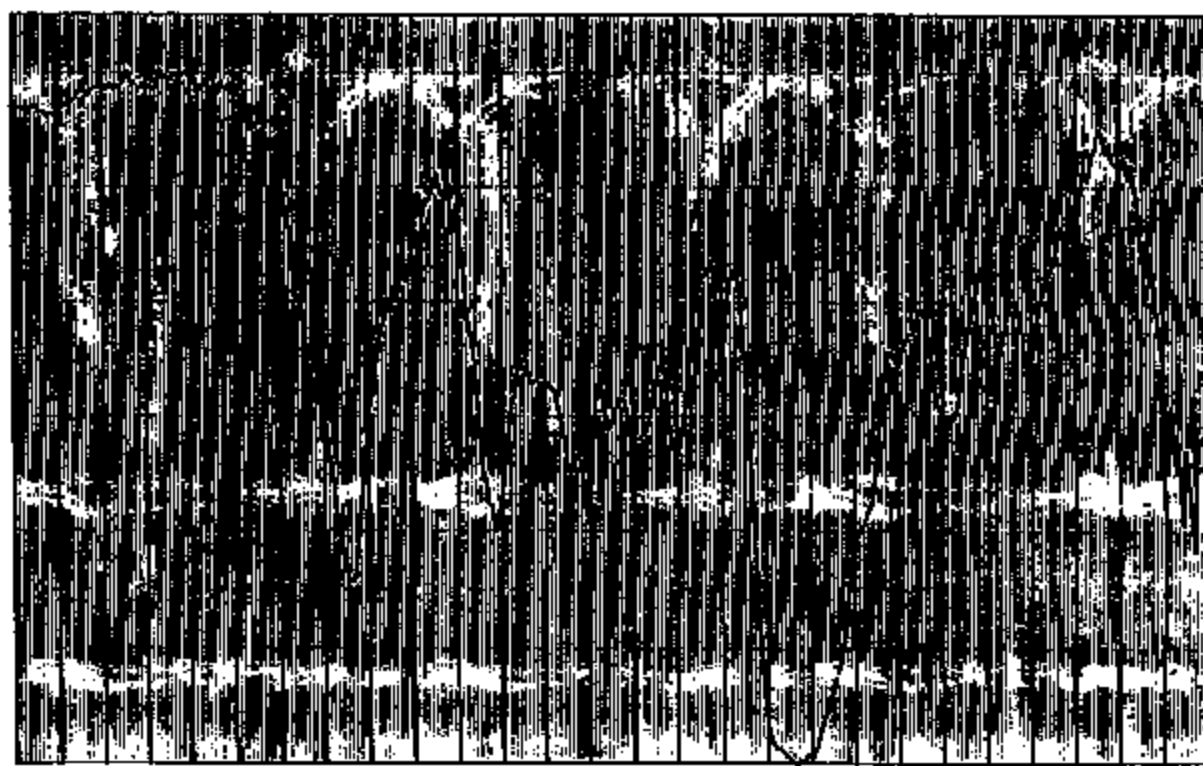
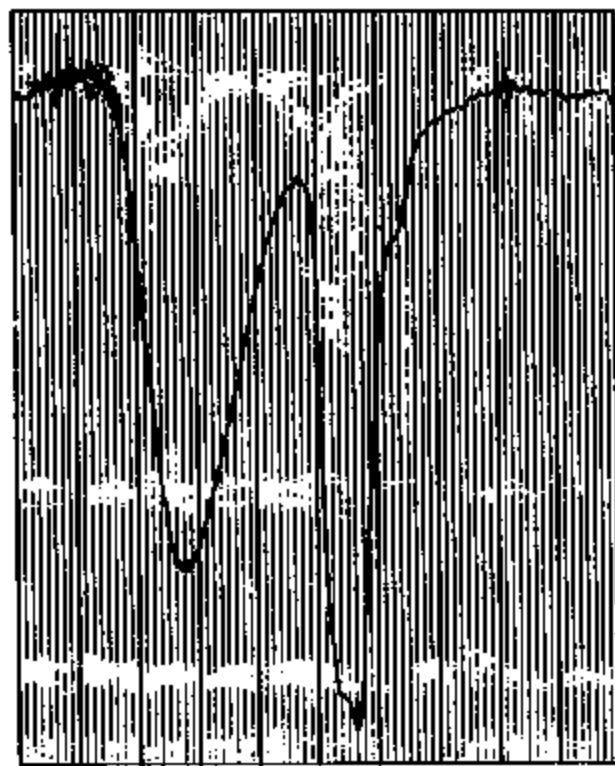
Y Axis: % Transmittance

X Axis: Wavenumber

Engineer:

Comment:

m.s (no) & gbm (pht)



3713 2812

9900226 11 HEXPORT, CAVITY

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Fri Feb 05 15:06:54 1999

Scans: 128 / 256

Resolution: 4.00

Gain: 4 / 4

Engineer: MCH

APOD: Norton-Bear (medium)

Detector: MCT[15]

Y Axis: % Transmittance

X Axis: Wavenumber

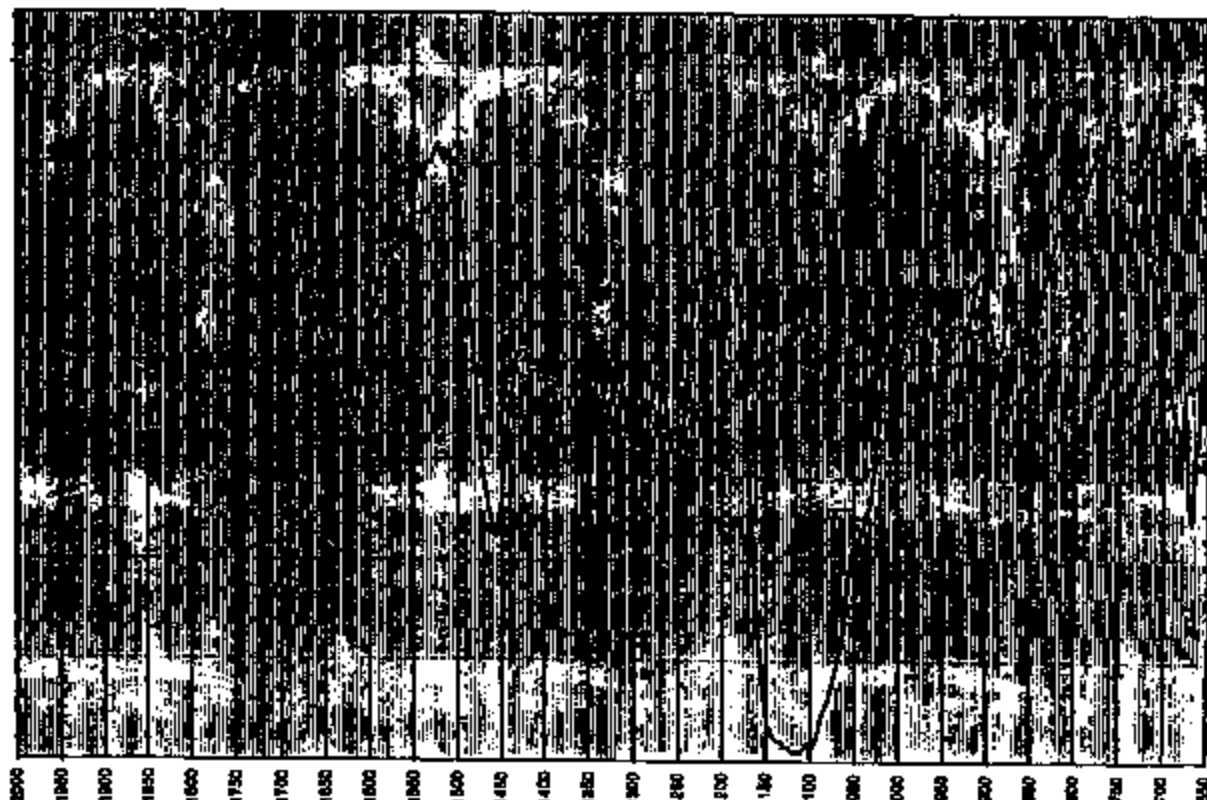
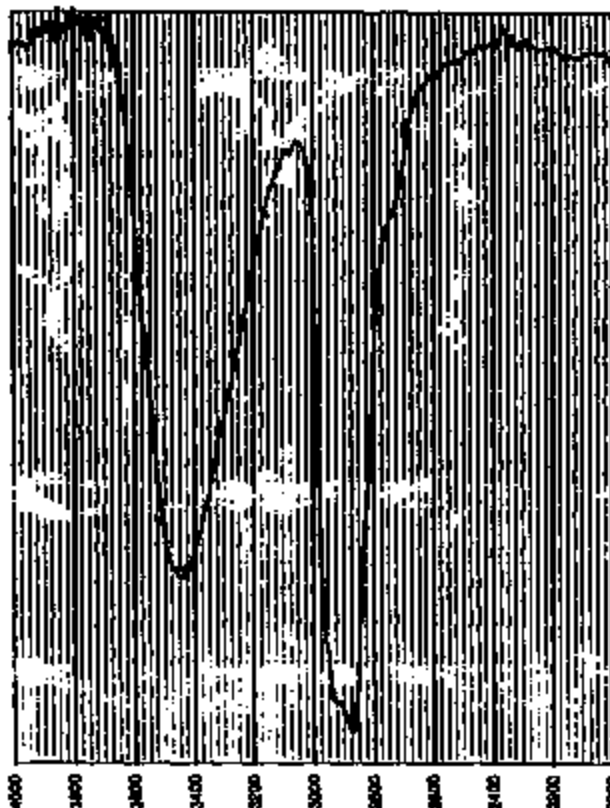
Engineer:

MCH

Comment:

Interpretation:

glac (vibr) + m-2 (v-2)



9900226 11 SEAL 1, FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 10:12:17 1999

Engineer: MCH

Scans: 128 / 256

APOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[15]

Gain: 2R / 2R

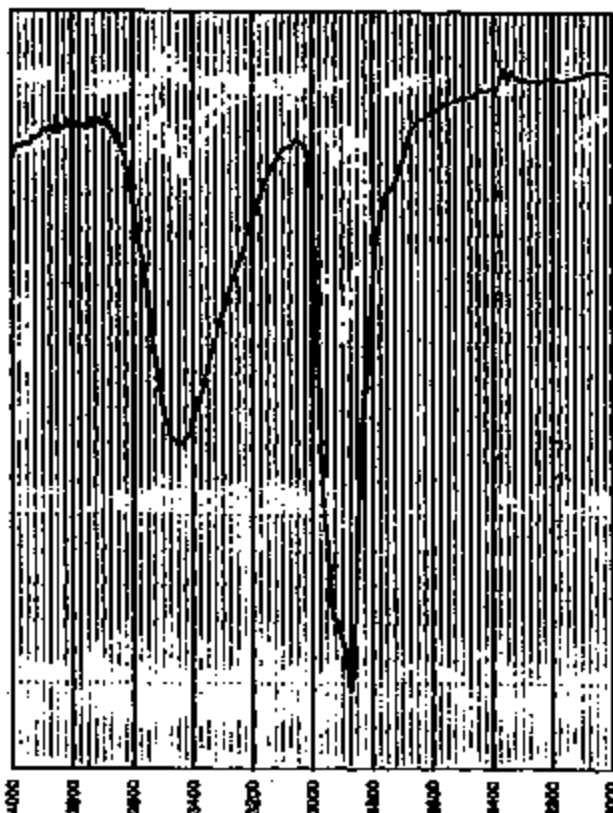
Y Axis: % Transmittance

X Axis: Wavenumber (cm⁻¹)

Original:

Center:

1115 gbm (AB)



3713 2814

9900226 11 SEAL 2, FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 06 13:23:05 1999

Engineer: MCH

Scan: 128 / 256

APOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[15]

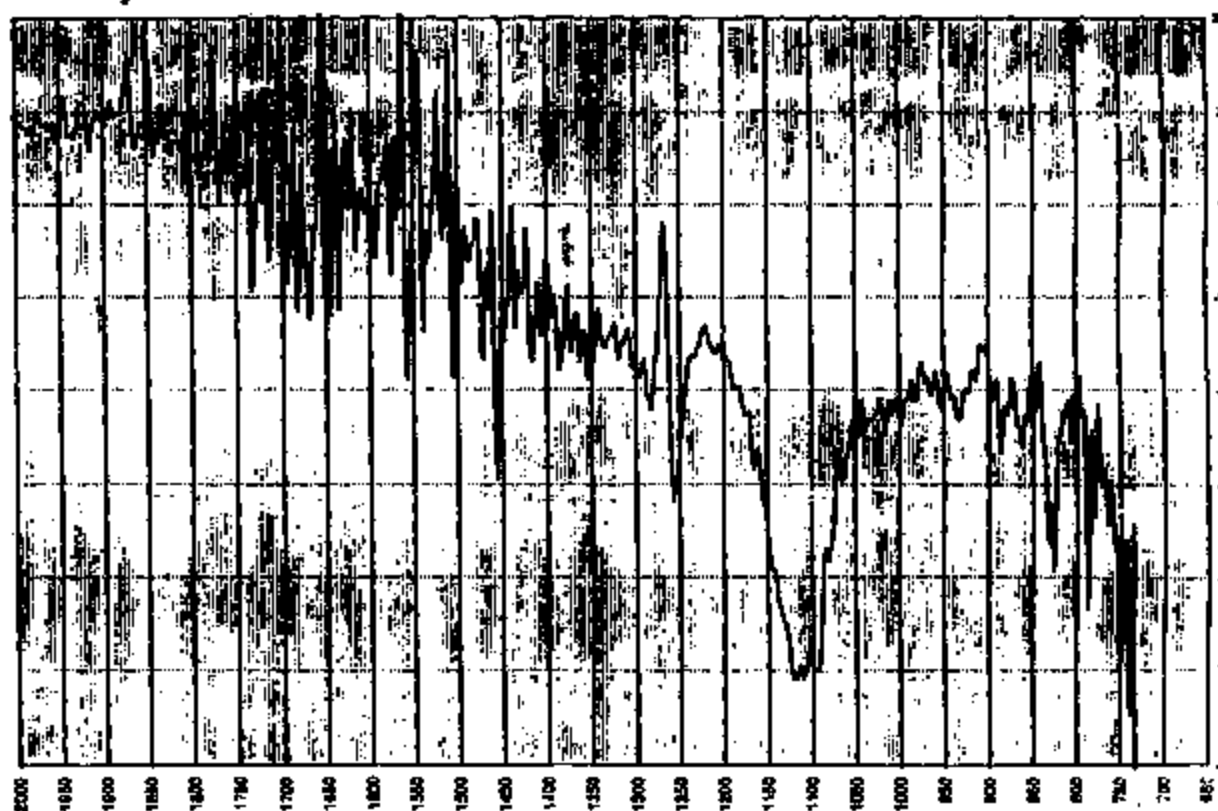
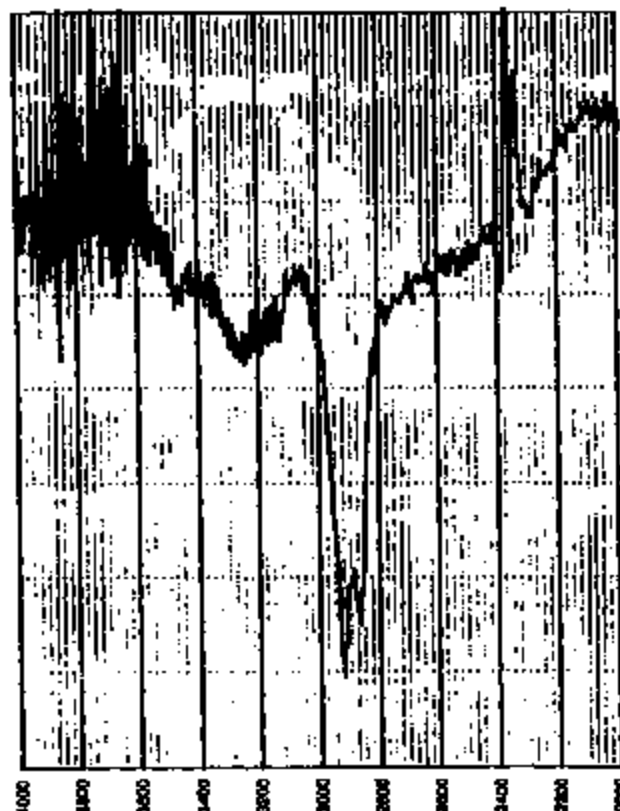
Gain: 2R / 2R

Y Axis: % Transmittance X Axis: Wavenumber

Engineer:

Comment:

gum + silicone



9718 2815

9900226 11 SEAL 3, FLUID

Specification:

Supplier:

Preparation method: AS RECEIVED

IR Technique: MICROSCOPE

Interpretation:

Mon Feb 08 13:26:49 1999

Engineer: MCH

Scene: 128 / 256

APOD: Norton-Bear (medium)

Resolution: 4.00

Detector: MCT[15]

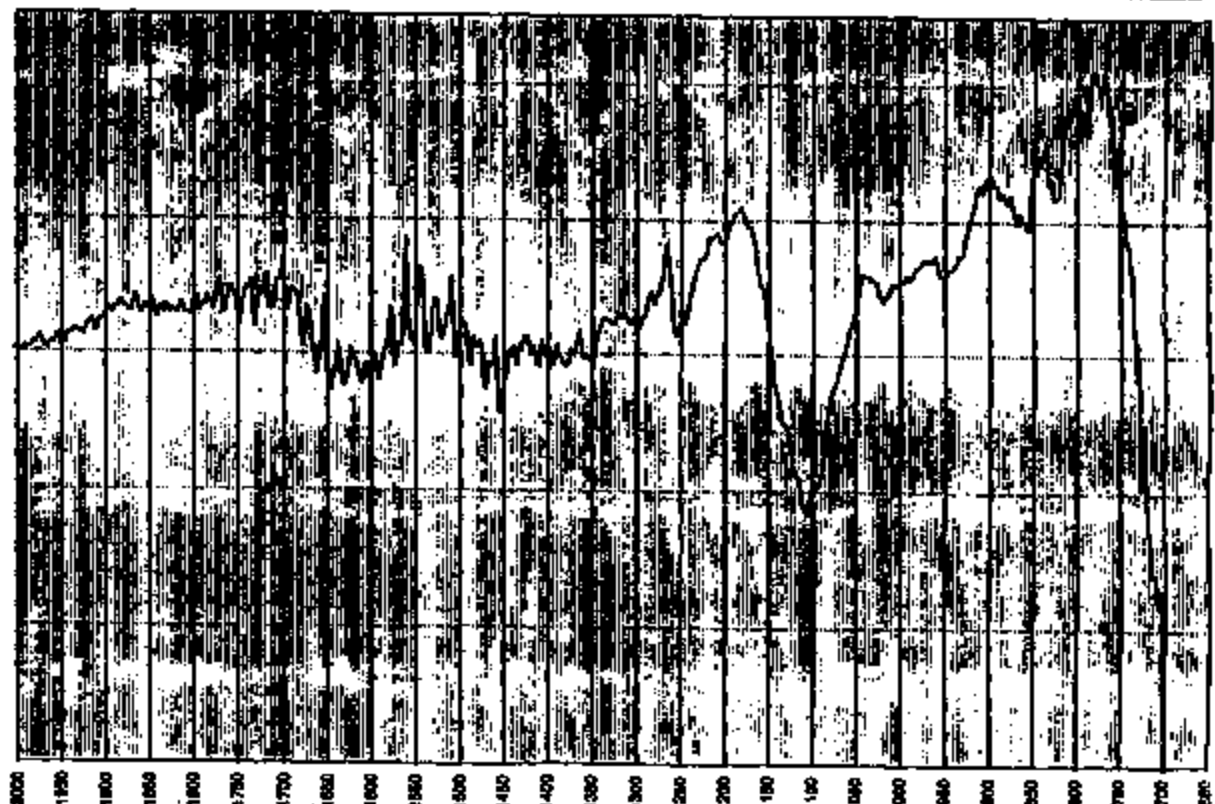
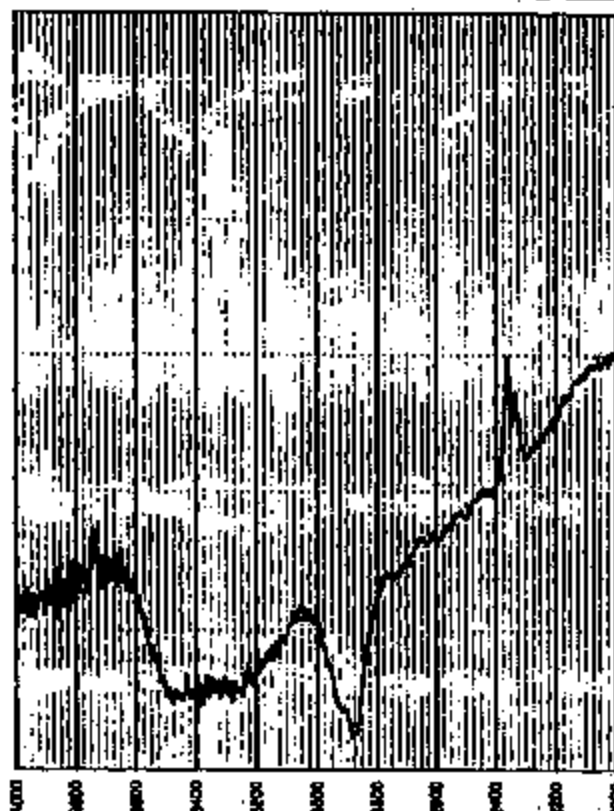
Gain: 2R / 2R

Y Axis: % Transmittance X Axis: Wavenumber

Engineer:

Comment:

ghm + mostly silicone



3713 2916

Project No. 9900226

Book No. 2765

TITLE SPEED CONTROL CUT OFF SWITCH

From Page No. _____

BY G. STEVENS

LEAD COORDINATOR: S.

~~ST. MICHAEL~~ LAROCHE

RECEIVED: 3 SAMPLES (3 PIECES EACH) OF KAPTON STRIPS (D.E. REF # 11 - PRESSURE MODE) WERE RECEIVED ON 1/26/99.

REQUESTED: DETERMINE EXTENT/CAUSE OF DAMAGE OF THE KAPTON STRIPS.

CONCLUSION: DAMAGE IS CONSISTENT W/ CLS # 98 & 105.

SEE REPORT FOR DETAILS

To Page No. _____

Witnessed & Understood by me,

Date

Invented by

Date

Robert J. Bell 4/1/99

From Page No. _____

ADDITIONAL SAMPLESSAMPLE C HEX PORT - PARTIALLY BURNED &
CHARRED KAPTON LAYERS

#5 KAPTON LAYERS 1-3

#6 KAPTON LAYERS 1-3

SHEAR FRACTURE~~IN THE~~ IN THE TOP TEFLON LAYERS OF #5-1
& #6-1 WERE FOUNDSAMPLE C TEFLON LAYERS WERE MELTED
NO INFORMATION WAS OBTAINED FROM EXAMINATION
OF THE KAPTON LAYERS.

To Page No. _____

Witnessed & Understood by me,

Date

Invented by

Date

Recorded by

Kodum S. Bellman

9/7/99



Central Laboratory
16000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1614

Report 9900226

February 10, 1999

To: G. Stevens (313) 32-36886 39-07224 FAX

From: V. Beltran (313) 39-06018

Subject: Speed Control Cut Off Switch
Part Number: F2VY-9F324-A
Specification: Not Provided
Supplier: Texas Instruments

Received: 3 samples (3 specimens each) of Kapton Strips identified as D, F, and 11 (pre-failure mode) were received on January 26, 1999.

Object: Determine the extent/cause of the damage of the Kapton strips.

Conclusion: The damage visible on the strips is consistent with the damage seen in CLS#980105. Fractured strip material and torn Teflon layers provide a potential leak path. Cracking is present in the strips of the pre-failure mode samples.

Data and Analysis:

Reflected Light Microscopy

Tears were found on the Teflon layers of each strip (Figure 1) of the failed samples. The Teflon was peeled away to reveal the presence of brittle fractures (Figure 2. See also Reference CLS#9804105). When stacked in the proper orientation, the deformed areas of the fractures of each strip fit together. The alignment of fractures in the strips provides a possible leak path.



Figure 1.
Typical Example of Torn Teflon Layer

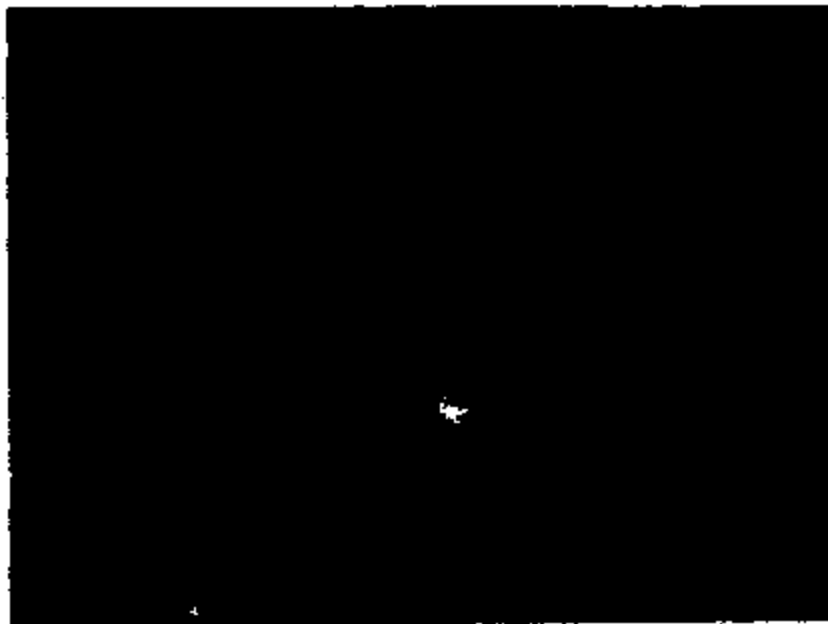


Figure 2.
Typical Example of Damaged Kapton Material.

Reflected Light Microscopy continued

Microscopic examination of the pre-failure mode sample (#11) reveals the presence of fractures in the early stage of development (Figure 3). It has not been determined if these cracks completely penetrate the Kapton material. No signs of tearing in the Teflon layer surrounding these cracks could be found. This may indicate that the Kapton material in this sample may have been brittle at the time of deformation and fractured. The deformation may not have been sufficient to tear the Teflon layer.



Figure 3.
Possible Early Stage of Fracture Formation in Pre-Failure Mode
Sample

By:

Vladimir S. Beltran (VBELTRA1)
Laboratory Engineer



Central Laboratory
15000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1814

Report 9900226

February 3, 1999

To: G. Stevens (313) 32-36666 (313) 39-07224 FAX

From: P. J. Nallos (313) 33-75366

Subject: Speed Control Cutoff Switch
Part Number: F2VY-9F824-A
Specification: Not Provided
Supplier: Texas Instruments

Received: Ten pieces of filter paper, containing particles scraped from component parts, were received on January 28, 1999. They were identified as A, B, and C (Cup and Port samples), and D and F (Cup and Contact samples).

Object: Perform EDS analysis on each sample.

Conclusion: There was transfer of copper-zinc material from the contact to the cup region on each part.

Data and Analysis:

Surface Analysis

(Scanning Electron Microscopy (SEM), and Energy Dispersive X-ray Spectroscopy (EDS))

Particles from each piece of filter paper were placed on a carbon stud for examination in a scanning electron microscope (SEM) using Energy Dispersive X-ray Spectroscopy (EDS). The D and F samples were wet, so a portion of each was rinsed in freon and re-filtered before particles were placed on a carbon stud. Four particles/groups of particles from each sample were examined. Although there was some variation in the analyzed samples, typical EDS spectra are given in Figures 1 - 10. The following elements were detected in these spectra, in decreasing order of elemental concentration.

A Cup	B Cup	C Cup	D Cup	F Cup
Zinc	Copper	Zinc	Zinc	Copper
Copper	Zinc	Iron	Copper	Zinc
Aluminum	Phosphorus	Copper	Potassium	Potassium
Iron	Iron	Chromium	Iron	Sulfur
Silicon	Silicon	Silicon	Silicon	Iron
Calcium	Sulfur	Calcium	Sulfur	
Sulfur	Potassium	Sulfur		
Potassium	Calcium			
A Port	B Port	C Port	D Contact	F Contact
Iron	Silicon	Iron	Copper	Copper
Copper	Calcium	Copper	Silver	Zinc
Aluminum	Phosphorus	Zinc	Zinc	Silver
Potassium	Aluminum	Sulfur	Iron	Potassium
	Copper	Aluminum	Silicon	Iron
	Zinc	Silicon		Sulfur
	Iron			
	Titanium			
	Chlorine			

Surface Analysis (continued)



There are several particles in the A, B, and C cup samples that are iron-rich. These are from the steel base material. A typical EDS spectrum is shown in Figure 11 for these particles.

The number of copper-zinc particles in the cup indicate material transfer from the contact to the cup. The B port sample was composed primarily of fibers.

By: _____

Patrick J. Nalica (PNAJLOS)
Laboratory Specialist

Enclosures: Figures 1 - 11
PJN/pjn



Central Laboratory
15000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1614

Report 9900226

February 10, 1999

To: G. Stevens (313) 32-36866 39-07224 FAX

From: V. Beltran (313) 39-06018

Subject: Speed Control Cut Off Switch
Part Number: F2VY-9F824-A
Specification: Not Provided
Supplier: Texas Instruments

Received: 3 samples (3 specimens each) of Kapton Strips identified as D, F, and 11 (pre-failure mode) were received on January 26, 1999.

Object: Determine the extent/cause of the damage of the Kapton strips.

Conclusion: The damage visible on the strips is consistent with the damage seen in CLS#980106. Fractured strip material and torn Teflon layers provide a potential leak path. Cracking is present in the strips of the pre-failure mode samples.

Data and Analysis:

Reflected Light Microscopy

Tears were found on the Teflon layers of each strip (Figure 1) of the failed samples. The Teflon was peeled away to reveal the presence of brittle fractures (Figure 2. See also Reference CLS#9804105). When stacked in the proper orientation, the deformed areas of the fractures of each strip fit together. The alignment of fractures in the strips provides a possible leak path.



Figure 1.
Typical Example of Torn Teflon Layer

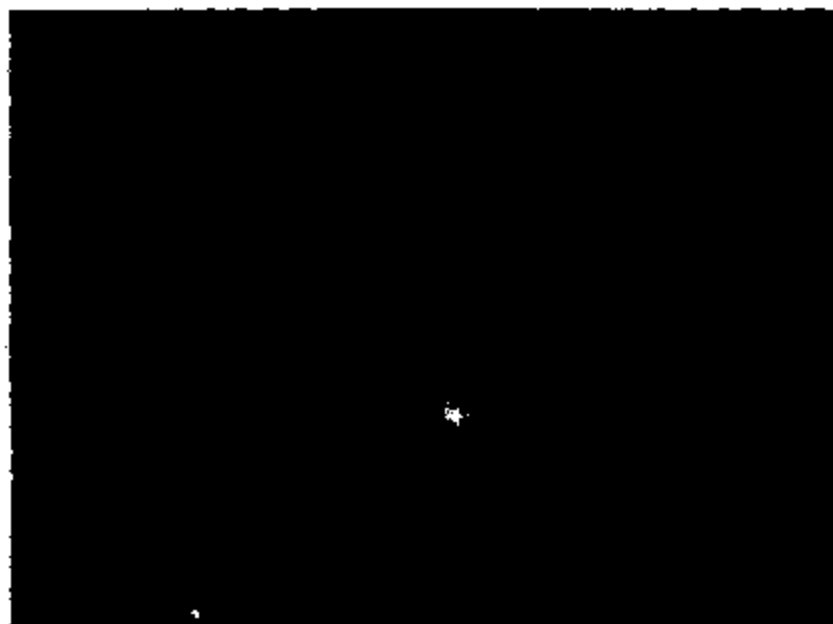


Figure 2.
Typical Example of Damaged Kapton Material

**Reflected Light Microscopy** continued

Microscopic examination of the pre-failure mode sample (#11) reveals the presence of fractures in the early stage of development (Figure 3). It has not been determined if these cracks completely penetrate the Kapton material. No signs of tearing in the Teflon layer surrounding these cracks could be found. This may indicate that the Kapton material in this sample may have been brittle at the time of deformation and fractured. The deformation may not have been sufficient to tear the Teflon layer.



Figure 3.
Possible Early Stage of Fracture Formation in Pre-Failure Mode Sample

By:

Vladimir S. Beltran (VBELTRA1)
Laboratory Engineer



Central Laboratory
15000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1614

Report 9900228

February 3, 1999

To: G. Stevens (313) 32-38886 (313) 38-07224 FAX
From: P. J. Nallo (313) 33-75358
Subject: Speed Control Cutoff Switch
Part Number: F2VY-9F924-A
Specification: Not Provided
Supplier: Texas Instruments

Received: Ten pieces of filter paper, containing particles scraped from component parts, were received on January 26, 1999. They were identified as A, B, and C (Cup and Port samples), and D and F (Cup and Contact samples).

Object: Perform EDS analysis on each sample.

Conclusion: There was transfer of copper-zinc material from the contact to the cup region on each part.

Data and Analysis:

Surface Analysis

(Scanning Electron Microscopy (SEM), and Energy Dispersive X-ray Spectroscopy (EDS))

Particles from each piece of filter paper were placed on a carbon stud for examination in a scanning electron microscope (SEM) using Energy Dispersive X-ray Spectroscopy (EDS). The D and F samples were wet, so a portion of each was rinsed in freon and re-filtered before particles were placed on a carbon stud. Four particles/groups of particles from each sample were examined. Although there was some variation in the analyzed samples, typical EDS spectra are given in Figures 1 - 10. The following elements were detected in these spectra, in decreasing order of elemental concentration.

(2) Zinc, Iron - Cup

(2) Zinc, Copper - Contact

Al, Si, Ca
K position
Base on
MIL-STD-883C

	A Cup	B Cup	C Cup	D Cup	F Cup
	3 2 Zinc	Copper 2	Zinc 2.3	Zinc 2.4	Copper 3
	3 Copper	Zinc 2.3	Iron 2	Copper 3	Zinc 2.3
	+ Aluminum	Phosphorus 1	Copper 3	Potassium 1	Potassium 1
	2 Iron	Iron 2	Chromium 1	Iron 1	Sulfur 1
	+ Silicon	Silicon 1	Silicon 1	Silicon 1	Iron 2
	+ Calcium	Sulfur	Calcium 1	Sulfur	
	Sulfur	Potassium 1	Sulfur		
	+ Potassium	Calcium 1			
	A Port	B Port	C Port	D Contact	F Contact
4 Port	4 Iron	Silicon 1	Iron 4	Copper 5	Copper 5
5 Contact	3 Copper	Calcium 1	Copper 3	Silver 5	Zinc 5
	1 Aluminum	Phosphorus 1	Zinc 4.3	Zinc 5	Silver 5
	1 Potassium	Aluminum 1	Sulfur	Iron 1	Potassium 1
		Copper 1	Aluminum 1	Silicon 1	Iron 1
		Zinc 4.3	Silicon 1		Sulfur 1
		Iron 4			
		Titanium			
		Chlorine			



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16000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1814

Report 9900226

February 4, 1999

To: G. Stevens (313) 32-36686 (313) 39-07224 FAX
From: P. J. Nalos (313) 33-75358
Subject: Speed Control Cutoff Switch
Part Number: F2VY-8F924-A
Specification: Not Provided
Supplier: Texas Instruments

Received: Two short lengths of copper tubing and two brass fittings were received on February 2, 1999. A copper tube and brass fitting were placed in a bath of old brake fluid, and a potential applied across the two parts; the other set was placed in a bath of new brake fluid, with a potential applied across the two parts.

Object: Perform an EDS analysis on the surface deposits.

Data and Analysis:

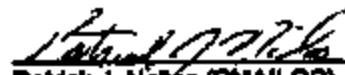
Surface Analysis

(Scanning Electron Microscopy (SEM) and Energy Dispersive X-ray Spectroscopy (EDS))

A portion of the surface deposit from each sample was removed, rinsed in freon, and placed on a carbon stud for Energy Dispersive X-ray Spectroscopy (EDS) in a scanning electron microscope (SEM). The following elements were detected, in decreasing order of elemental concentration.

Copper Tube - New Brake Fluid	Copper Tube - Old Brake Fluid	Fitting - New Brake Fluid	Fitting - Old Brake Fluid
Copper	Copper	Copper	Copper
Zinc	Chlorine	Zinc	Potassium
Sulfur		Chlorine	Sulfur
Iron			
Calcium			
Aluminum			
Silicon			

By:


Patrick J. Nalos (PNAILOS)
Laboratory Specialist

Enclosures: Figures 1 - 4
PJN/pjn

Surface Analysis (continued)

There are several particles in the A, B, and C cup samples that are iron-rich. These are from the steel base material. A typical EDS spectrum is shown in Figure 11 for these particles.

The number of copper-zinc particles in the cup indicate material transfer from the contact to the cup. The B port sample was composed primarily of fibers.

By: _____

Patrick J. Nallos (PNAILOS)
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Enclosures: Figures 1 - 11
PJN/pjn



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15000 Century Drive
Dearborn, MI 48120-1267
FAX (313) 322-1814

Report 9900228

February 4, 1999

To: G. Stevens (313) 32-36686 (313) 39-07224 FAX

From: P. J. Nalos (313) 33-75358

Subject: Speed Control Cutoff Switch
Part Number: F2VY-6F824-A
Specification: Not Provided
Supplier: Texas Instruments

Received: Two short lengths of copper tubing and two brass fittings were received on February 2, 1999. A copper tube and brass fitting were placed in a bath of old brake fluid, and a potential applied across the two parts; the other set was placed in a bath of new brake fluid, with a potential applied across the two parts.

Object: Perform an EDS analysis on the surface deposits.

Data and Analysis:

Surface Analysis

(Scanning Electron Microscopy (SEM) and Energy Dispersive X-ray Spectroscopy (EDS))

A portion of the surface deposit from each sample was removed, rinsed in iron, and placed on a carbon stud for Energy Dispersive X-ray Spectroscopy (EDS) in a scanning electron microscope (SEM). The following elements were detected, in decreasing order of elemental concentration.

Copper Tube - New Brake Fluid	Copper Tube - Old Brake Fluid	Fitting - New Brake Fluid	Fitting - Old Brake Fluid
Copper	Copper	Copper	Copper
Zinc	Chlorine	Zinc	Potassium
Sulfur		Chlorine	Sulfur
Iron			
Calcium			
Aluminum			
Boron			

By: Patrick J. Nalos (PNALOS)
Laboratory Specialist

Enclosures: Figures 1 - 4
PJN/pjn



Figure 1: Typical EDS X-ray spectrum of particles from the A Cup sample.

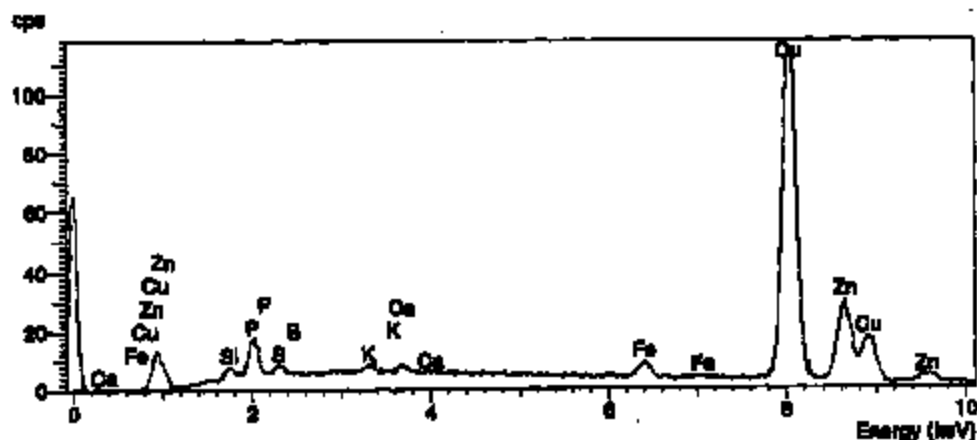


Figure 2: Typical EDS X-ray spectrum of particles from the B Cup Sample.

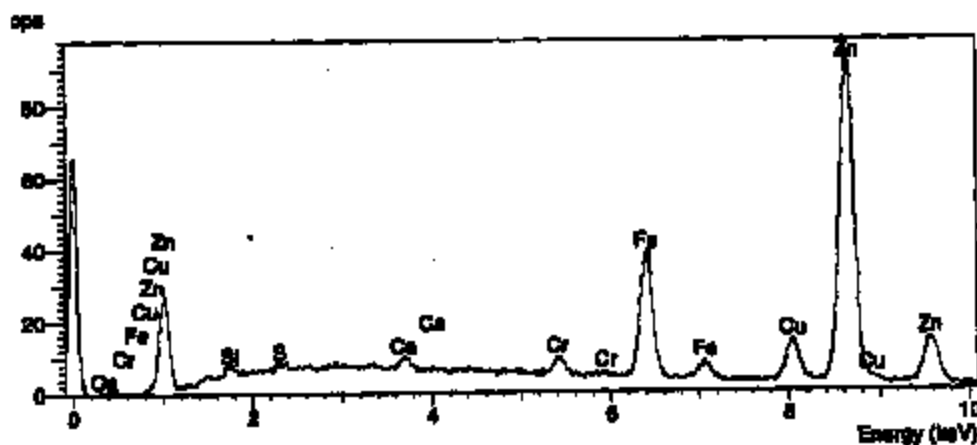


Figure 3: Typical EDS X-ray spectrum of particles from the C Cup sample.

Note: Nominal magnifications given for photomicrographs.



Figure 4: Typical EDS X-ray spectrum of particles from the D Cup Sample.

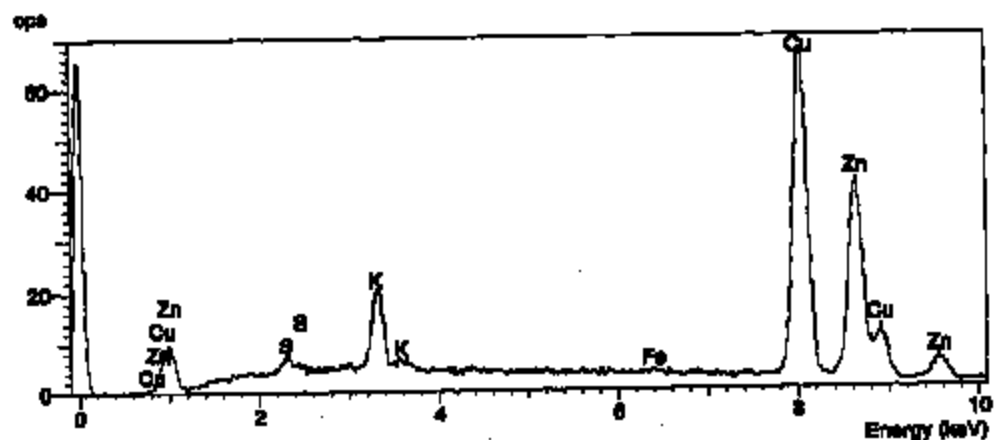


Figure 5: Typical EDS X-ray spectrum of particles from the F Cup sample.

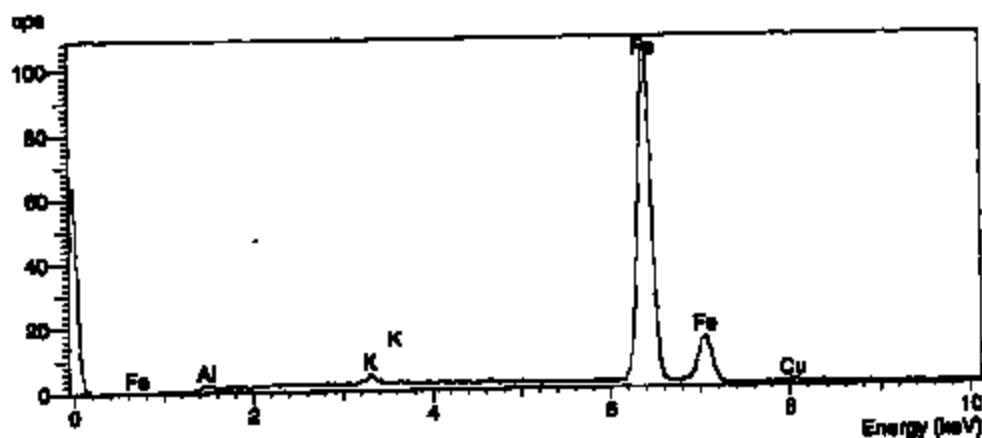


Figure 6: Typical EDS X-ray spectrum of particles from the A Port sample.

Note: Nominal magnifications given for photomicrographs.

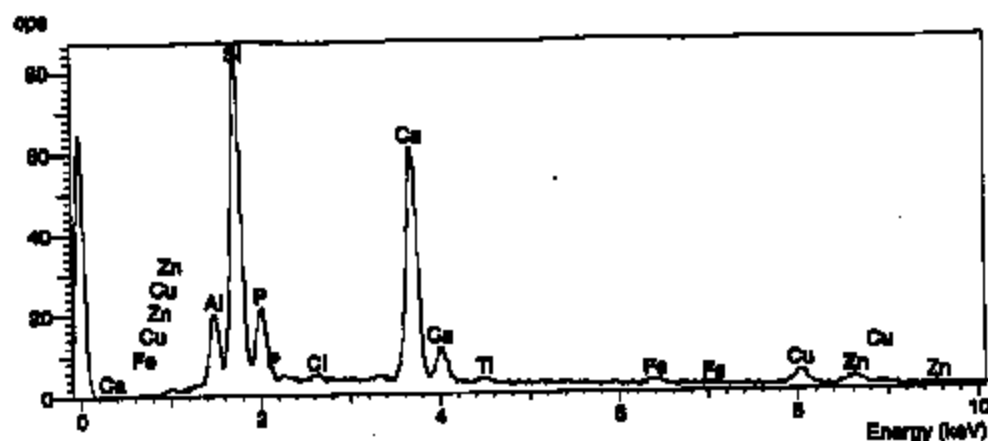


Figure 7: Typical EDS X-ray spectrum of particles from the B Port sample.

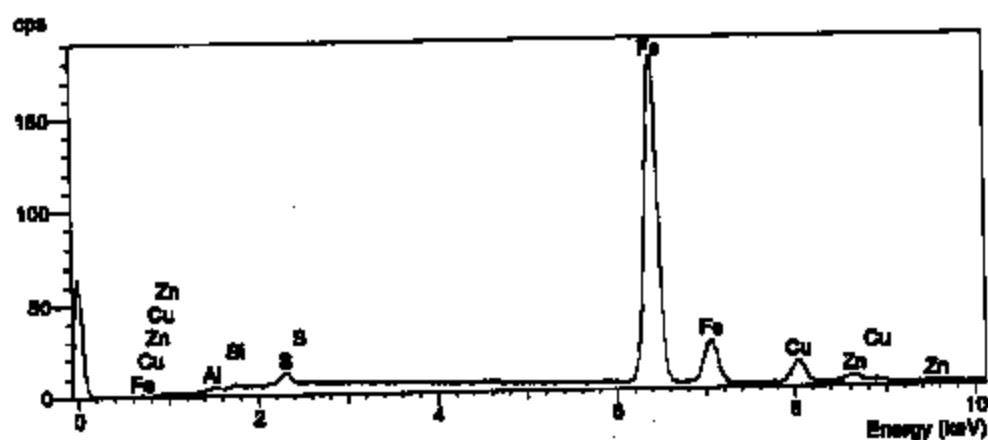


Figure 8: Typical EDS X-ray spectrum of particles from the G Port sample.

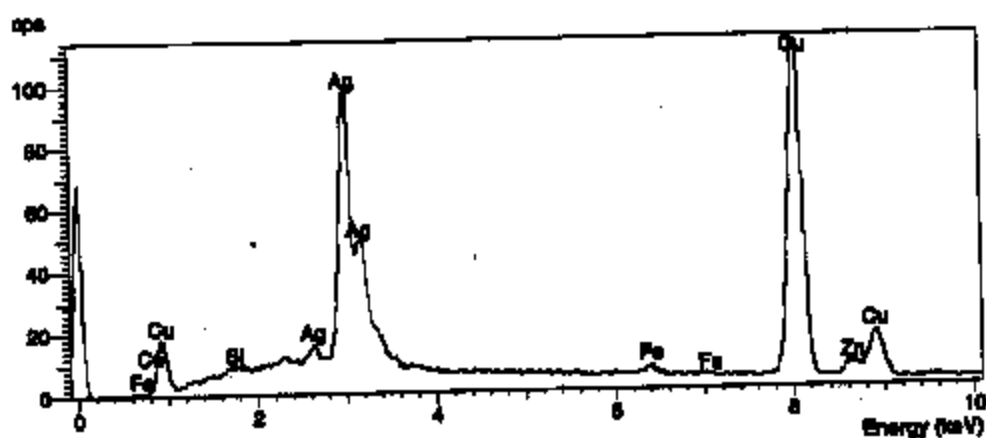


Figure 9: Typical EDS X-ray spectrum of particles from the D Contact sample.

Note: Nominal magnifications given for photomicrographs.

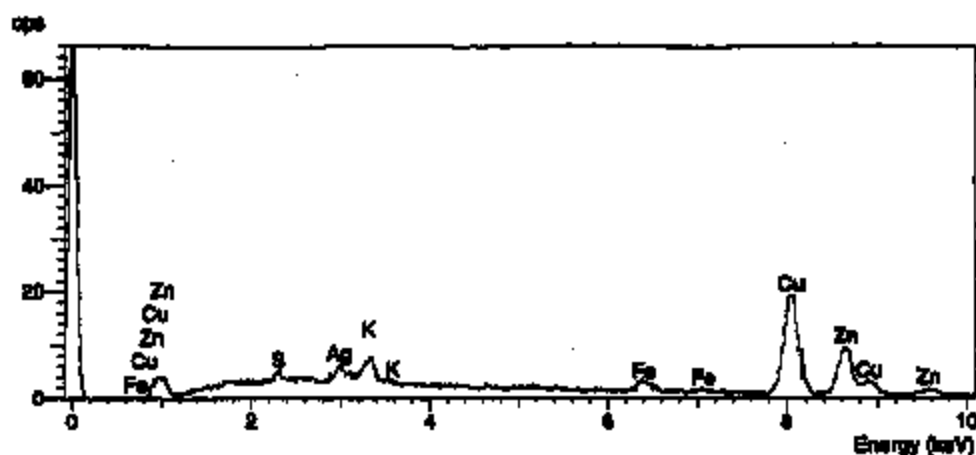


Figure 10: Typical EDS X-ray spectrum of particles from the F Contact sample.

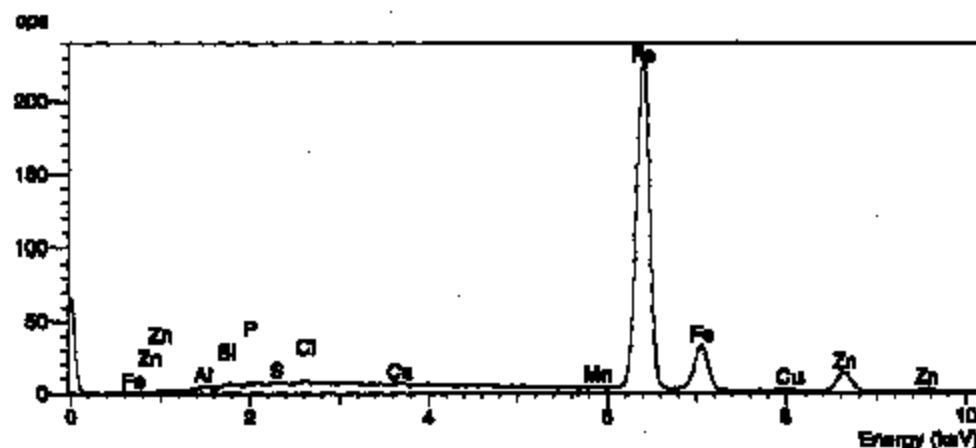


Figure 11: Typical EDS X-ray spectrum of particles from the A, B, and C Cup samples. These are representative of the steel base material.

Note: Nominal magnifications given for photomicrographs.

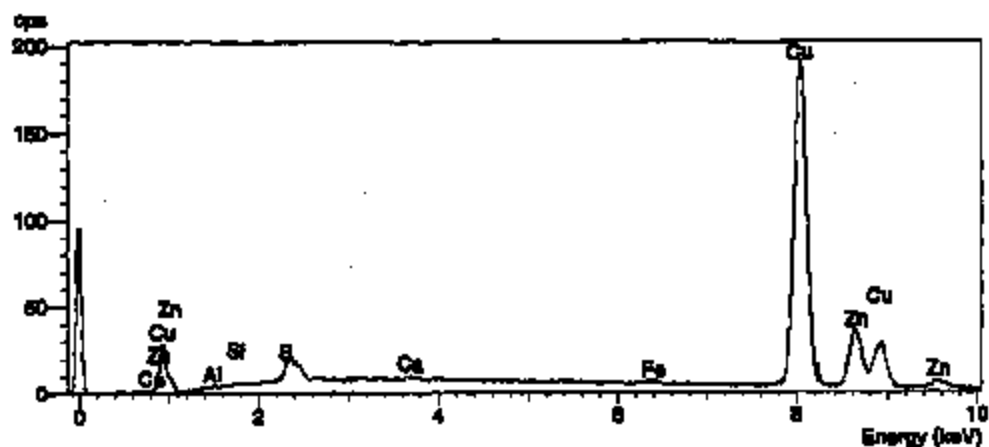


Figure 1: Typical EDS X-ray spectrum of the Copper Tubing - New Brake Fluid sample.

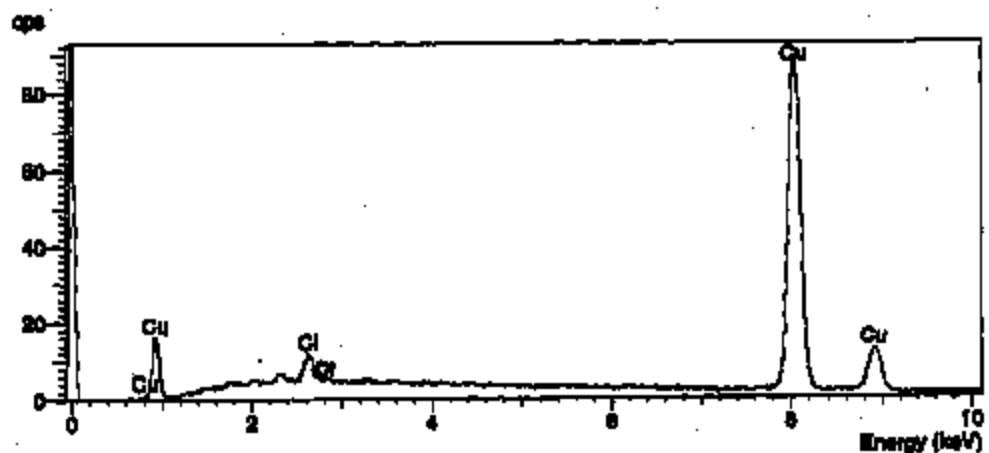


Figure 2: Typical EDS X-ray spectrum of the Copper Tubing - Old Brake Fluid sample.

Note: Nominal magnifications given for photomicrographs.

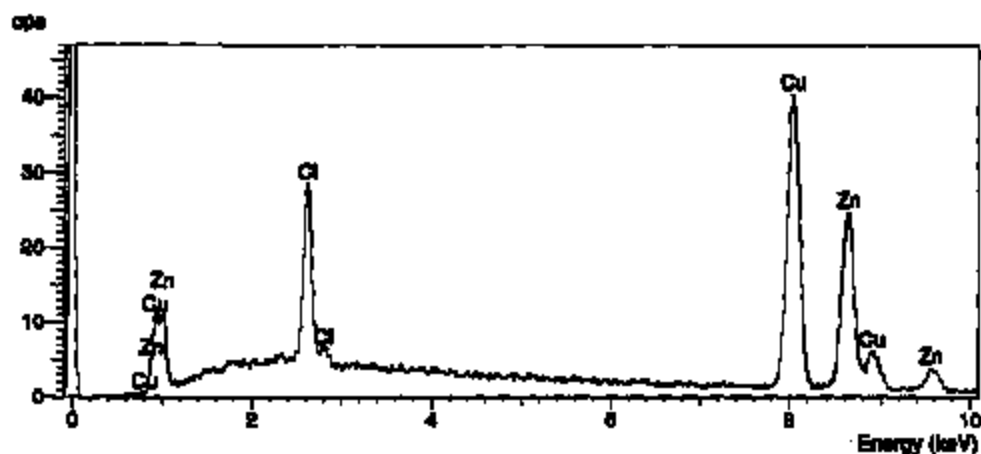


Figure 3: Typical EDS X-ray spectrum of the Filling - New Brake Fluid sample.

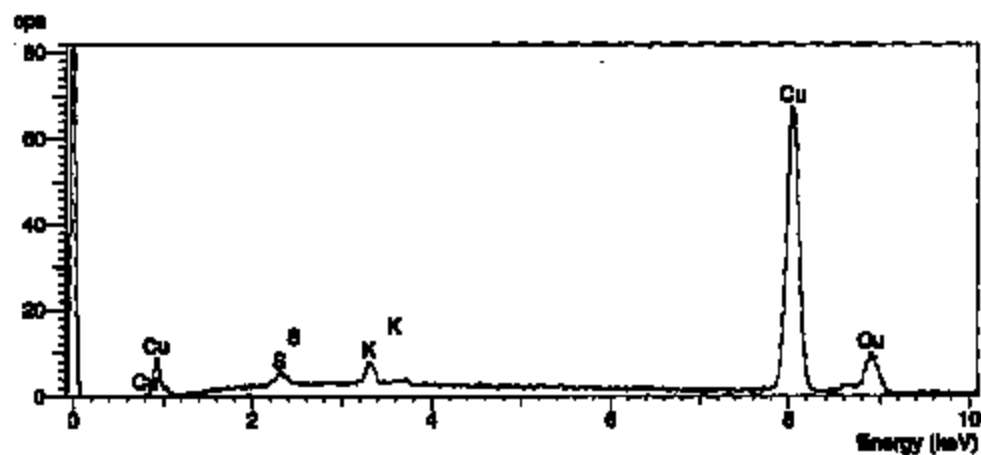
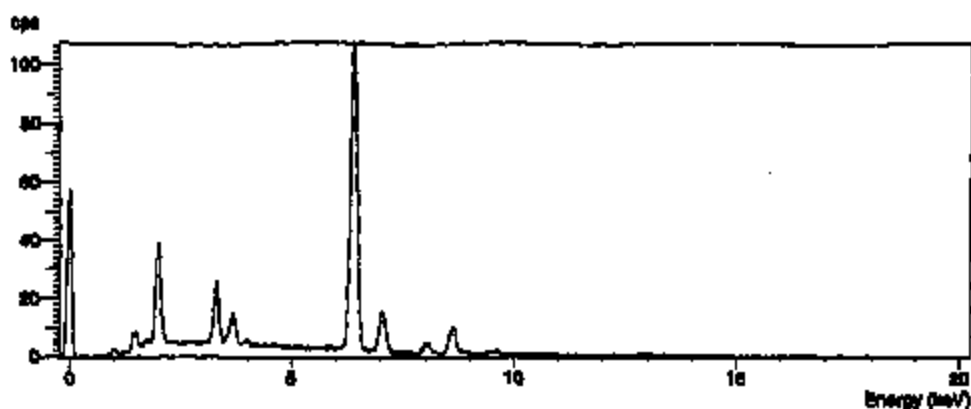
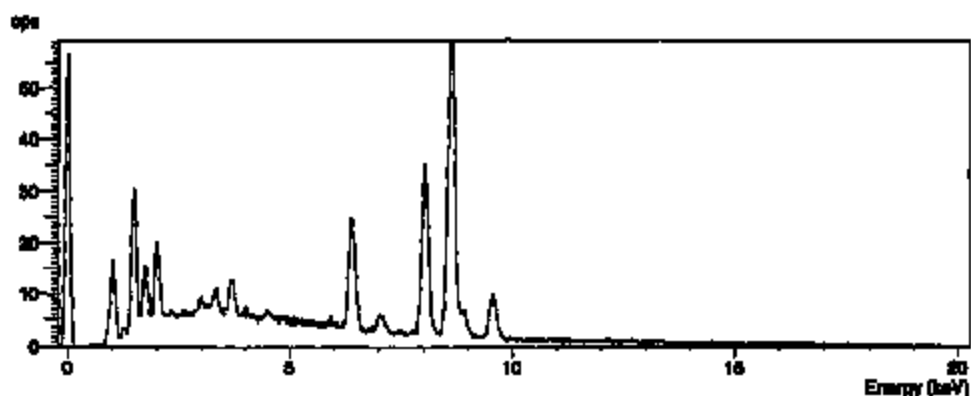


Figure 4: Typical EDS X-ray spectrum of the Filling - Old Brake Fluid sample.

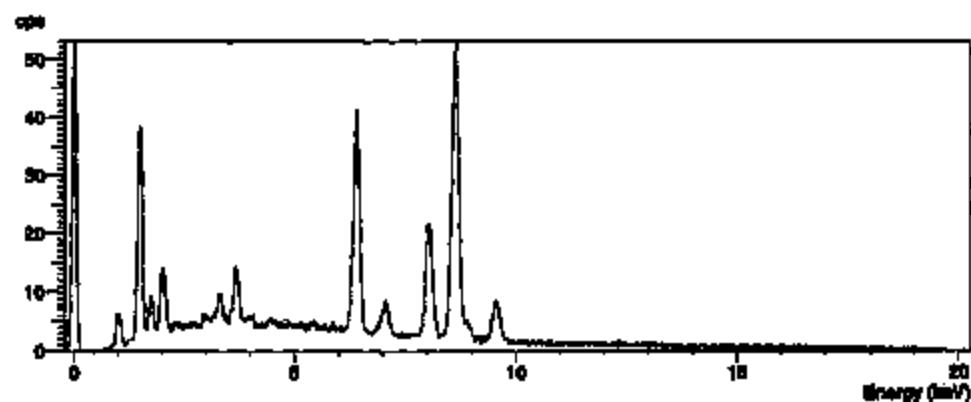
Note: Notional designations given for photomicrographs.



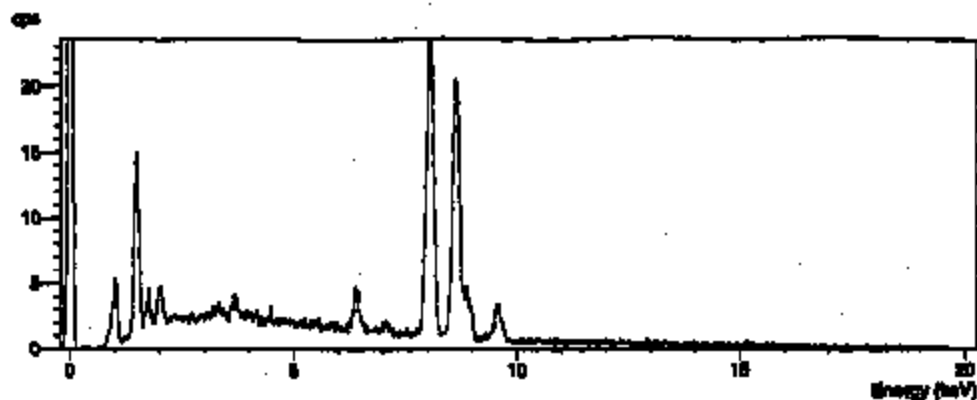
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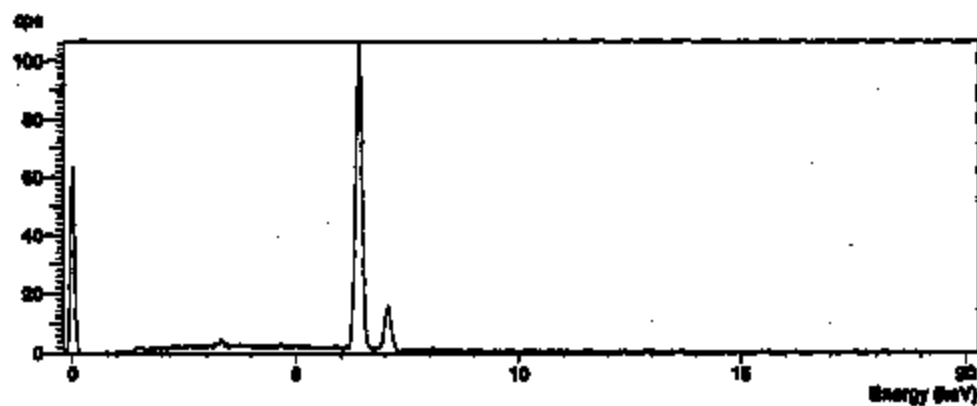
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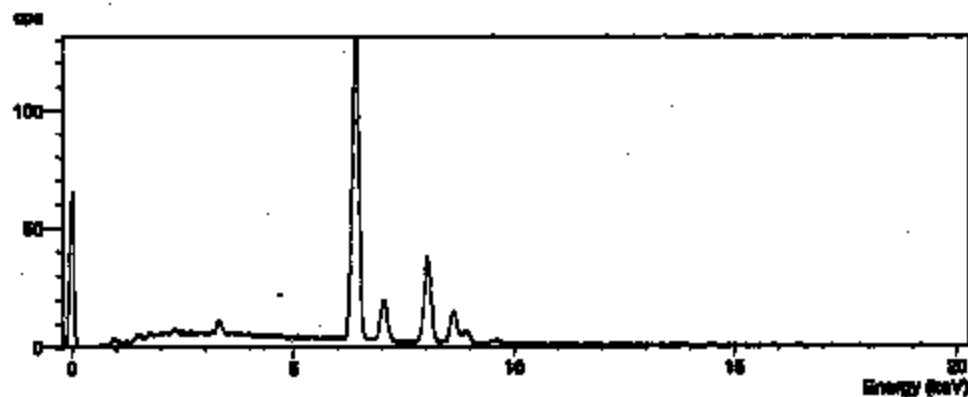
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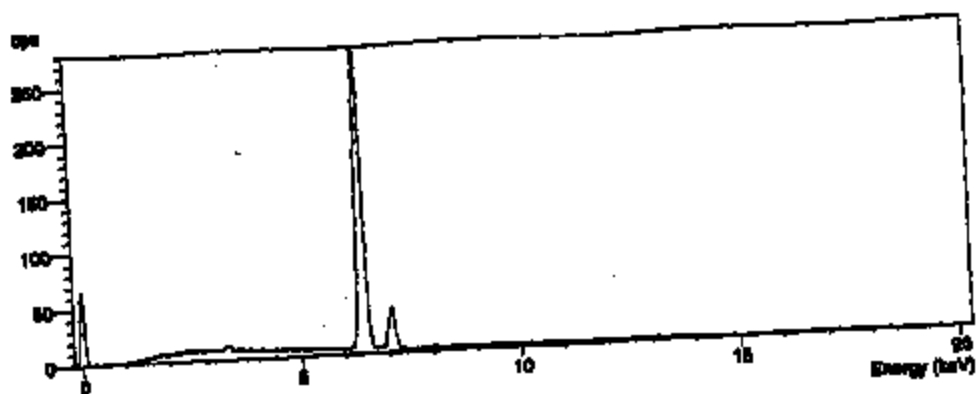
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Job : 9900226
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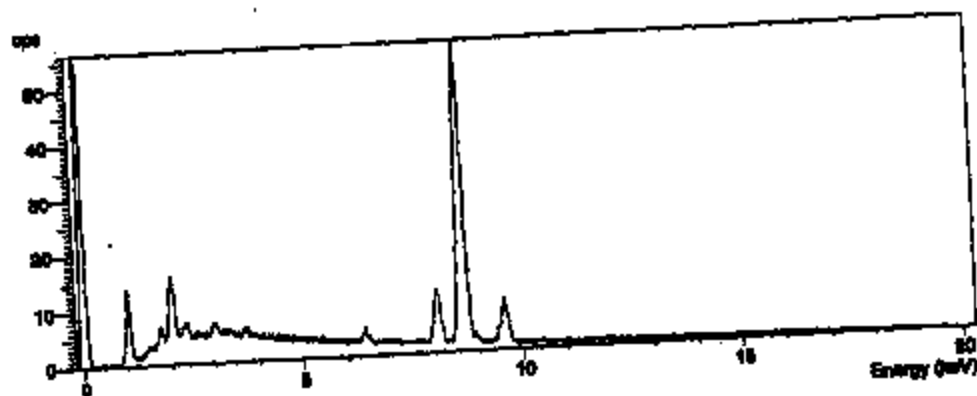
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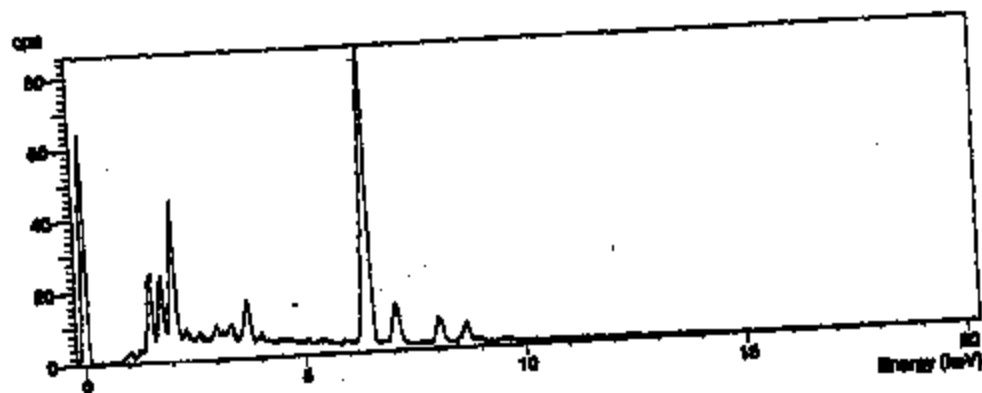
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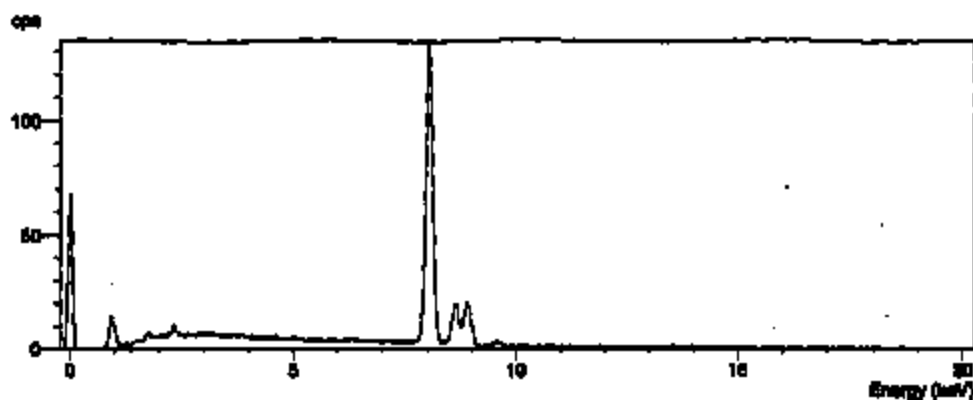
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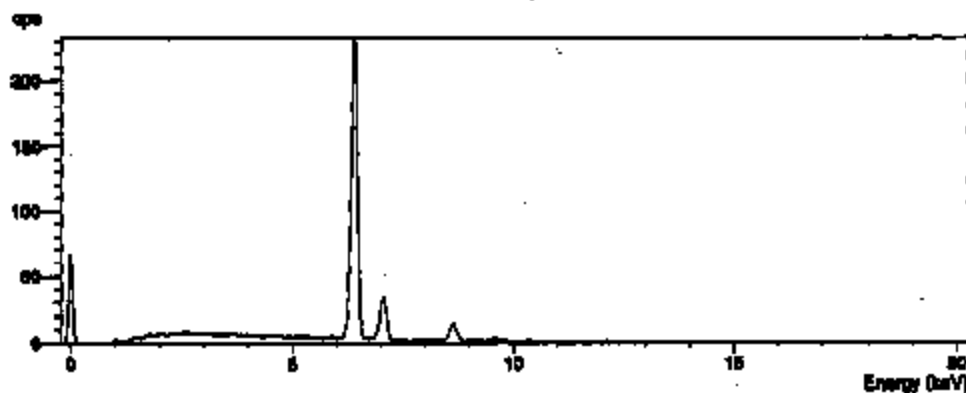
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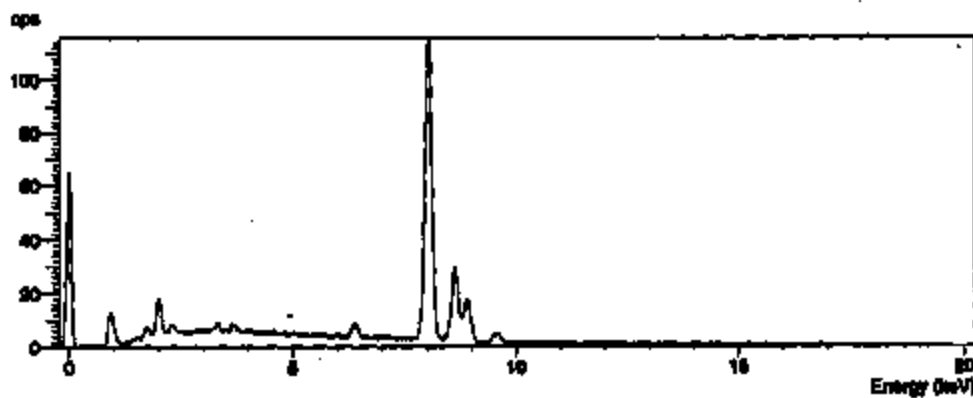
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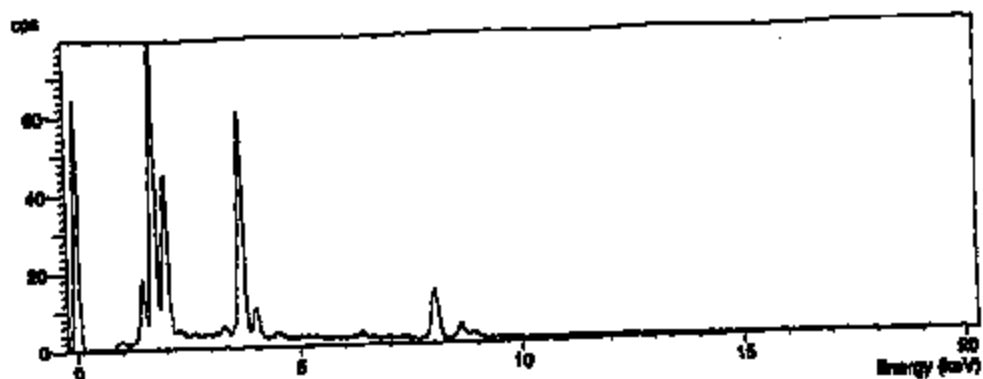
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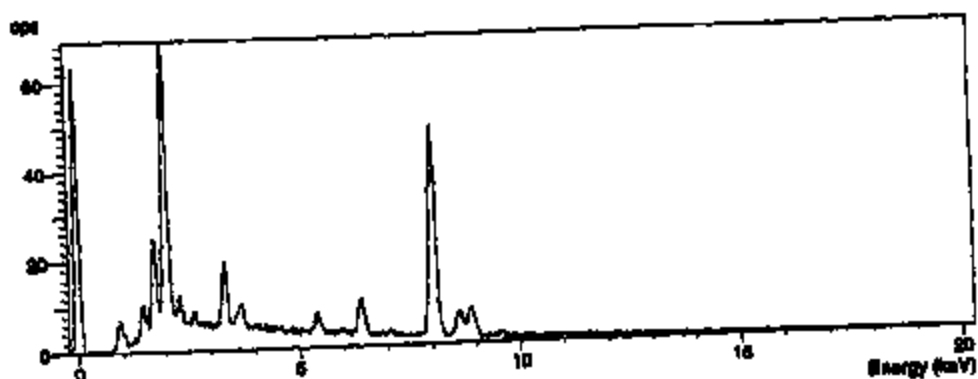
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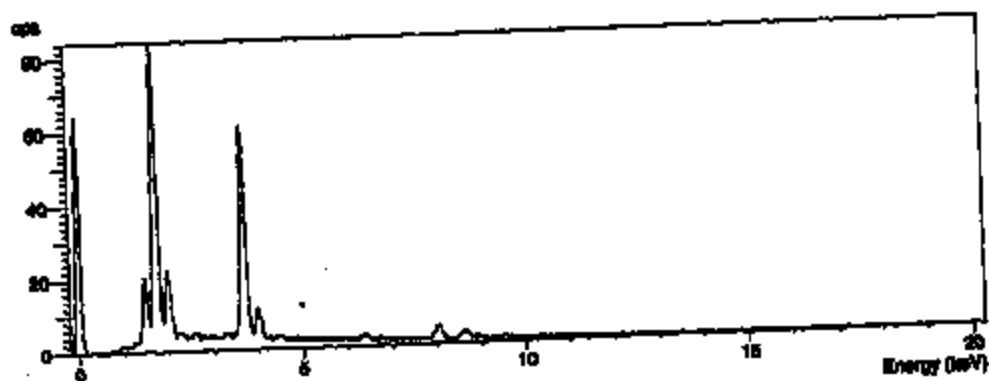
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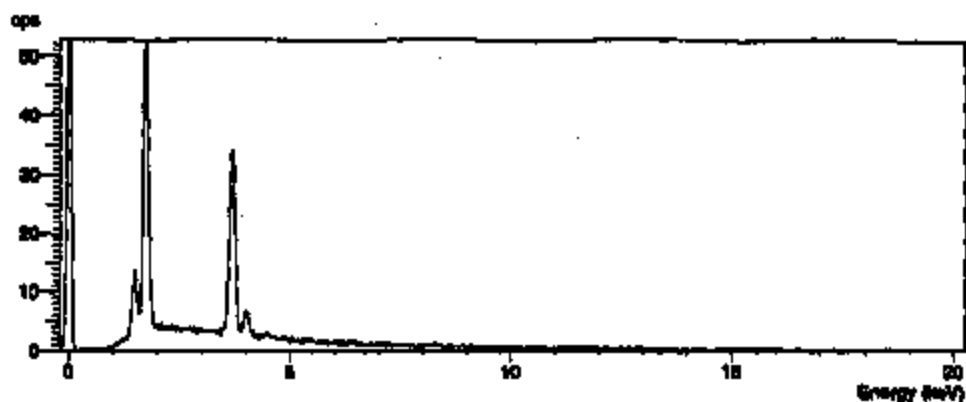
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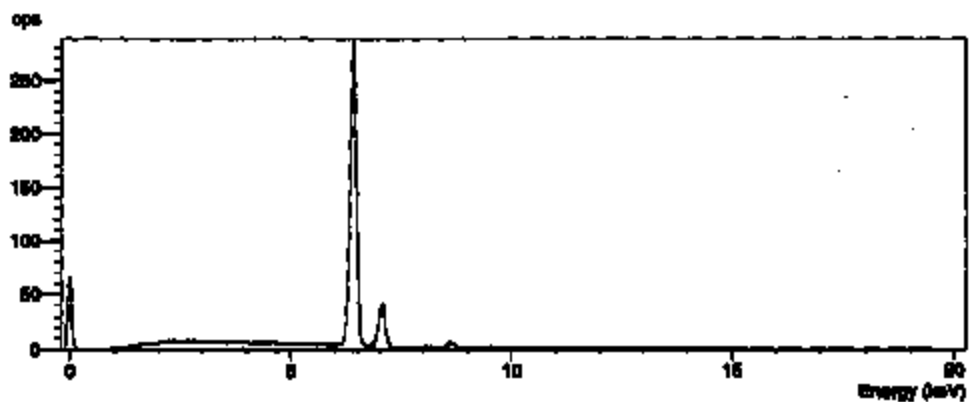
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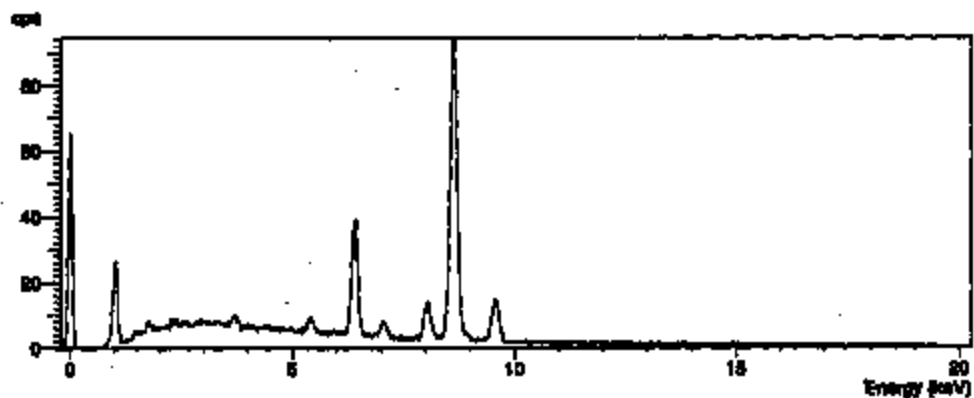
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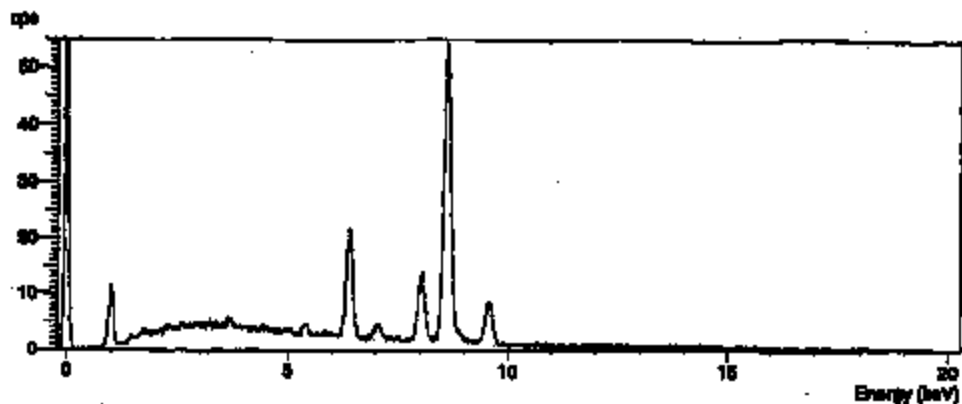
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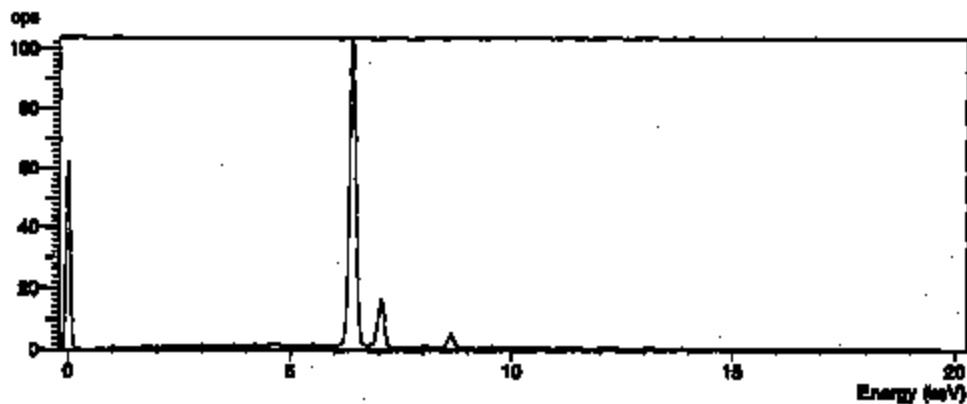
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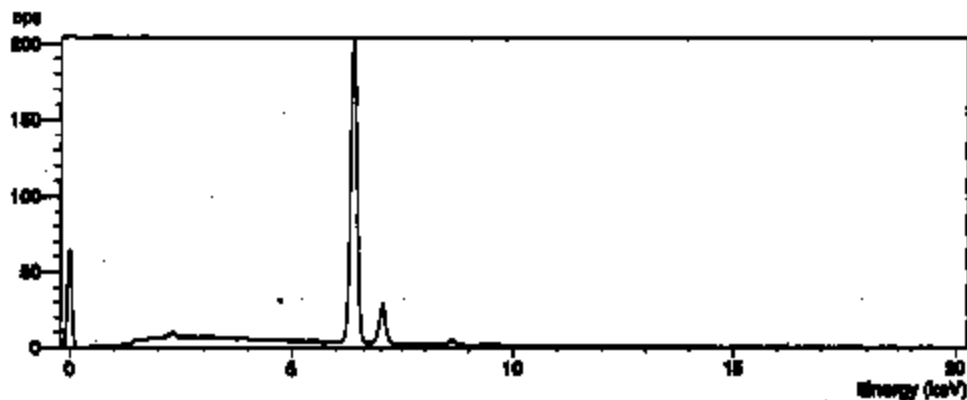
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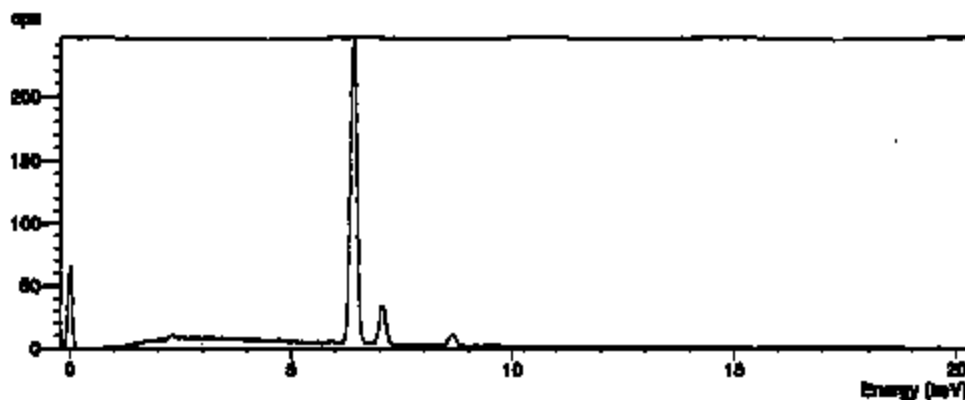
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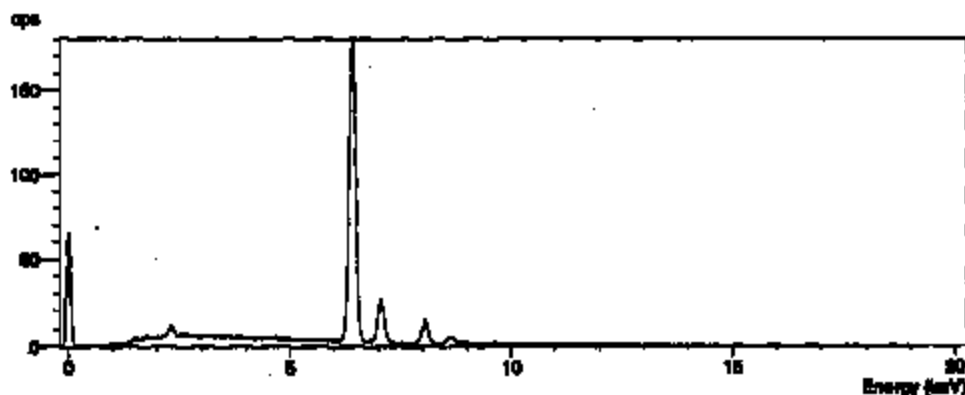
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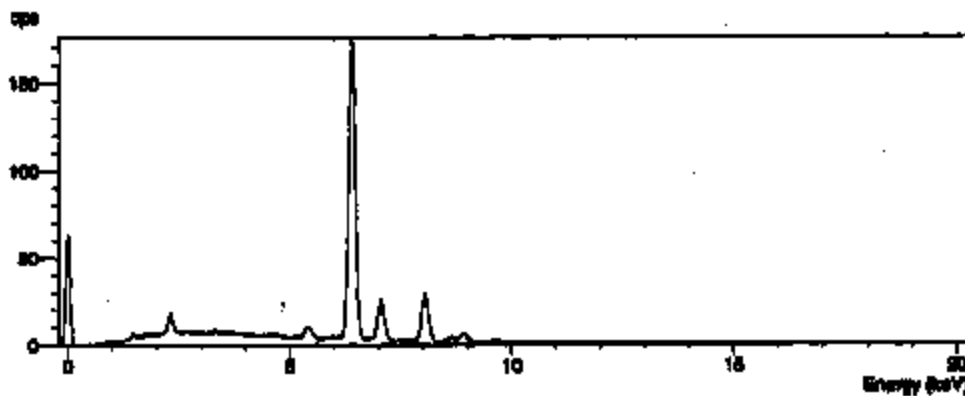
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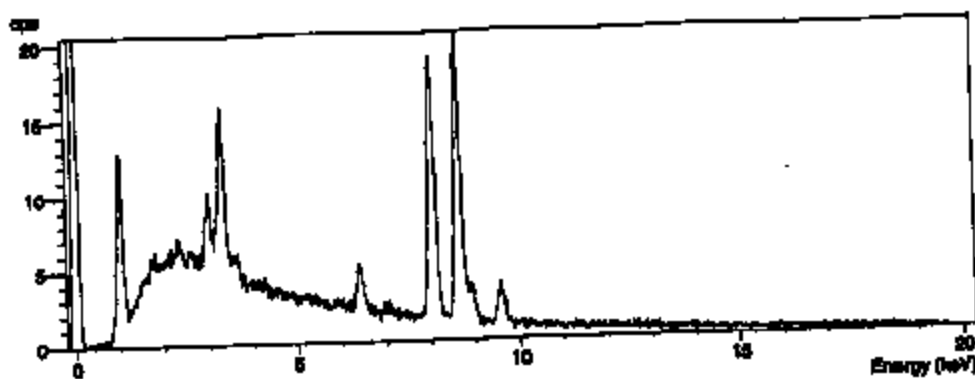
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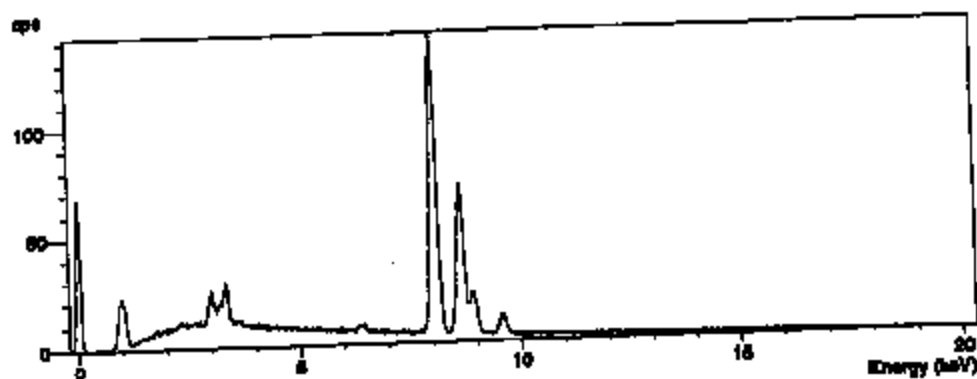
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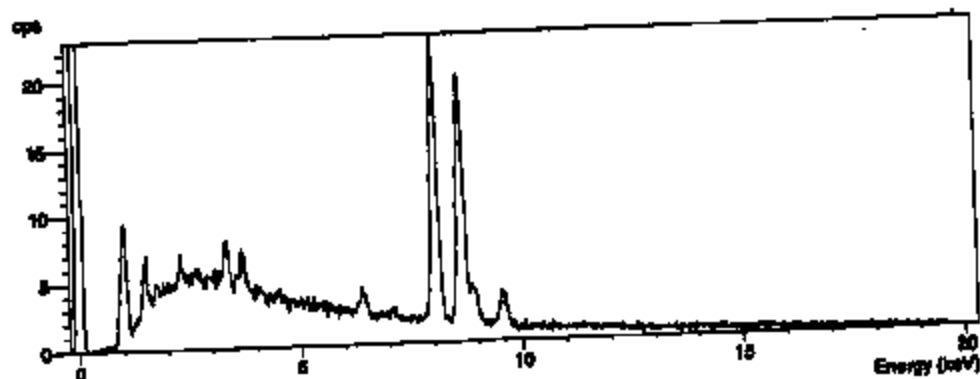
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Job : 9900226
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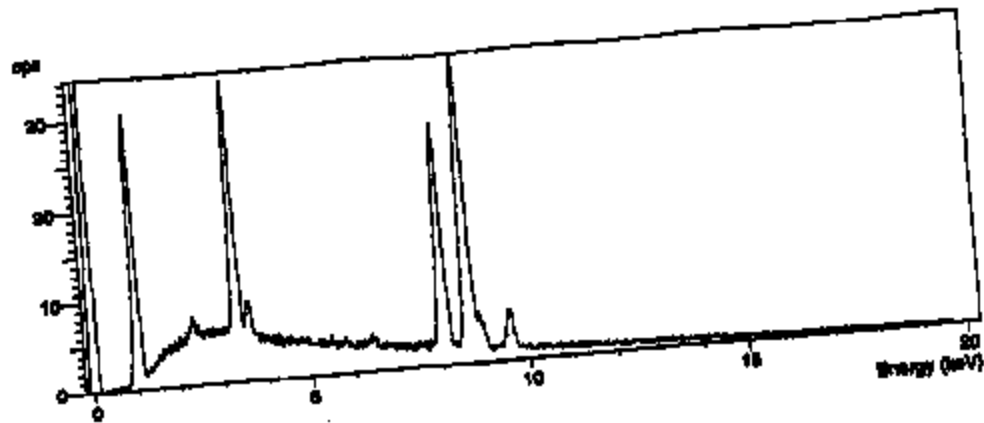
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Client : Greg Stevens
Job : 9900226
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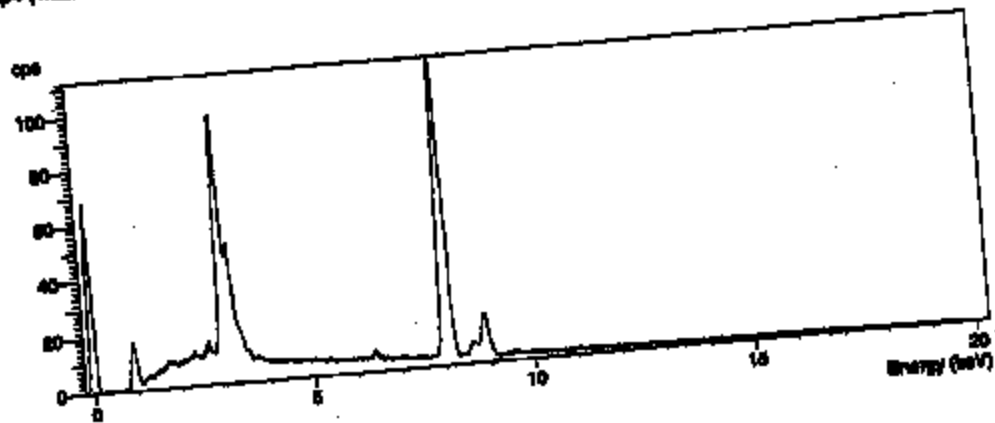
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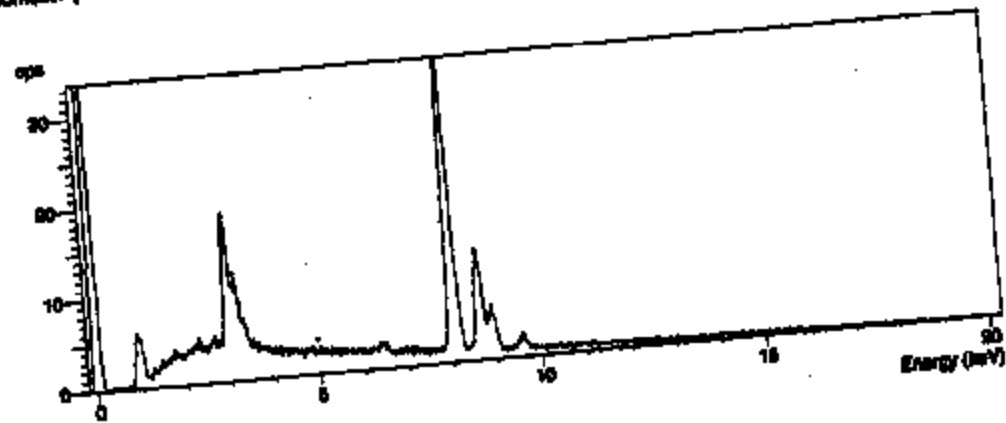
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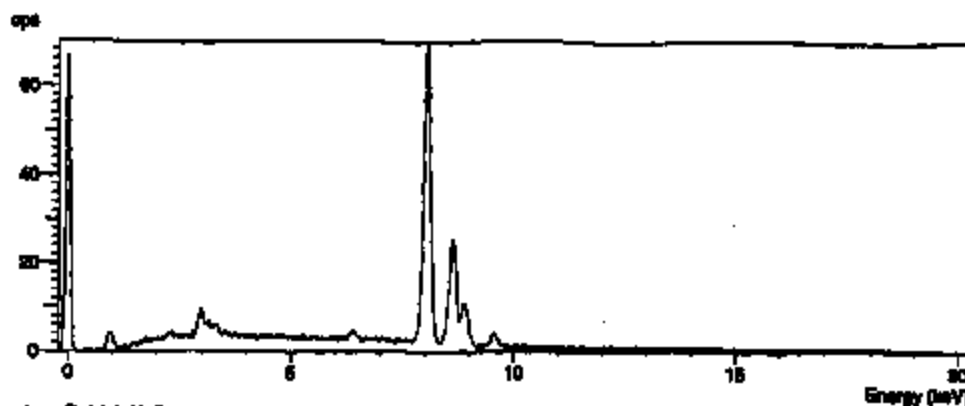
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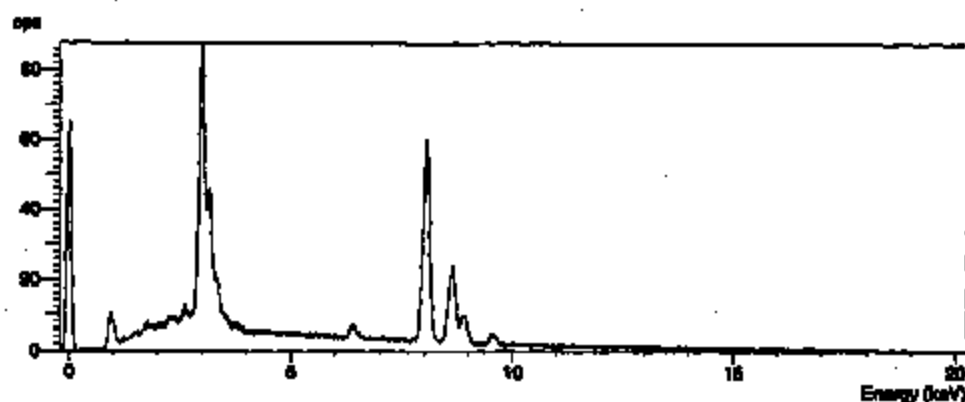
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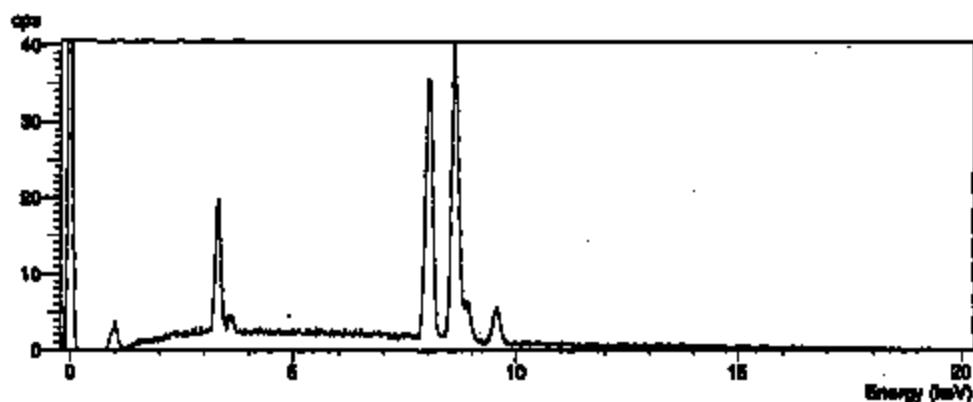
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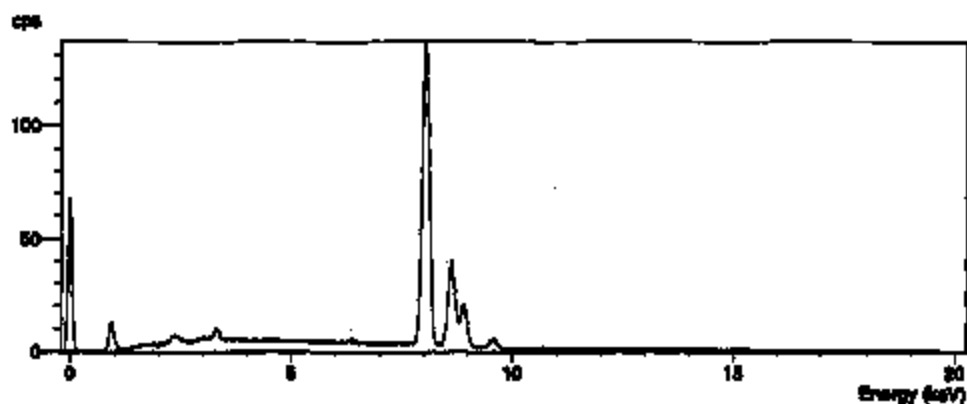
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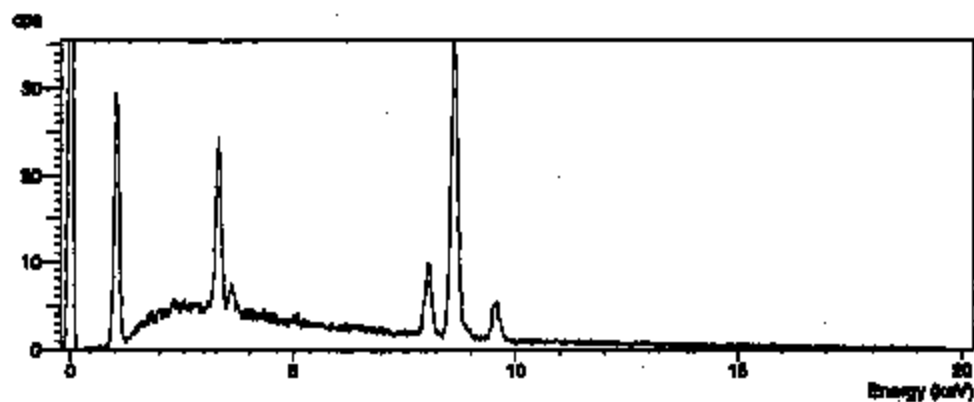
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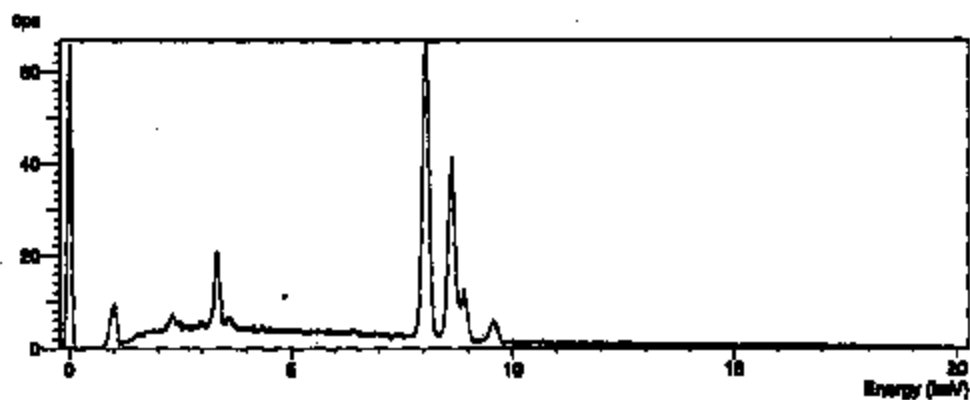
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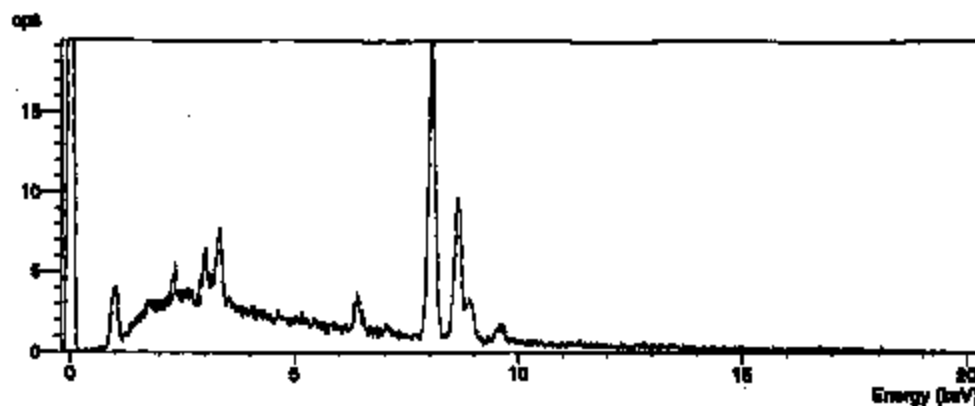
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Job : 8900226
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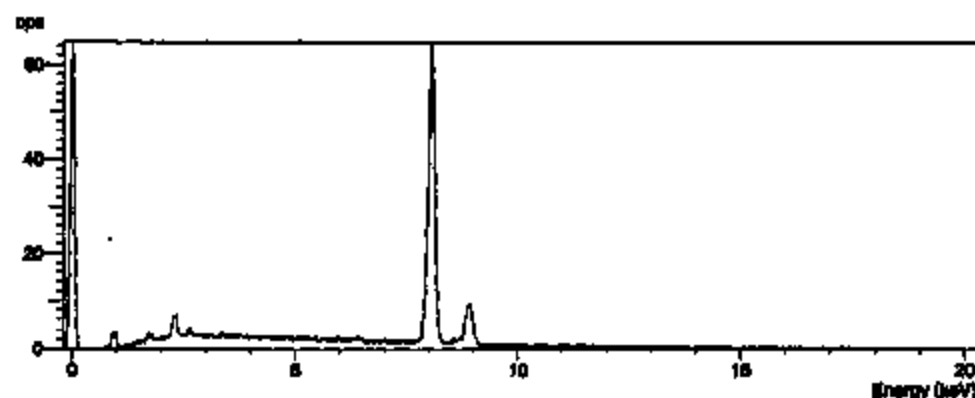
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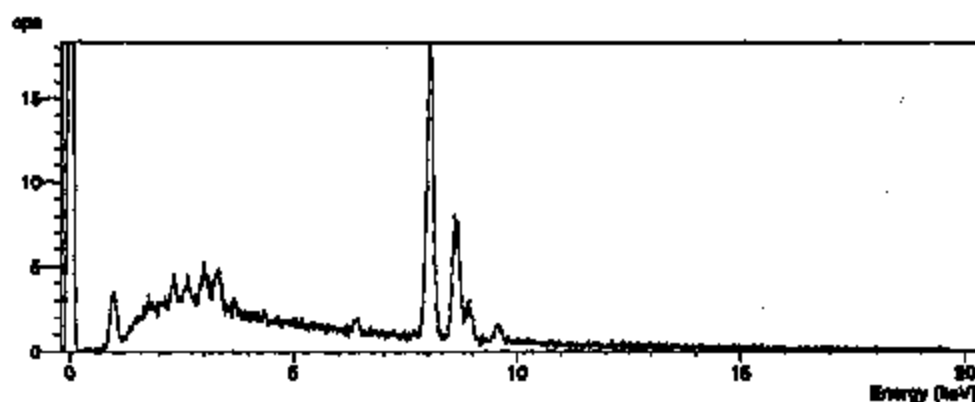
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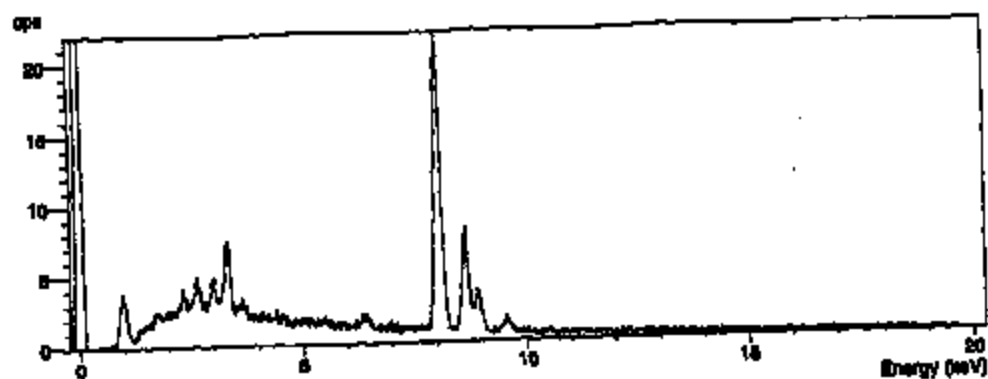
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Job : 9900226
FContact1 (1/29/99 09:48)



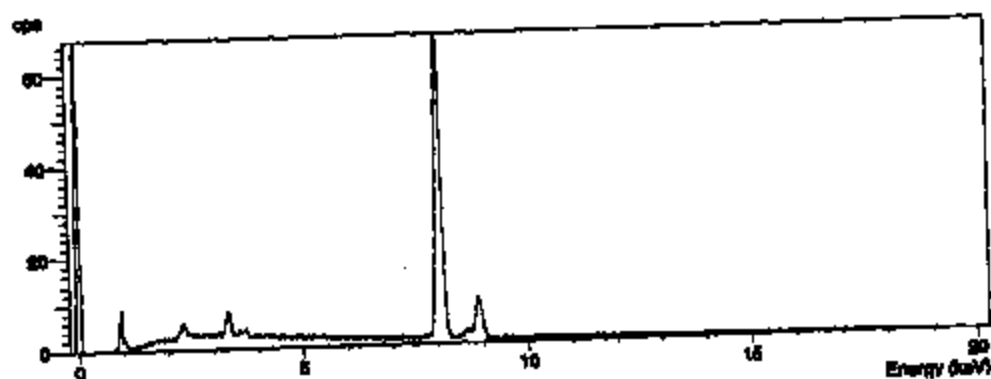
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Client : Greg Stevens
Job : 9900226
FContact2 (1/29/99 09:48)



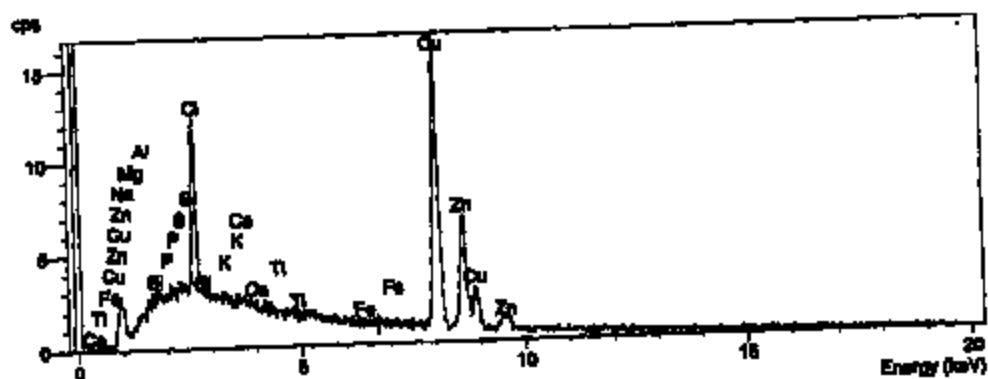
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Client : Greg Stevens
Job : 9900226
FContact3 (1/29/99 09:48)



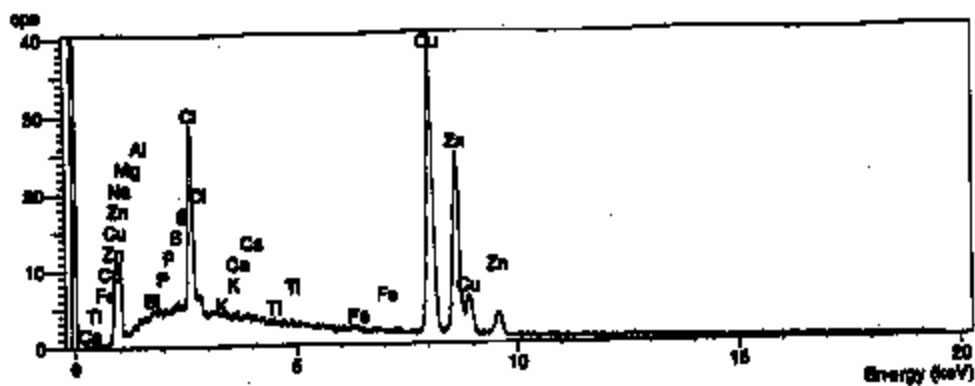
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 Client : Greg Stevens
 Job : 9900226
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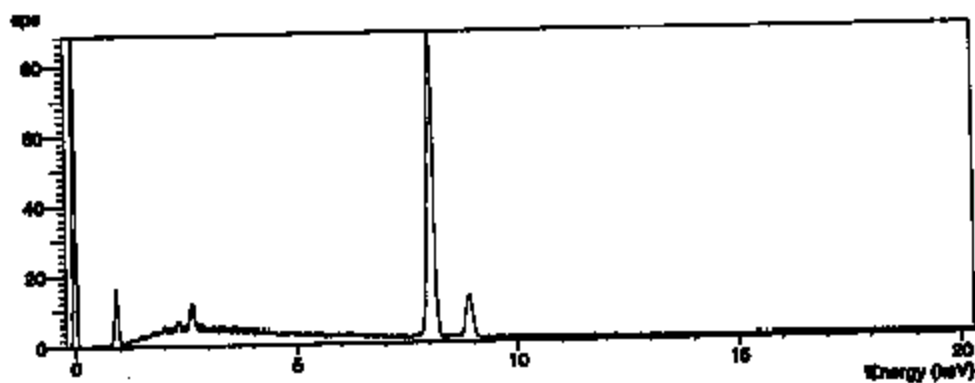
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 Client : Greg Stevens
 Job : 9900226
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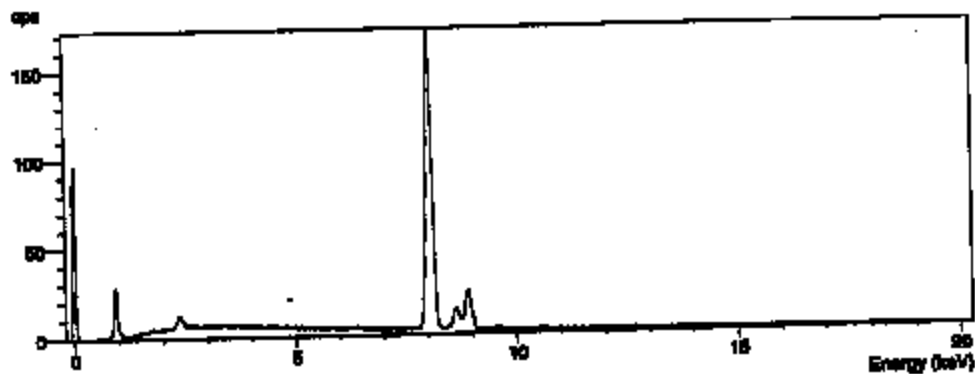
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 Client : Greg Stevens
 Job : 9900226
 Filing New1 (2/2/99 14:07)



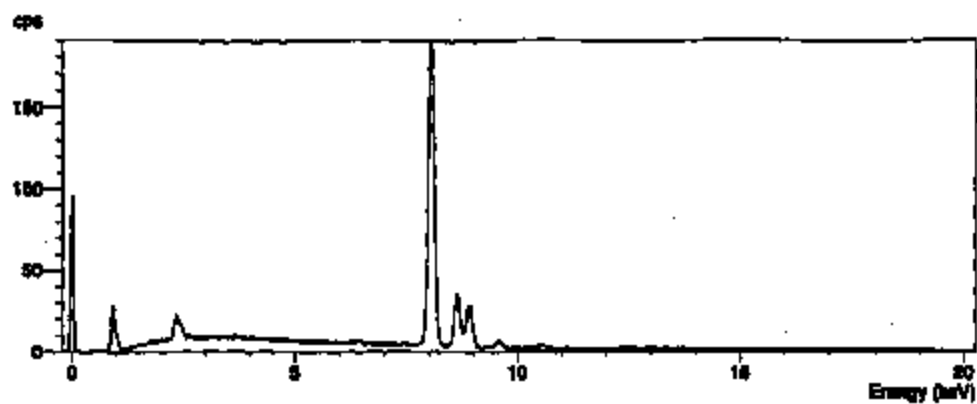
Operator : Patrick Nallo
 Client : Greg Stevens
 Job : 9900228
 Fitting New2 (2/3/99 14:22)



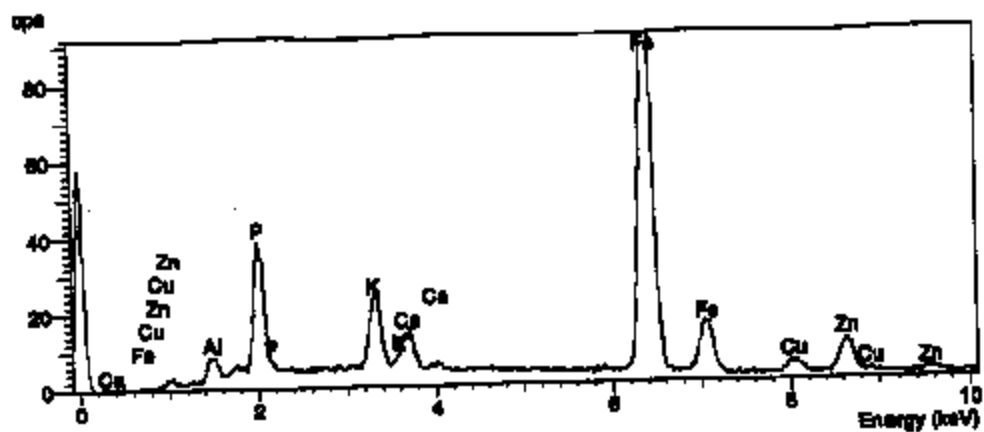
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 Client : Greg Stevens
 Job : 9900228
 Copper Tubing Old1 (2/3/99 14:49)



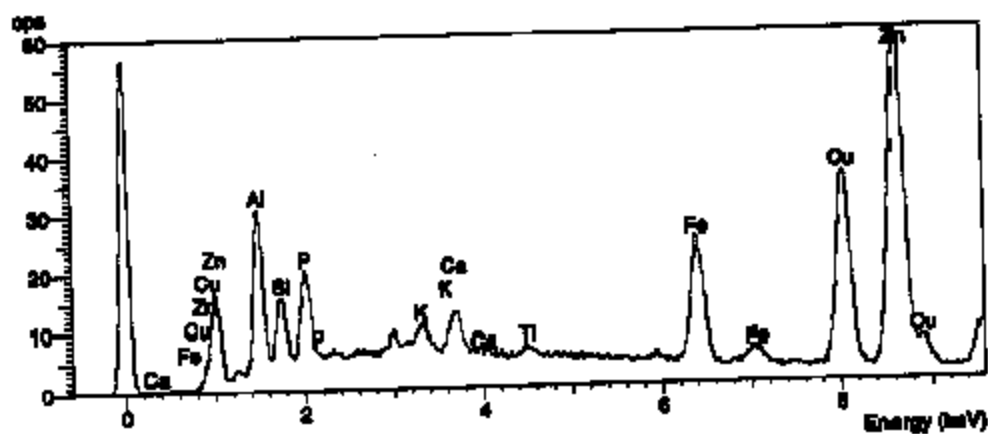
Operator : Patrick Nallo
 Client : Greg Stevens
 Job : 9900228
 Copper Tubing New1 (2/3/99 15:01)



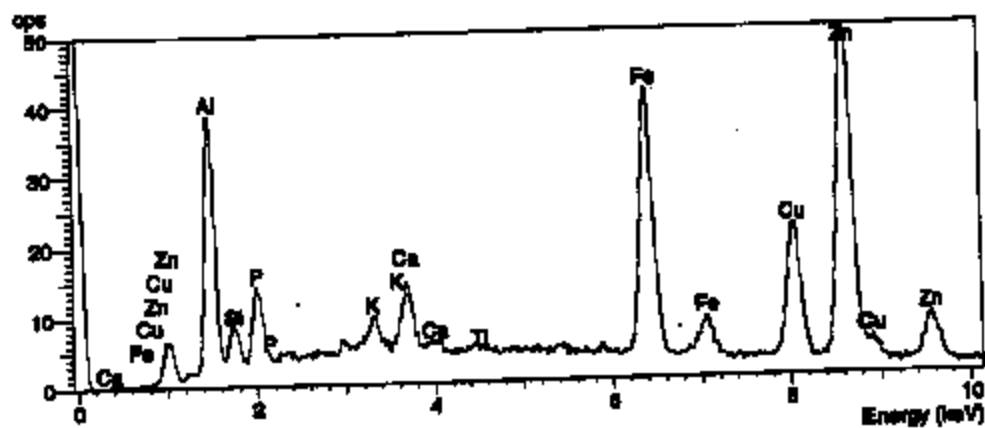
Operator : Patrick Nallio
Client : Greg Bravens
Job : 9900226
Copper Tubing New2 (2/3/99 15:07)



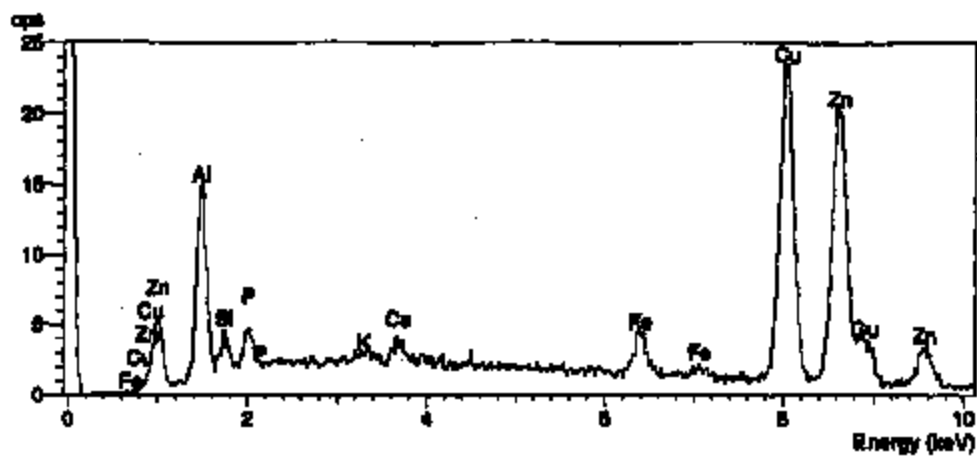
Acup1



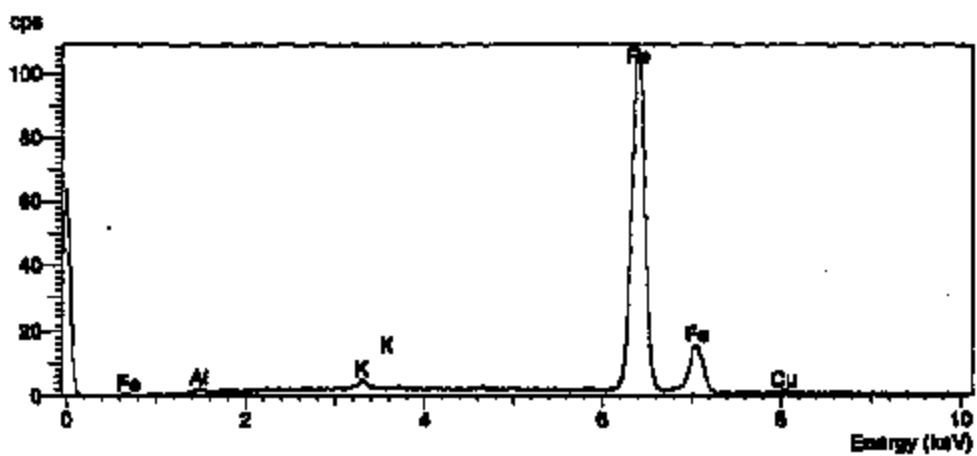
Acup2



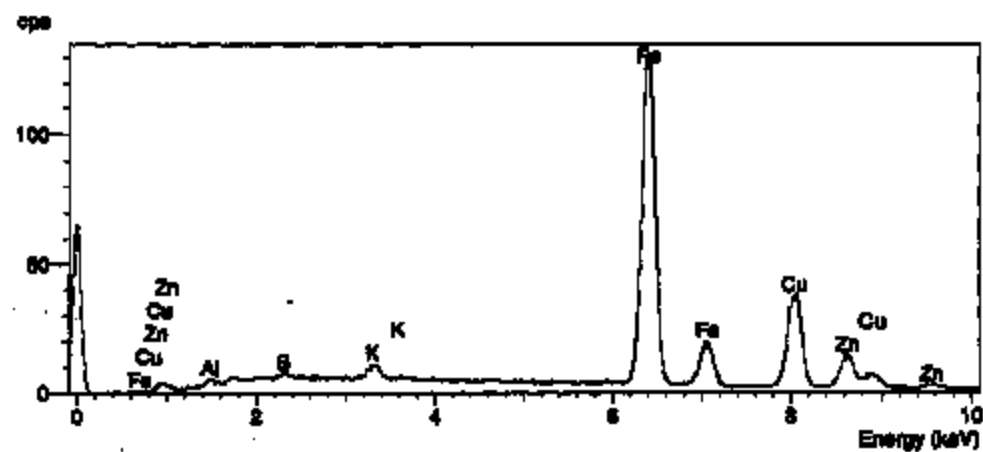
Acup3



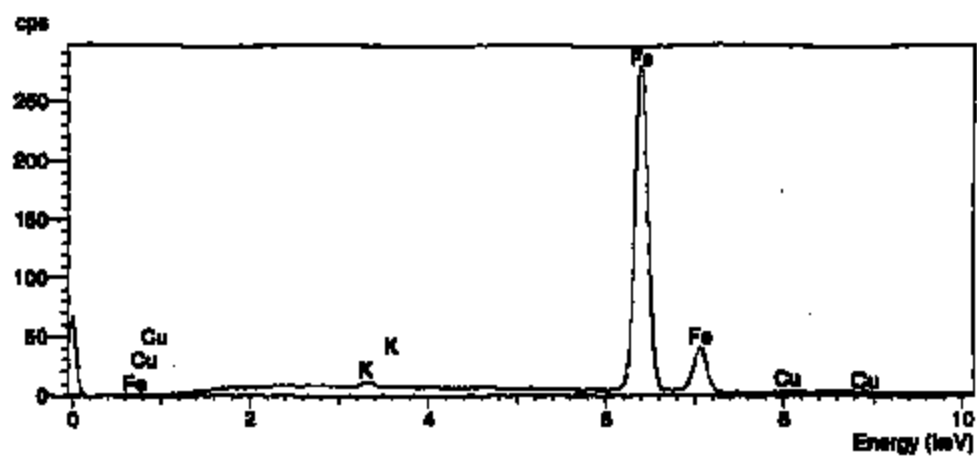
Acup4



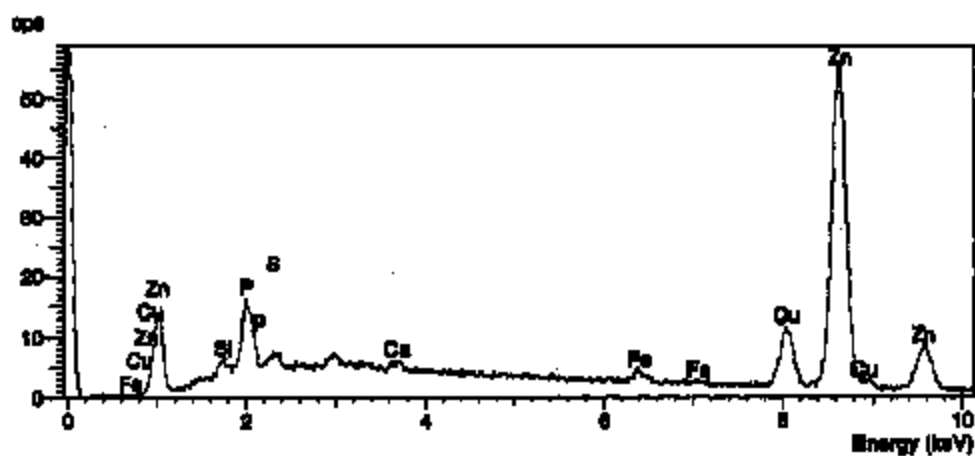
Aport1



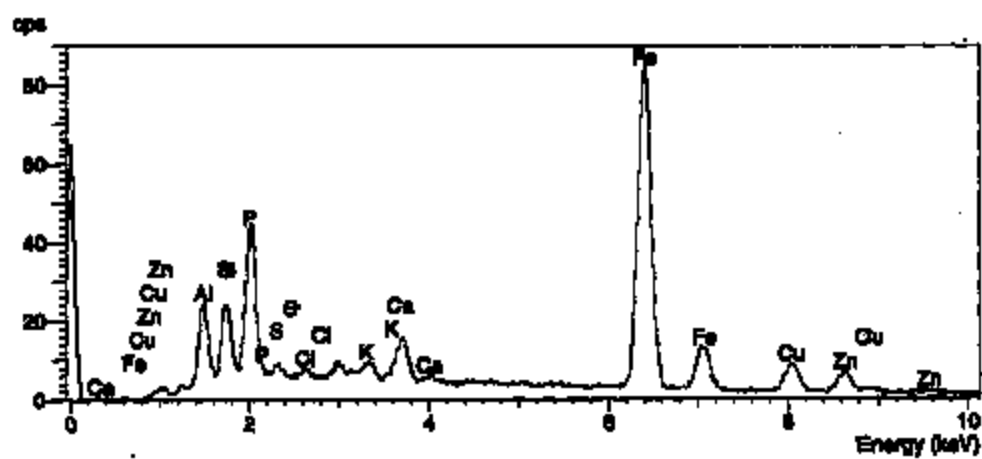
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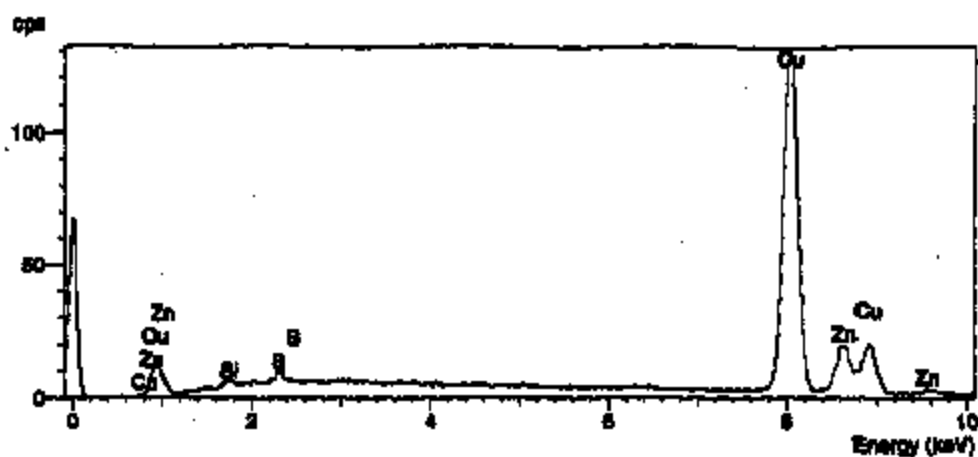
Aport3



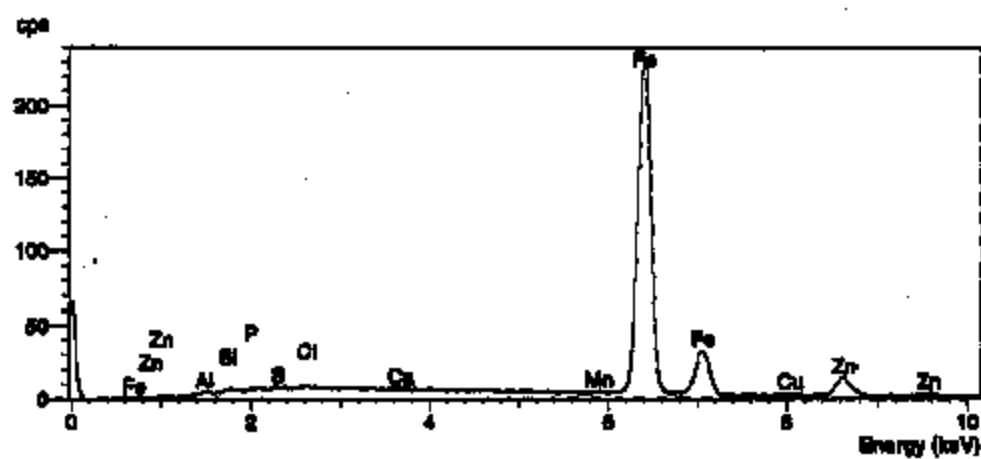
Bcup1



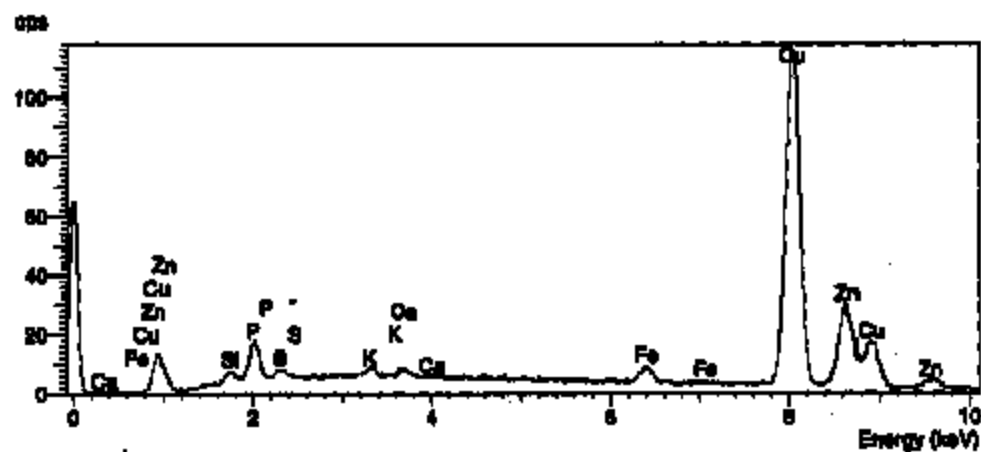
Bcup2



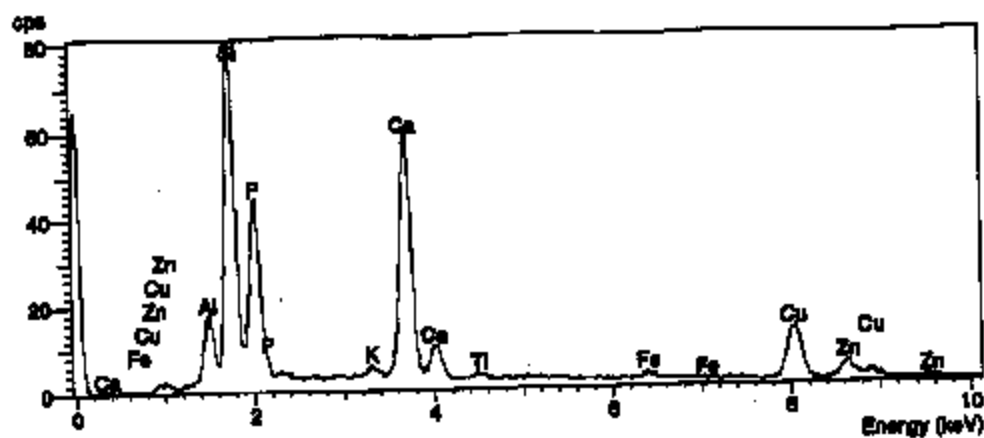
Bcup3



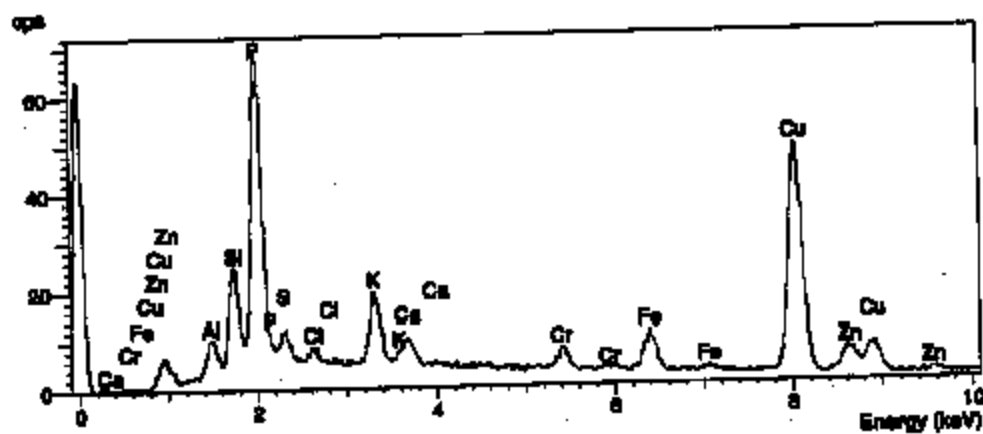
Bcup4



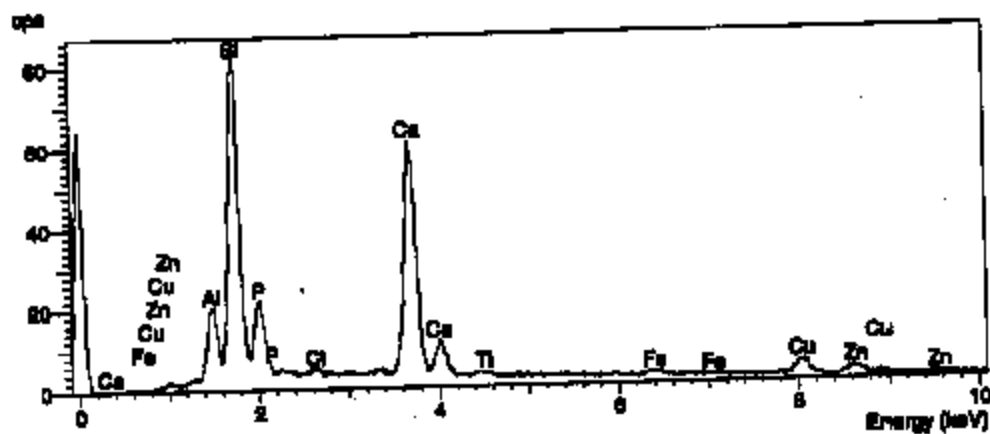
Bcup6



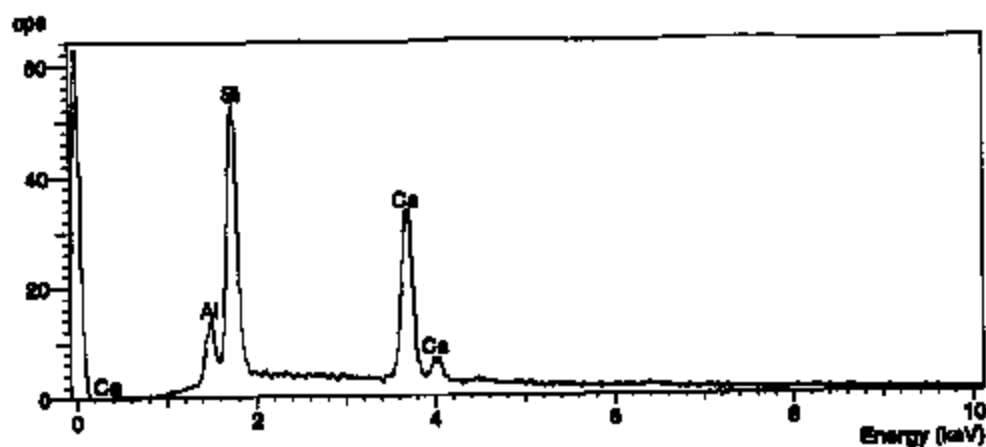
Bport1



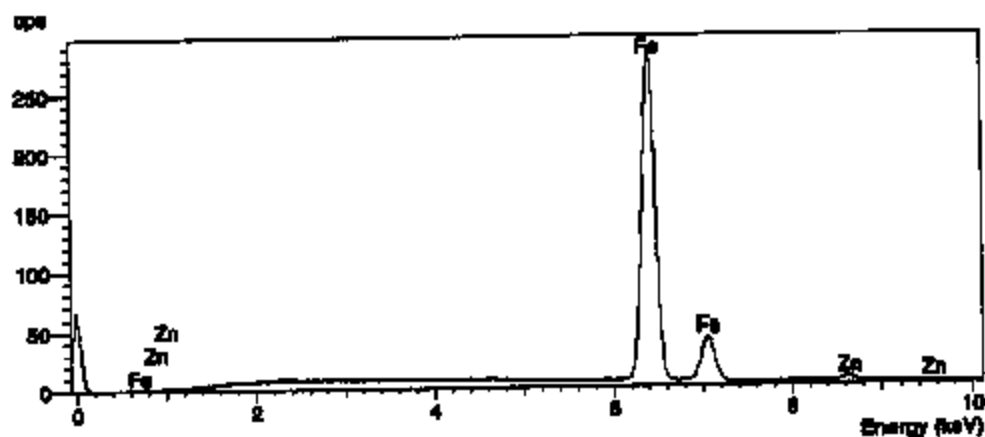
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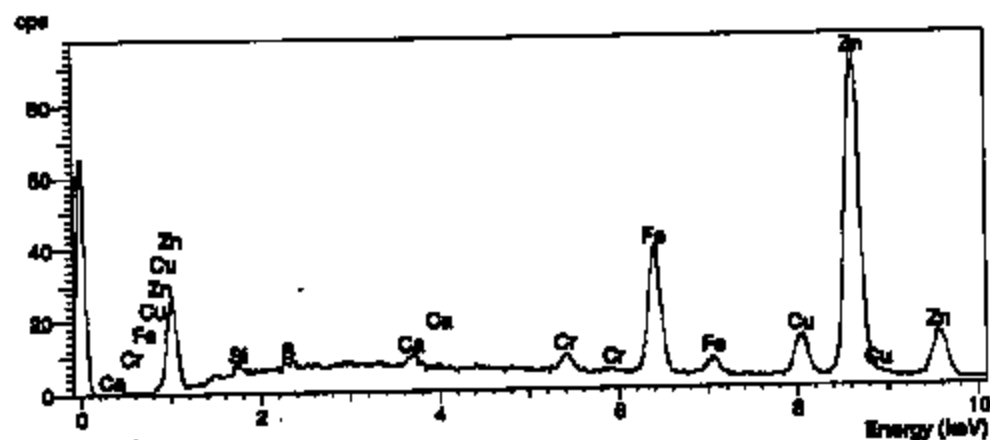
Bport3



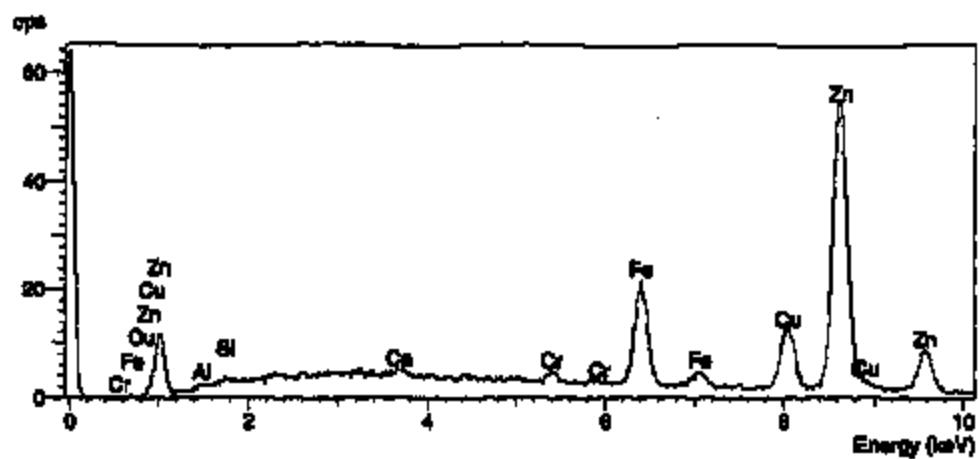
Bport4



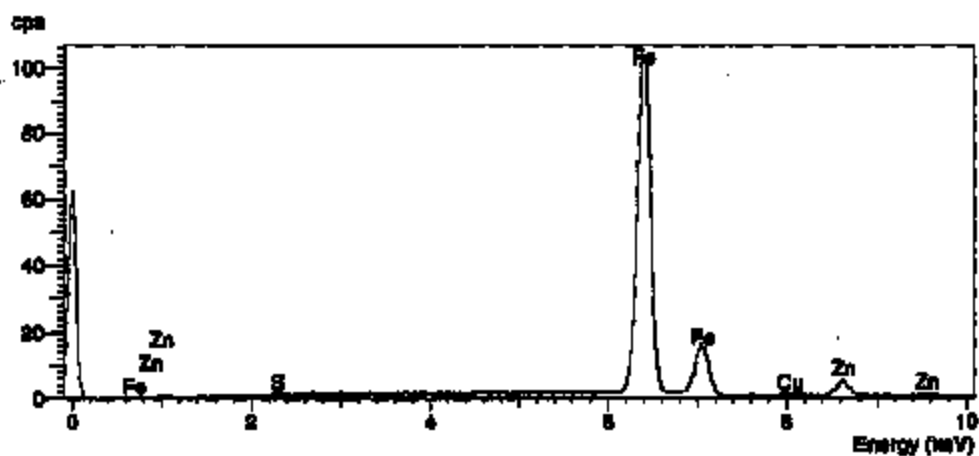
Ccup1



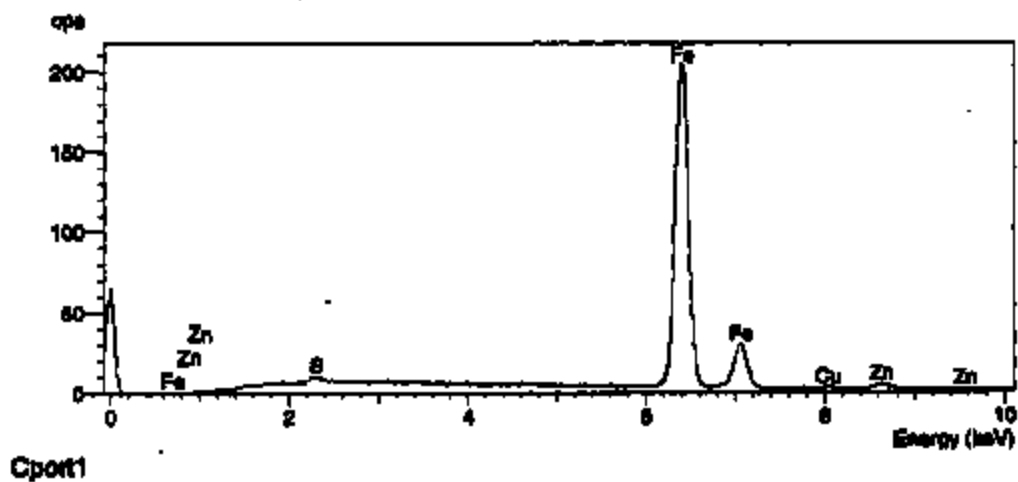
Coup2



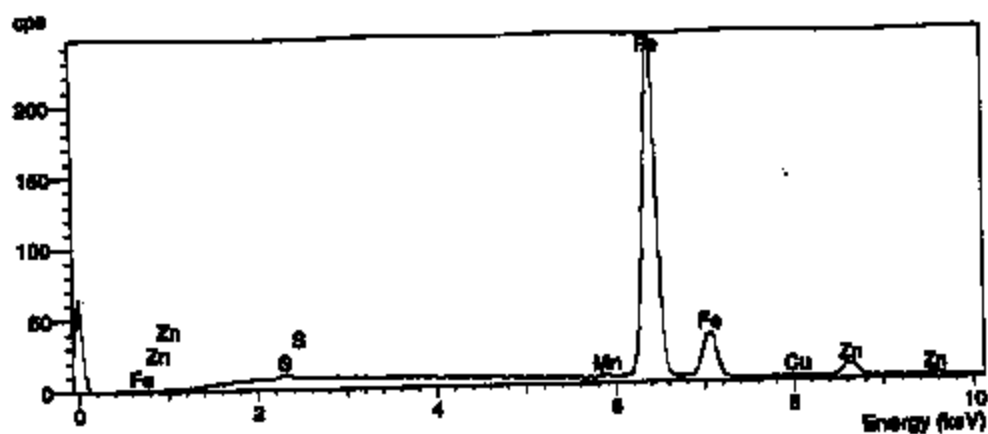
Ccup3



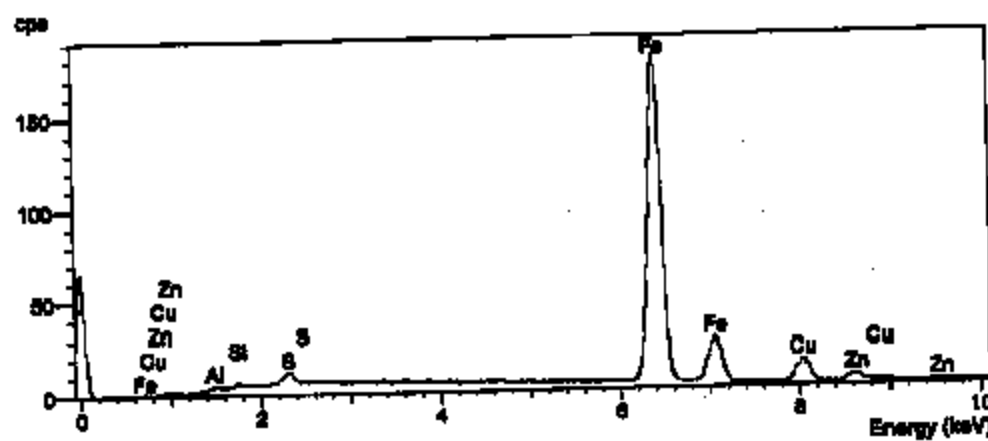
Ccup4



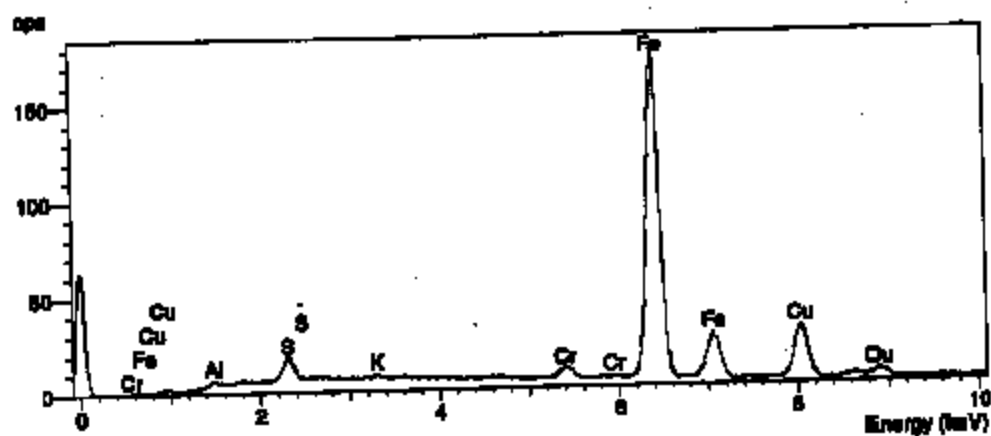
Cport1



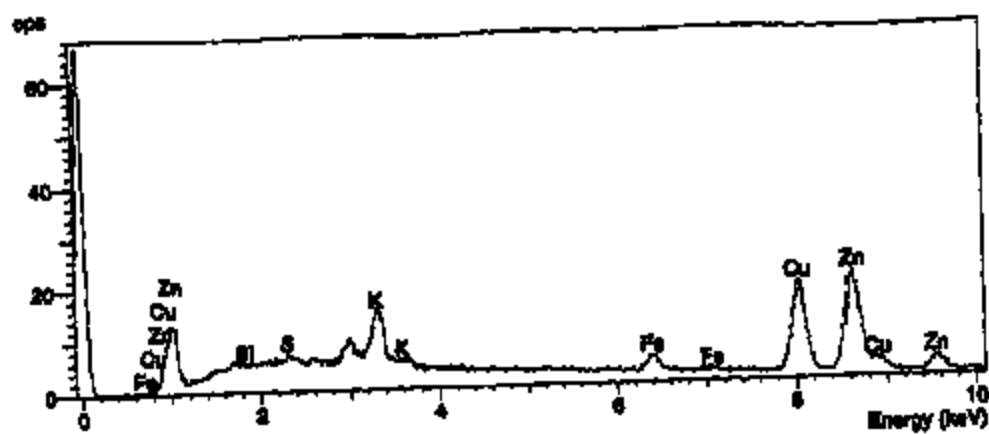
Cport2



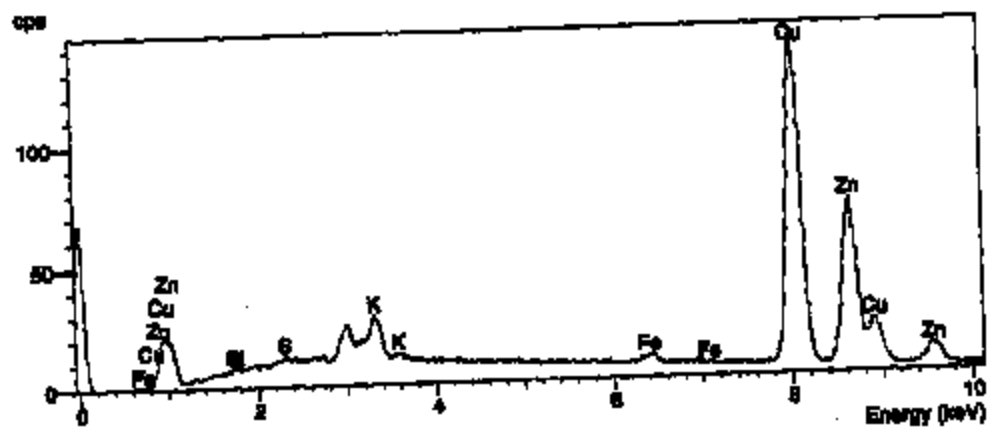
Cport3



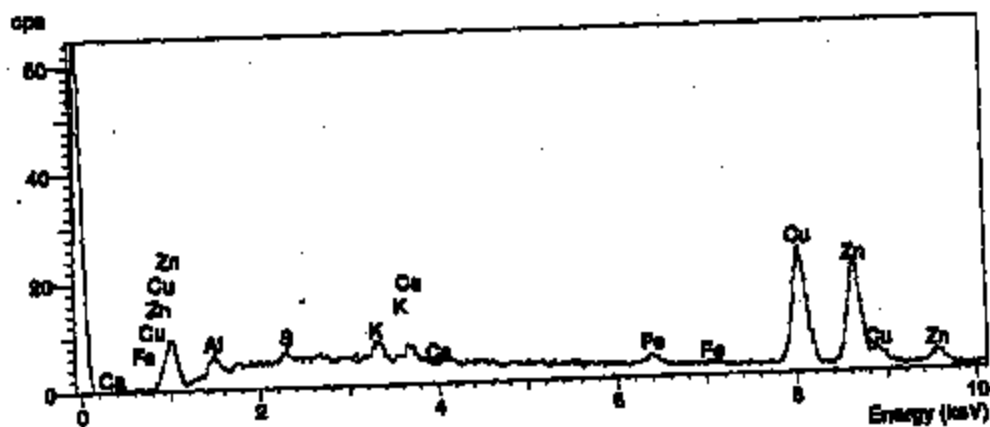
Cport4



Dcup1



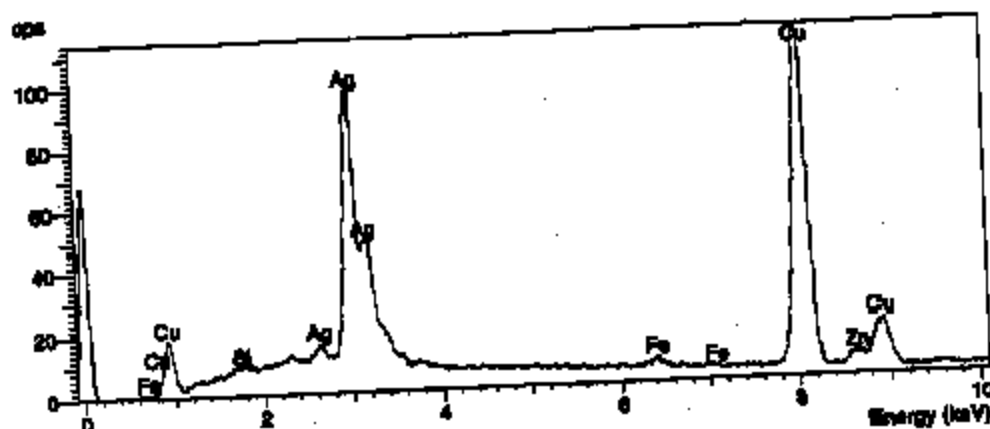
Dcup2



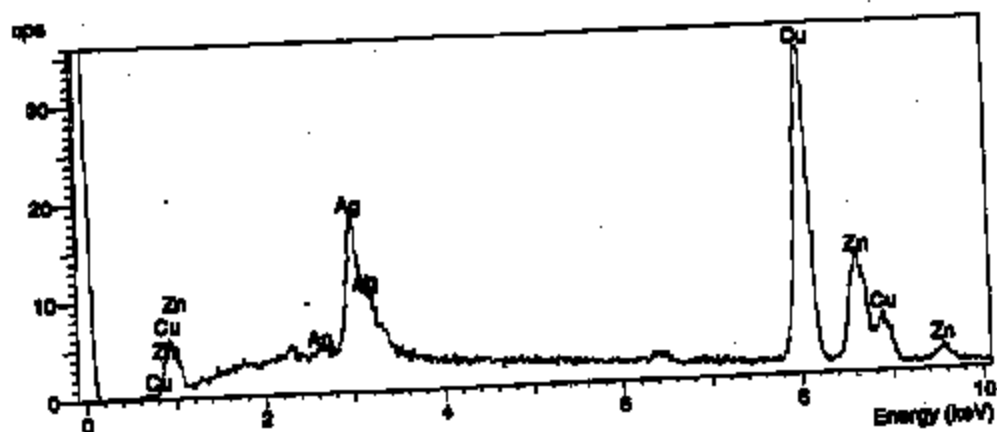
Dcup3



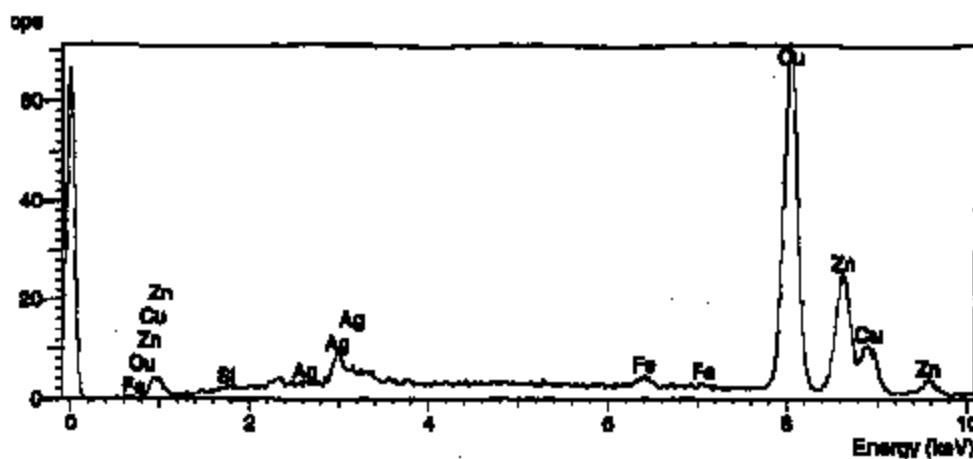
Dcup4



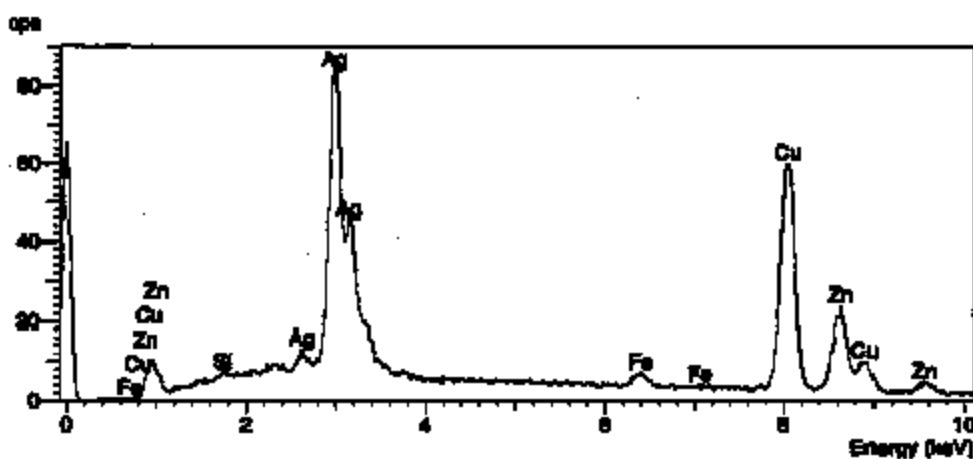
Dcontact1



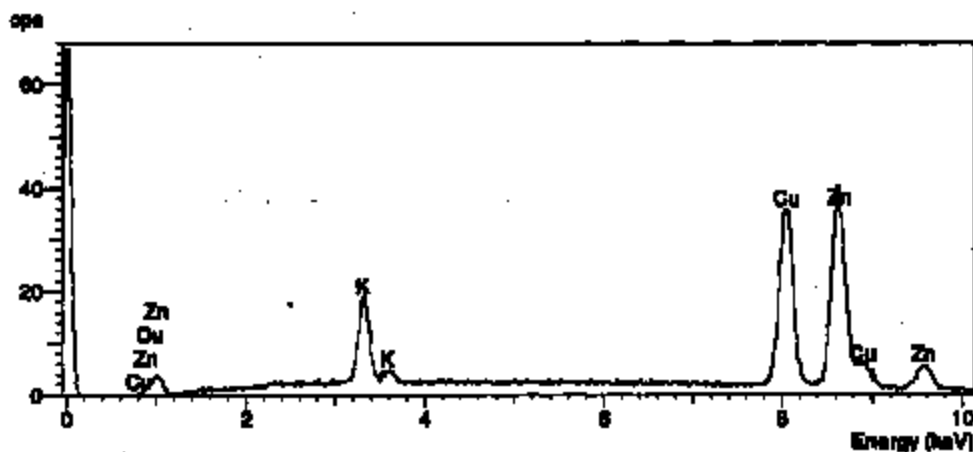
Dcontact2



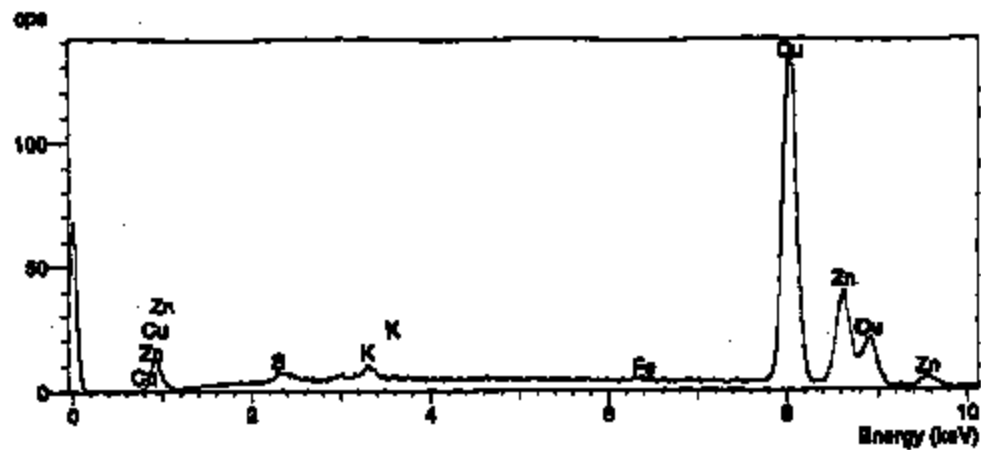
Dcontact3



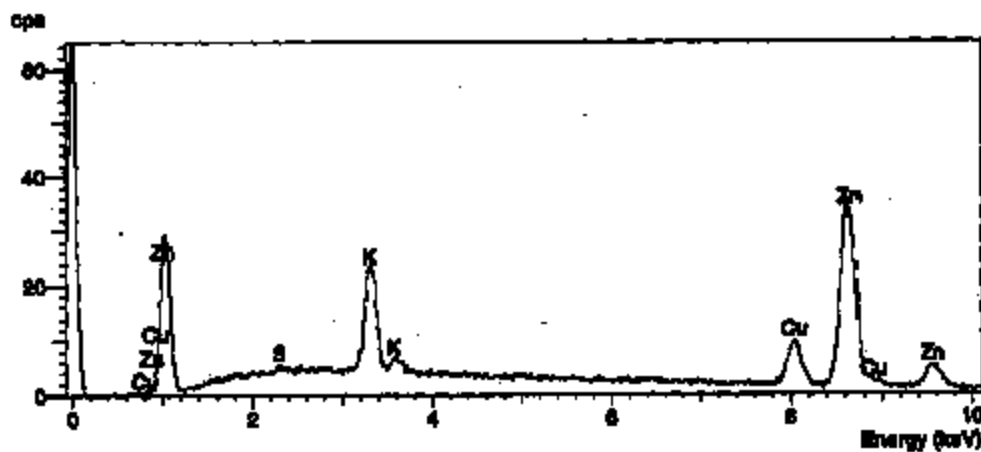
Dcontact4



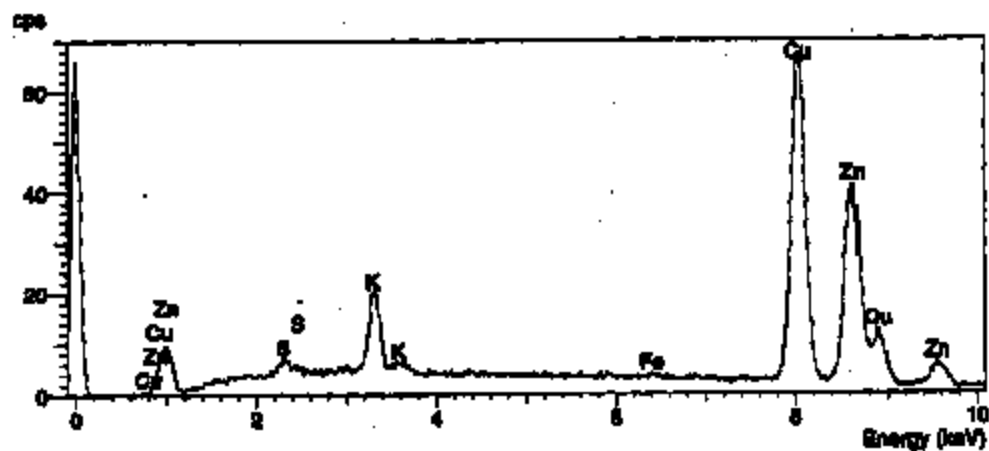
Foup1



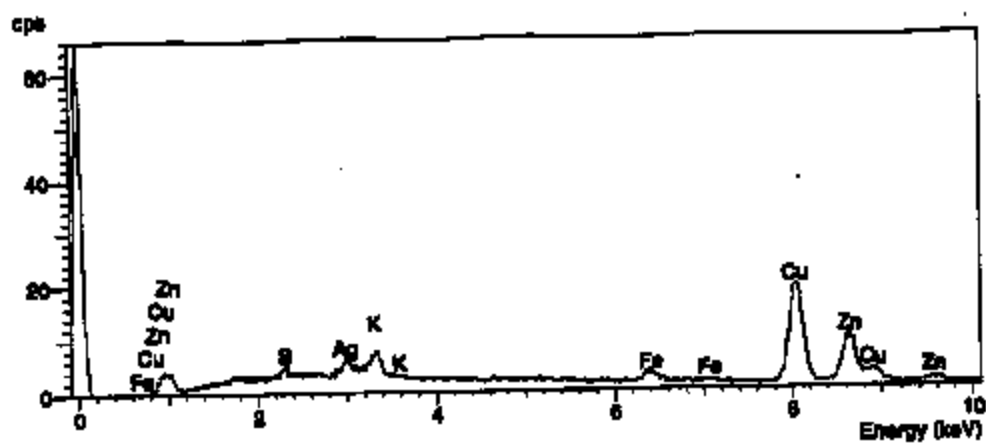
Foup2



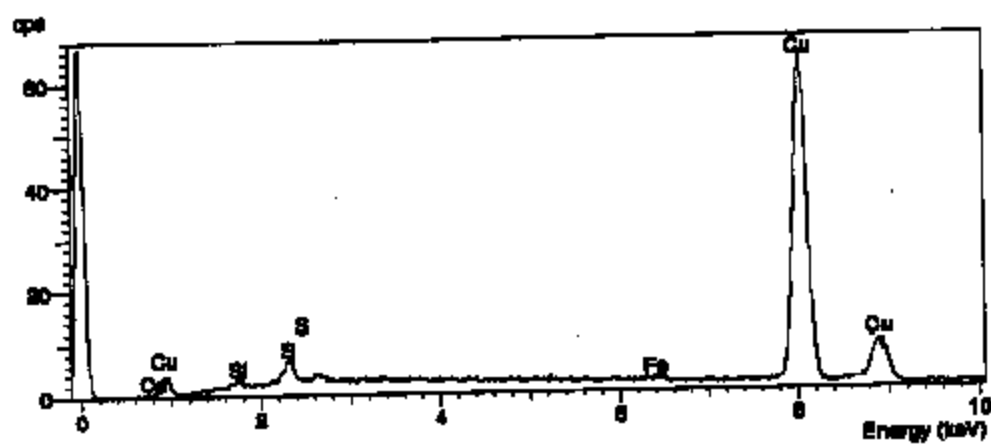
Foup3



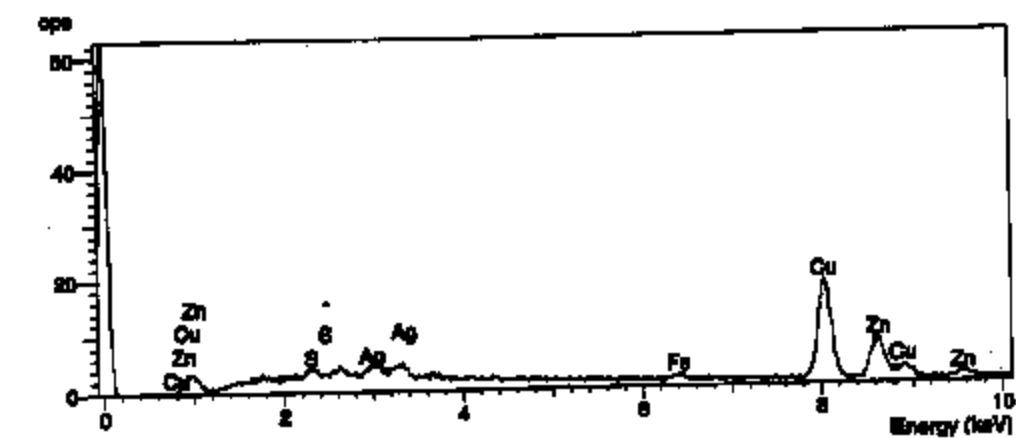
Foup4



Fcontact1



Fcontact2



Fcontact3



From Page No. To Gary Stearns / Steve LaRue

Subject: Speed Control Shut-off Switch

Part No. F2VY-9F924-A

Specimen: Not Provided

Supplier: Tedco's Instruments

Received: Ten pieces of (the paper was received on 1/20/88, the
was classified as A, B, C (Sup & Part), D & F (Sup & Part)

Object: Perform EDS analysis on the 10 pieces
mentioned in the

TEST DATA

SEM Examination & EDS Analysis

Particles were received from each piece of (the paper, & placed
on a carbon stub. Pieces D & F (the Sup & Part) were found "not"
representative due to broken shell. The particles were placed on a
stub & into new pieces of paper. These elements particles mentioned
transferred to a carbon stub for EDS analysis.

4 representative particles from each paper were given EDS
EDS see line here 19.635 kV point size 3. The following elements were
detected in decreasing order of elemental concentration.

A	Cuo	1	2	3	4
	Fe	En	En	En	
	an	Ca	Ca	Ca	
	P	Al	Fe	Al	
	K	Fe	Al	Fe	
	Ca	Si	Si	Si	
	Al	K	Ca	Ca	
	Ca	S	K	S	
	Mn	Ti	S	K	
			Mn		
			Ti		

To Page No. 33

Witnessed & Understood by me,

Date

Invented by

Date

Recorded by

From Page No. 32

ED: Analysis (cont)

A Part

1	2	3
Fe	Fe	Fe
Cu	Cu	Cu
Al	Zn	K
K	K	
	Al	
	S	

B Cup

1	2	3	4	5
Zn	Fe	Cu	Fe	Cu
Cu	Fe P	Zn	Zn	Zn
P	Cu	S	Cu	P
Fe	Al	S	Al	Fe
Si	Zn		Si	Si
S	Si		S	S
Cu	Cu		P	K
	K		Cl	Cu
	S		Mn	
	Cl		Cu	

B Part

1	2	3	4
Si	Cu	Si	Si
Cu	P	Cu	Cu
Cu	Zn	P	Al
Zn-P	Si	Al	
Al-Zn	Fe	Cu	
Al	K	Zn	
Fe	Al	Fe	
K	Cr	Ti	
Ti	S	Cl	
	Cu		
	Cl		

To Page No. 34

Witnessed & Understood by me,

Date

Invented by

Date

Recorded by

From Page No. 33 SDS Analysis (cont)

C Cup	1	2	3	4
	Fe	Zn	Zn	Fe
	Zn	Fe	Cu	Zn
		Cu	Fe	Cu
		Cr	Cr	S
		Si	Al	
		Ca	Ca	
		S	Si	

C Port	1	2	3	4
	Fe	Fe	Fe	Fe
	Zn	Zn	Cu	Cu
	Cu	Cu	Zn	Zn
	S	S	S	S
		Mn	Al	Cr
			Si	Al
				K

D Cup	1	2	3	4
	Zn	Cu	Zn	Zn
	Cu	Zn	Cu	Cu
	K	K	Al	K
	Fe	Fe	Fe	Fe
	S	S	K	S
	S	Si	Ca	
			S	

To Page No. 35

Witnessed & Understood by me,

Date

Invented by

Date

Recorded by

From Page No. 34

EDS Analysis (cont)

D Contact

1	2	3	4
Cu	Cu	Cu	Cu
Ag	Zn	Zn	Ag
Zn	Ag	Ag	Zn
Fe	Fe	Fe	Fe
Si		Si	Si

FCup

1	2	3	4
Zn	Cu	Zn	Cu
Cu	Zn	Cu	Zn
FeK	K	K	K
	Fe	S	S
	Si		Fe

FContact

1	2	3	4
Cu	Cu	Cu	Cu
Zn	S	Zn	Zn
Ag	Si	Ag	Ag
K	Fe	Fe	K
Fe		S	Cl
S			Fe
			S
			Si

There is transfer of metal from the contacts to the cup on each switch (Cu/Zn present in cups)

To put sample in primarily fibers. A, C, and Fe-rich

Contacts are Cu-Zn-Ag

To Page No. 36

Witnessed & Understood by me,

Date

Invented by

Date

Recorded by

From Page No. 37

4 additional reports were received 2/2/97. They were
 2 Copper tubes & 2 brass tubes
 They were in either a new or old hole found

At the same time the new water, caused in from the station
 a certain point for 1000 ft. or more

The following elements were detected in the water and
 at chemical composition

Copper Tube New	Copper Tube Old	Fitting New	Fitting Old
Cu	Cu	Cu	Cu
Zn	Cl	Zn	K
S		Cl	S
Fe			
Ca			
Al			
S			

To Page No. _____

Witnessed & Understood by me,

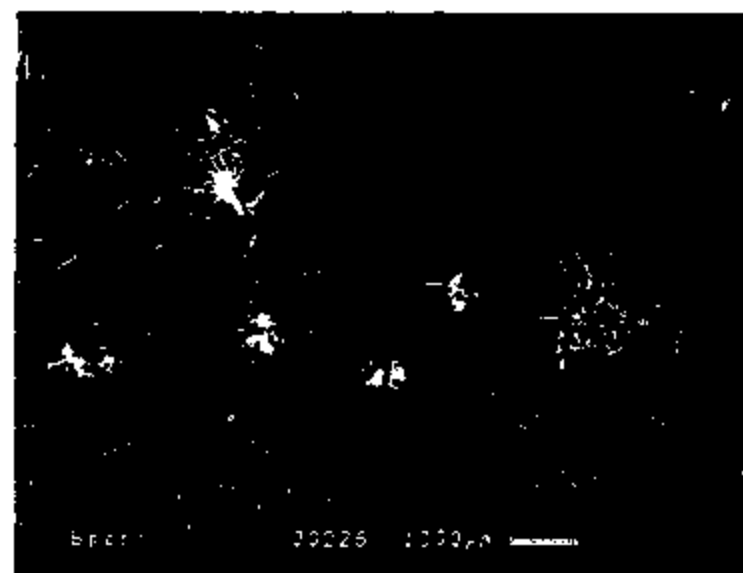
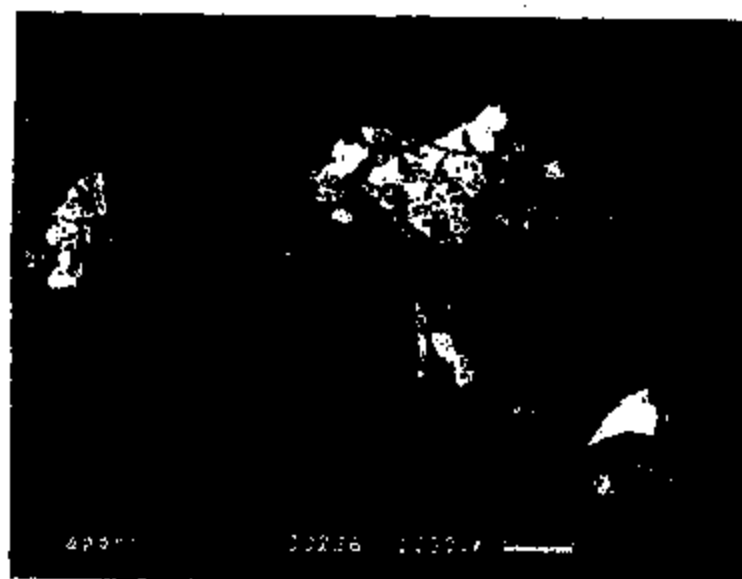
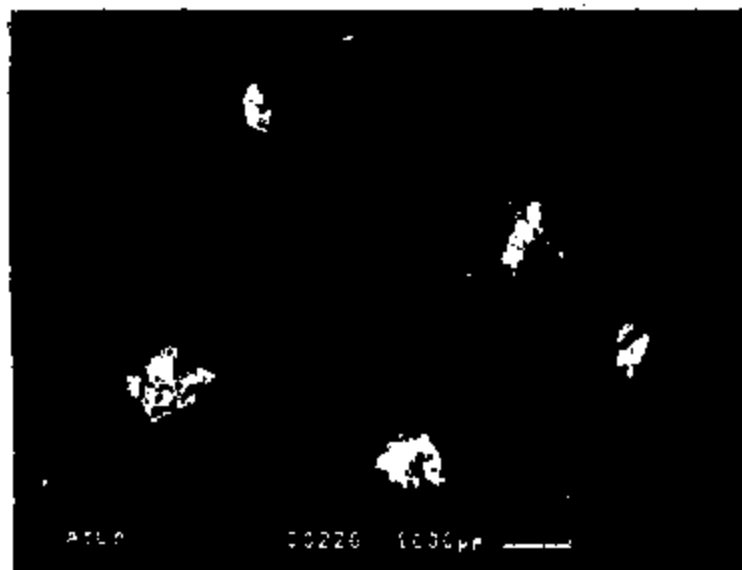
Date

Invented by

Date

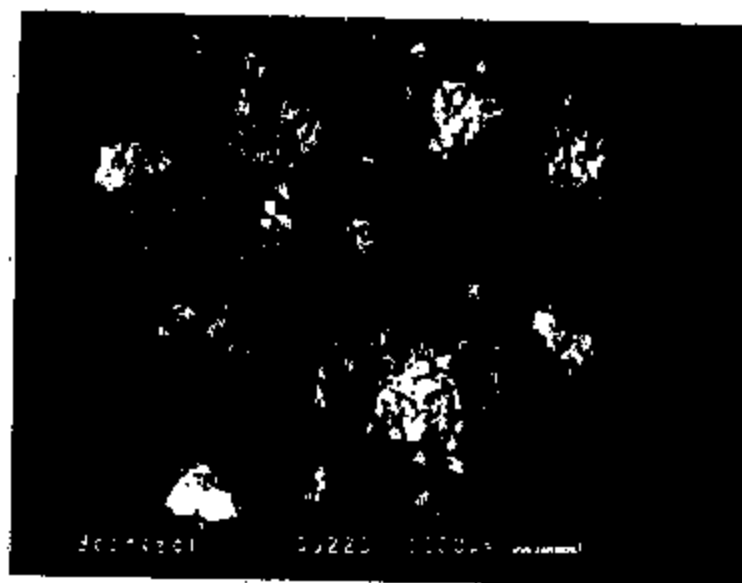
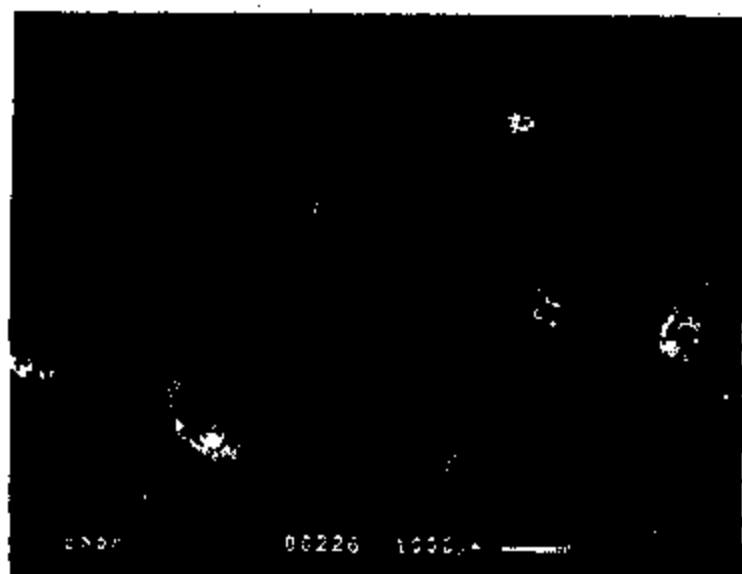
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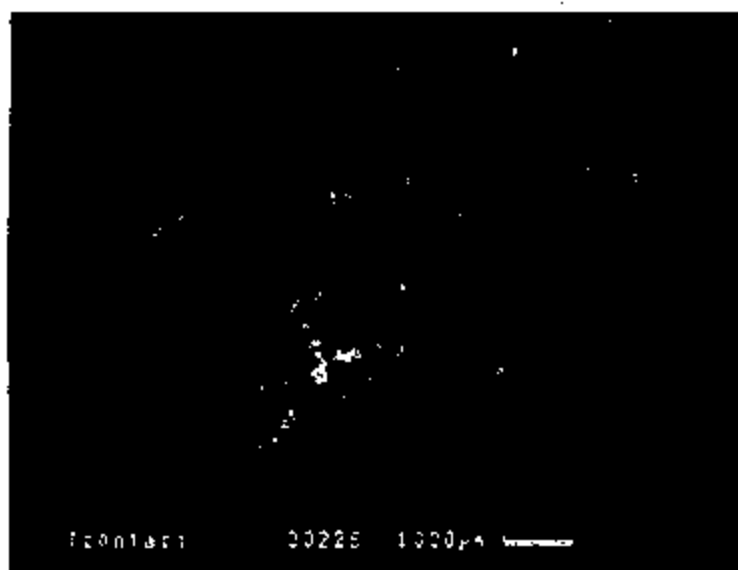
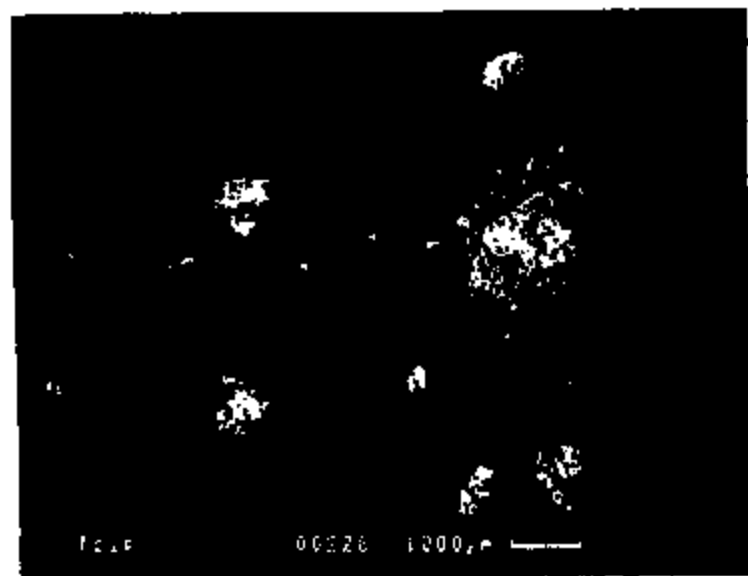
2/4/97





3713 2871





SEMQuant results. Listed at 1:47:02 PM on 2/1/94
 Operator: Patrick Harlow
 Client: Greg Stevens
 Job: 5900022
 Spectrum label: Copper Tubing Row2

System resolution = 0.4 eV

Quantitative method: ZAF (2 iterations).
 Analysed all elements and normalised results.

4 peaks possibly omitted: 0.00, 1.12, 10.54,
 12.66 keV

Standards:

Al K Al2O3 21/11/93
 Si K Quartz 01/12/93
 S K FeS2 01/12/93
 Ca K Molten 21/11/91
 Fe K Fe 01/12/93
 Cu K Cu 01/12/93
 Zn K Zn 01/12/93

Line	Spect. Type	Element	Atomic %
Al K	ED	0.12	0.28
Si K	ED	0.09	0.21
S K	ED	0.55	1.09
Ca K	ED	0.15	0.24
Fe K	ED	0.27	0.31
Cu K	ED	80.55	80.20
Zn K	ED	18.27	17.68
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Al K	0.1
Si K	0.8
S K	82.2
Ca K	0.5
Fe K	0.9
Cu K	5.3
Zn K	2.1

SEMQuant results. Listed at 1:44:14 PM on 12/1/95
Operator: PATRICK HALLON
Client: GLEN STEVENS
Job: 9906224
Spectrum label: Copper Tubing Old1

System resolution = 64 eV

Quantitative method: ZAF (2 iterations).
Analysed all elements and normalised results.

2 peaks possibly omitted: 0.00, 7.44 keV

Standards :
Cl K RCl 15/02/94
Cu K Cu 01/12/94

Elmt	Spect. Type	Element %	Atomic %
Cl K	ED	1.79	3.16
Cu K	ED	98.21	96.84
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Cl K	0.7
Cu K	2.1

SEMQuant results. Listed at 3:29:45 PM on 2/3/94
Operator: Patrick Nailon
Client: Greg Stevens
Job: 950023a
Spectrum label: Fitting New?

System resolution = 13 eV

Quantitative method: ZAF (2 iterations).
Analyzed all elements and normalized results.

1 peak possibly omitted: 0.00 keV

Standards:

Cl K KCl 15/02/94
Cu K Cu 01/12/93
Zn K Zn 01/12/93

Elem	Spect. Type	Element %	Atomic %
Cl K	KD	7.01	12.04
Cu K	KD	51.70	49.60
Zn K	KD	41.21	38.36
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Cl K	0.3
Cu K	2.1
Zn K	1.2

SEIQuant results, listed at 1:26:22 PM on 07/1/96
 Operator: Patrick Barlow
 Client: Greg Stevens
 Job: 996422
 Spectrum Label: Fitting old

System resolution = 0.1 eV

Quantitative method: ZAF (2 iterations).
 Analysed all elements and normalized results.

1 peak possibly omitted: 6.00 keV

Standards :

S K Fe22 01/12/94
 K K HA01-16 02/12/94
 Cu K Cu 01/12/94

Elem	Speci.	Element	Atomic
	Type		
S K	KD	0.81	1.58
K K	KD	1.56	2.90
Cu K	KD	97.63	95.52
Total		100.00	100.00

* < 2 Sigma

Fit Indices

S K	1.6
K K	1.7
Cu K	5.4

SEMQuant results. Emission at 1:30:18 PM on 1/24/94
 Operator: Patrick Harlos
 Client: Greg Stevens
 Job: 9900224
 Spectrum label: 74001

System resolution - 102 eV

Quantitative method: ZAF (3 iterations).
 Analyzed all elements and normalized results.

1 peak possibly omitted: 0.00 keV

Standards :

Al K Al2O3 23/11/93
 P K GaP 29/11/93
 K K MAD-10 02/12/93
 Ca K Wolias 23/11/93
 Mn K Mn 01/12/93
 Fe K Fe 01/12/93
 Cu K Cu 01/12/93
 Zn K Zn 01/12/93

Elem	Spect. Type	Element %	Atomic %
Al K	ED	2.45	4.59
P K	ED	9.38	15.27
K K	ED	4.95	6.38
Ca K	ED	2.42	3.04
Mn K	ED	0.35	0.32
Fe K	ED	62.86	56.75
Cu K	ED	4.01	3.18
Zn K	ED	14.57	10.47
Total		100.00	100.00

* < 2 Sigma

Pit Indices

Al K	1.8
P K	0.7
K K	0.3
Ca K	0.4
Mn K	2.2
Fe K	2.0
Cu K	0.8
Zn K	1.4

SEM Quant results. Listed at 11:17:54 PM on 1/26/94
 Operator: Patrick Mullins
 Client: Greg Stetson
 Job: G000226
 Specimen label: Acup2

System resolution = 162 eV

Quantitative method: ZAF (1 iteration)
 Analysed all elements and normalized results.

1 peak possibly omitted: 0.00 keV

Standards:

Al K Al2O3 23/11/93
 Si K Quartz 01/12/93
 S K FeS2 01/12/93
 K K NaBr-70 02/12/93
 Ca K Wollast 23/11/93
 Ti K Ti 01/12/93
 Fe K Fe 01/12/93
 Cu K Cu 01/12/93
 Zn K Zn 01/12/93

Elmt	Spect. Type	Element	Atomic %
Al K	ED	8.44	17.10
Si K	ED	2.93	5.71
S K	ED	0.38	0.65
K K	ED	0.65	0.91
Ca K	ED	1.19	1.62
Ti K	ED	0.31	0.37
Fe K	ED	7.36	7.20
Cu K	ED	21.99	20.64
Zn K	ED	54.73	45.78
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Al K	4.6
Si K	60.1
S K	11.2
K K	0.4
Ca K	0.3
Ti K	0.3
Fe K	0.5
Cu K	2.8
Zn K	1.9

Quant results. Listed at 1:19:05 PM on 1/24/93
 Operator: Patrick Mallon
 Client: Greg Stevens
 Job: 9900224
 Spectrum label: ADAPT

System resolution = 16.3 eV

Quantitative method: ZAF (3 iterations),
 Analysed all elements and normalized results.

2 peaks possibly omitted: 0.06, 5.46 keV

Standards :

Al K Al2O3 23/11/91
 Si K Quartz 01/12/93
 S K FeS2 01/12/93
 K K HAP-10 02/12/93
 Ca K Molten 23/11/93
 Ti K Ti 01/12/93
 Mn K Mn 01/12/93
 Fe K Fe 01/12/93
 Cu K Cu 01/12/93
 Zn K Zn 01/12/93

Elmt	Spect. Type	Element %	Atomic %
Al K	ED	12.23	23.74
Si K	ED	1.47	1.48
S K	ED	0.36	0.59
K K	ED	0.76	1.02
Ca K	ED	1.66	2.17
Ti K	ED	0.17	0.18
Mn K	ED	0.25	0.24
Fe K	ED	14.63	13.71
Cu K	ED	15.48	12.76
Zn K	ED	52.58	42.10
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Al K	0.1
Si K	46.1
S K	25.7
K K	0.5
Ca K	0.6
Ti K	0.6
Mn K	0.6
Fe K	0.8
Cu K	0.7
Zn K	0.7

SEMQuant results. Listed at 11:41:48 PM on 1/29/94
 Operator: Patrick Rafter
 Client: Greg Stegman
 Job: 990672c
 Spectrum label: Acmp5

System resolution: 101 eV

Quantitative method: ZAF (3 iterations).
 Analysed all elements and normalized results.

1 peak possibly omitted: 0.00 keV

Standards :

Al K Al2O3 23/11/91
 Si K Quartz 01/12/91
 S K FeS2 01/12/91
 K K NAD-10 02/12/91
 Ca K Wollas 23/11/91
 Fe K Fe 01/12/91
 Cu K Cu 01/12/91
 Zn K Zn 01/12/91

Elem	Spect. Type	Element	Atomic
Al K	ED	10.21	20.88
Si K	ED	1.19	2.71
S K	ED	0.26	0.44
K K	ED	0.21	0.29
Ca K	ED	0.59	0.81
Fe K	ED	2.47	2.44
Cu K	ED	19.61	14.12
Zn K	ED	45.21	18.00
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Al K	0.5
Si K	7.1
S K	1.7
K K	0.6
Ca K	0.7
Fe K	0.6
Cu K	1.4
Zn K	1.2

EDSQuant results, listed at 1:41:59 PM on 1/29/99
Operator: Patrick Nollan
Client: Greg Stevens
Job: 950032r
Spectrum label: APost1

System resolution = 101 eV

Quantitative method: XAF (2 iterations).
Analyzed all elements and normalized results.

1 peak possibly omitted: 0.96 keV

Standards :

Al K	Al2O3 21/11/93
K K	NAB-10 02/12/93
Fe K	Fe 01/12/93
Cu K	Cu 01/12/93

Elmt	Spect. Type	Element %	Atomic %
Al K	ED	9.81	1.70
K K	ED	9.74	1.04
Fe K	ED	97.14	50.11
Cu K	ED	1.09	0.95
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Al K	0.2
K K	0.4
Fe K	1.7
Cu K	0.5

Quant results, listed at 1:41:21 PM on 1/29/91
 Operator: Patrick Mathias
 Client: Greg Stevens
 Job: 9900226
 Spectrum label: APort2

System resolution = 103 eV

Quantitative method: KAP (2 iterations).
 Analysed all elements and normalised results.

1 peak possibly omitted: 0.00 keV

Standards :

Al K Al2O3 23/11/91
 S K FeS2 01/12/91
 K K MnO 10 02/12/91
 Fe K Fe 01/12/91
 Cu K Cu 01/12/91
 Zn K Zn 01/12/91

Elem	Spect. Type	Element	Atomic
Al K	ED	0.75	1.61
S K	ED	0.28	0.51
K K	ED	0.98	1.46
Fe K	ED	51.79	56.18
Cu K	ED	30.70	28.18
Zn K	ED	11.50	12.04
Total		100.00	100.00

* -- <2 Sigma

Fit Indices

Al K	0.2
S K	0.1
K K	0.4
Fe K	1.6
Cu K	1.6
Zn K	0.7

SEMQuant results, listed at 1:48:04 PM on 1/26/96
Operator: Patrick Mallon
Client: Greg Stevens
Job: 9900226
Spectrum label: AP011

System resolution = 163 eV

Quantitative method: ZAF (2 iterations).
Analysed all elements and normalized results.

1 peak possibly missed: 0.00 keV

Standards :

K K MAH-10 02/12/91
Fe K Fe 01/12/93
Cu K Cu 01/12/93

Elem	Spect.	Element	Atomic
	Type		
K K	ED	0.22	0.88
Fe K	ED	98.00	99.91
Cu K	ED	1.38	1.21
Total		100.00	100.00

* = <2 Sigma

Fit Indices

K K 0.2
Fe K 3.1
Cu K 2.0

SEMQuant results, Listed at 1:52:05 PM on 1/29/91
 Operator: Patrick Baillos
 Client: Greg Stevens
 Job: 9004204
 Spectrum label: 85ap1

System resolution = 103 eV

Quantitative method: XAF (1 iterations).
 Analysed all elements and normalised results.

2 peaks possibly omitted: 0.00, 3.90 keV

Standards :

Si K Quartz 01/12/91
 P K GaP 25/11/91
 S K FeS2 01/12/91
 Ca K Wolfram 21/11/91
 Fe K Fe 01/12/91
 Cu K Cu 01/12/91
 Zn K Zn 01/12/91

Elem	Spect. Type	Element	Atomic %
Si K	ED	0.92	2.00
P K	ED	4.01	7.89
S K	ED	0.85	1.62
Ca K	ED	0.41	0.82
Fe K	ED	1.10	1.20
Cu K	ED	10.98	10.52
Zn K	ED	81.73	76.15
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Si K 0.5
 P K 0.6
 S K 0.7
 Ca K 0.4
 Fe K 0.4
 Cu K 0.6
 Zn K 0.5

SEM/EDS results listed at 1:54:29 PM on 1/29/94
 Operator: Patrick Naylor
 Client: Greg Stevens
 Job: 990022
 Spectrum label: Blaup2

System resolution = 103 eV

Quantitative method: KAP (3 iterations)
 Analysed all elements and normalised results.

1 peak possibly omitted: 0.00 keV

Standards :

Al K Al2O3 23/11/93
 Si K Quartz 01/12/93
 P K CaP 29/11/93
 S K FeS2 01/12/93
 Cl K KCl 15/02/94
 K K MAP-10 02/12/93
 Ca K Wollas 23/11/93
 Fe K Fe 01/12/93
 Cu K Cu 01/12/93
 Zn K Zn 01/12/93

Elemt	Spec. Type	Element %	Atomic %
Al K	ED	7.95	13.25
Si K	ED	5.86	9.39
P K	ED	11.74	17.05
S K	ED	1.00	1.41
Cl K	ED	0.58	0.73
K K	ED	1.03	1.16
Ca K	ED	2.87	3.22
Fe K	ED	52.24	42.08
Cu K	ED	0.81	0.73
Zn K	ED	7.95	5.47
Total		100.00	100.00

* = <3 Sigma

PIL Indices

Al K 0.1
 Si K 0.3
 P K 0.1
 S K 0.3
 Cl K 5.7
 K K 1.3
 Ca K 1.2
 Fe K 0.8
 Cu K 0.1
 Zn K 0.1

SEIQuant results, listed at 1:55:52 PM on 01/20/94
 Operator: Patrick Malloy
 Client: Greg Stevens
 Job: 690022c
 Spectrum label: Kcapi

System resolution = 161 eV

Quantitative method: ZAF (2 iterations)
 Analyzed all elements and normalized results.

1 peak possibly omitted: 6.00 keV

Standards :

Si K	Quartz 01/12/93
S K	FeS2 01/12/93
Cu K	Cu 01/12/93
Zn K	Zn 01/12/93

Elem	Spect. Type	Element	Atomic
Si K	K α	0.56	1.24
S K	K α	0.42	1.21
Cu K	K α	84.55	11.78
Zn K	K α	14.27	11.74
Total		100.00	100.00

* = <2 Sigma

Fit Indices

Si K	0.4
S K	0.6
Cu K	2.4
Zn K	1.7

#2242400 results, listed as 2:01:11 PM on 1/26/91

Operator: Patrick Nation

Client: Gary Stegans

Job: 590022

Spectrum label: Kcup4

System resolution = 101 eV

Quantitative method: XRF (2 iterations).

Analysed all elements and normalised results.

2 peaks possibly omitted: 0.00, 17.18 keV

Standards :

Al K	Al2O3 23/11/91
Si K	Quartz 01/12/91
P K	GaP 29/11/91
S K	KuS2 01/12/91
Cl K	KCl 15/02/91
Ca K	Nolan 23/11/91
Mn K	Mn 01/12/91
Fe K	Fe 01/12/91
Cu K	Cu 01/12/91
Zn K	Zn 01/12/91

Elmt	Spect. Type	Element %	Atomic %
Al K	ED	0.45	0.93
Si K	ED	0.19	0.77
P K	ED	0.21	0.38
S K	ED	0.22	0.38
Cl K	ED	0.21	0.11
Ca K	ED	0.15	0.20
Mn K	ED	0.20*	0.20*
Fe K	ED	85.28	85.70
Cu K	ED	0.68	0.60
Zn K	ED	12.24	10.51
Total		100.00	100.00

* = 42 Sigma

Fit Indices

Al K	0.2
Si K	0.5
P K	0.7
S K	0.3
Cl K	0.5
Ca K	4.4
Mn K	5.7
Fe K	5.1
Cu K	0.7
Zn K	0.7